TAIWAN
PHOTON
SOURCE

X-ray Nanoprobe Beamline for Nanoscale Solid State Physics Research

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2020/10/15

X-ray Image Group
Experiment Facility Division
NSRRC

National Synchrotron
Radiation Research Center

Outline

- Synchrotron Light Source
- Application of Synchrotron Light
- X-ray nano probe at TPS

"Light" is indispensable to man's exploration of nature.







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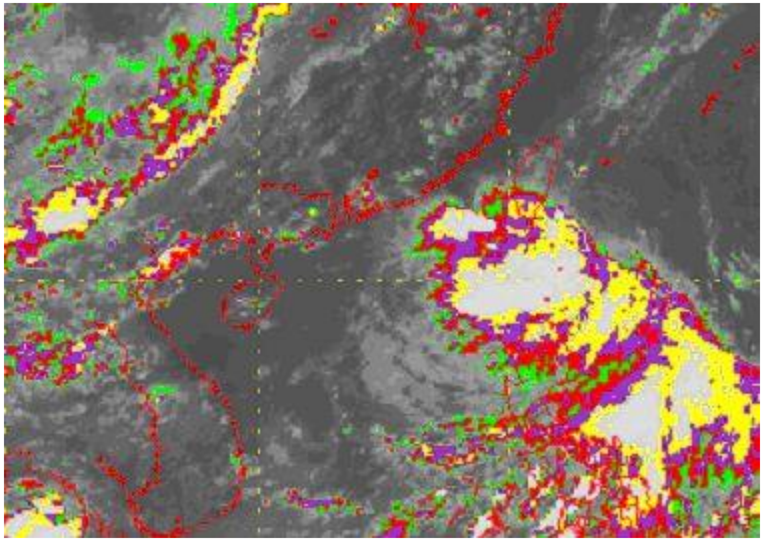
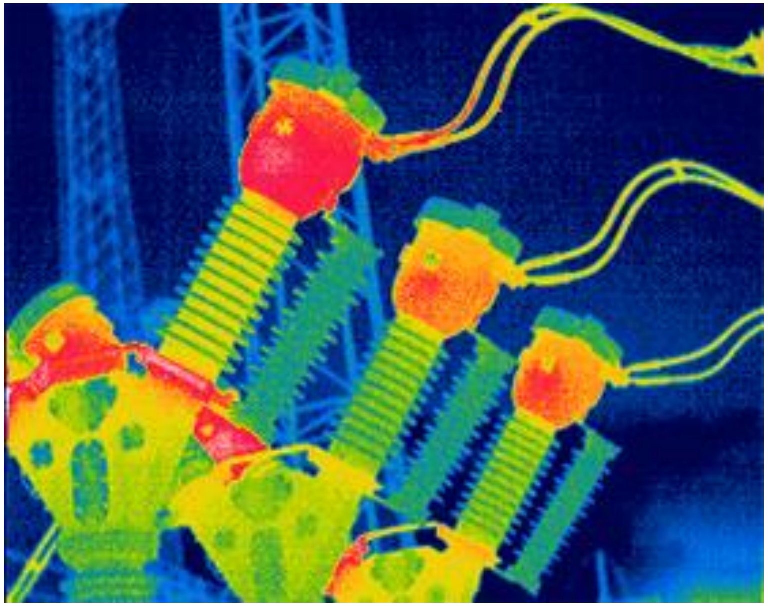
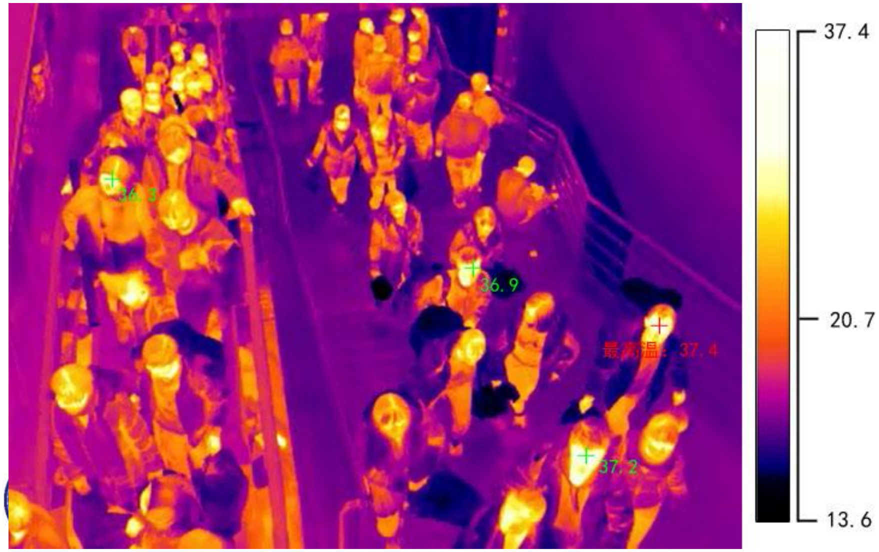
Invisible light: IR and X-ray…



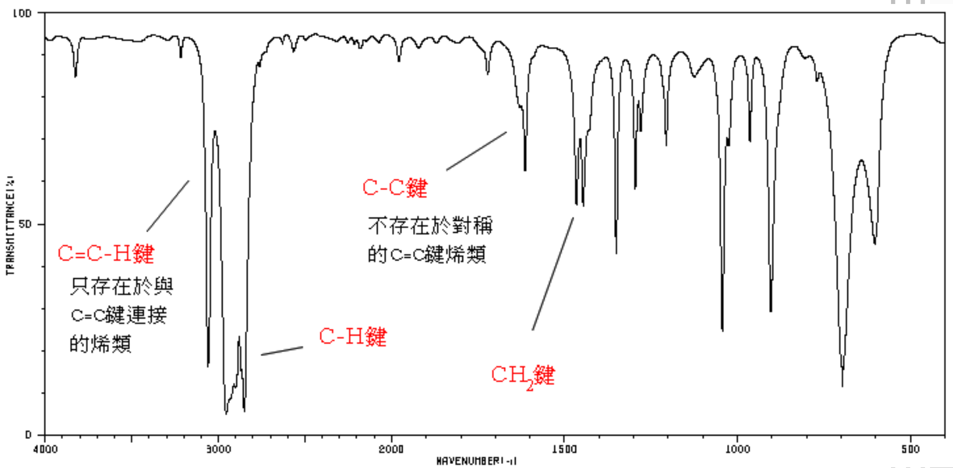
http://www.hko.gov.hk/prtver/html/docs/education/edu02rga/radiation/radiation_02-c.shtml



http://www.yingfukeji.com/appl/grid.html

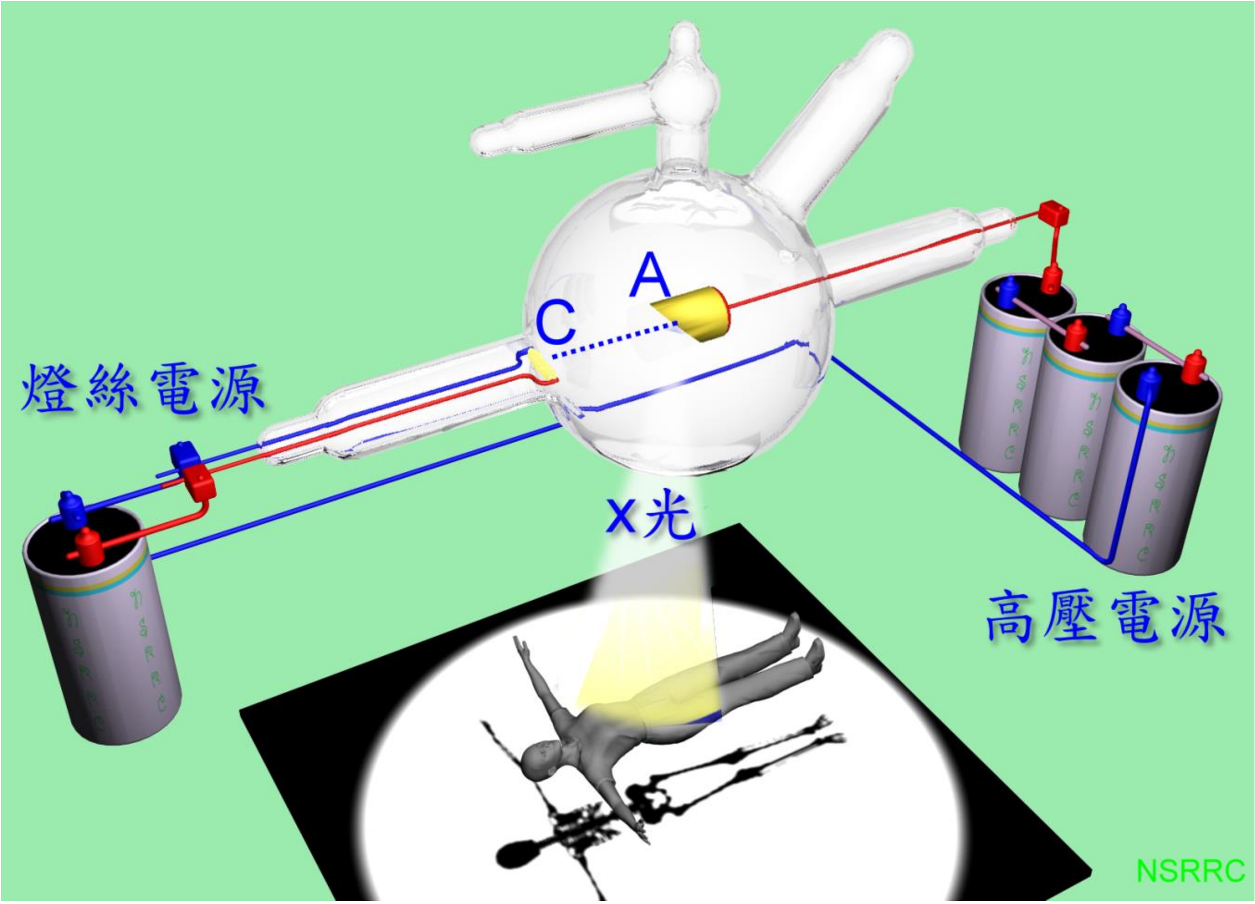


http://www.uv-teck.com/Ttwjy



http://smallcollation.blogspot.tw/2014/02/infrared-spectroscopy-of-alkanes.html#gsc.tab=0

Rontgen used a simple accelerator to discover X-rays



1895

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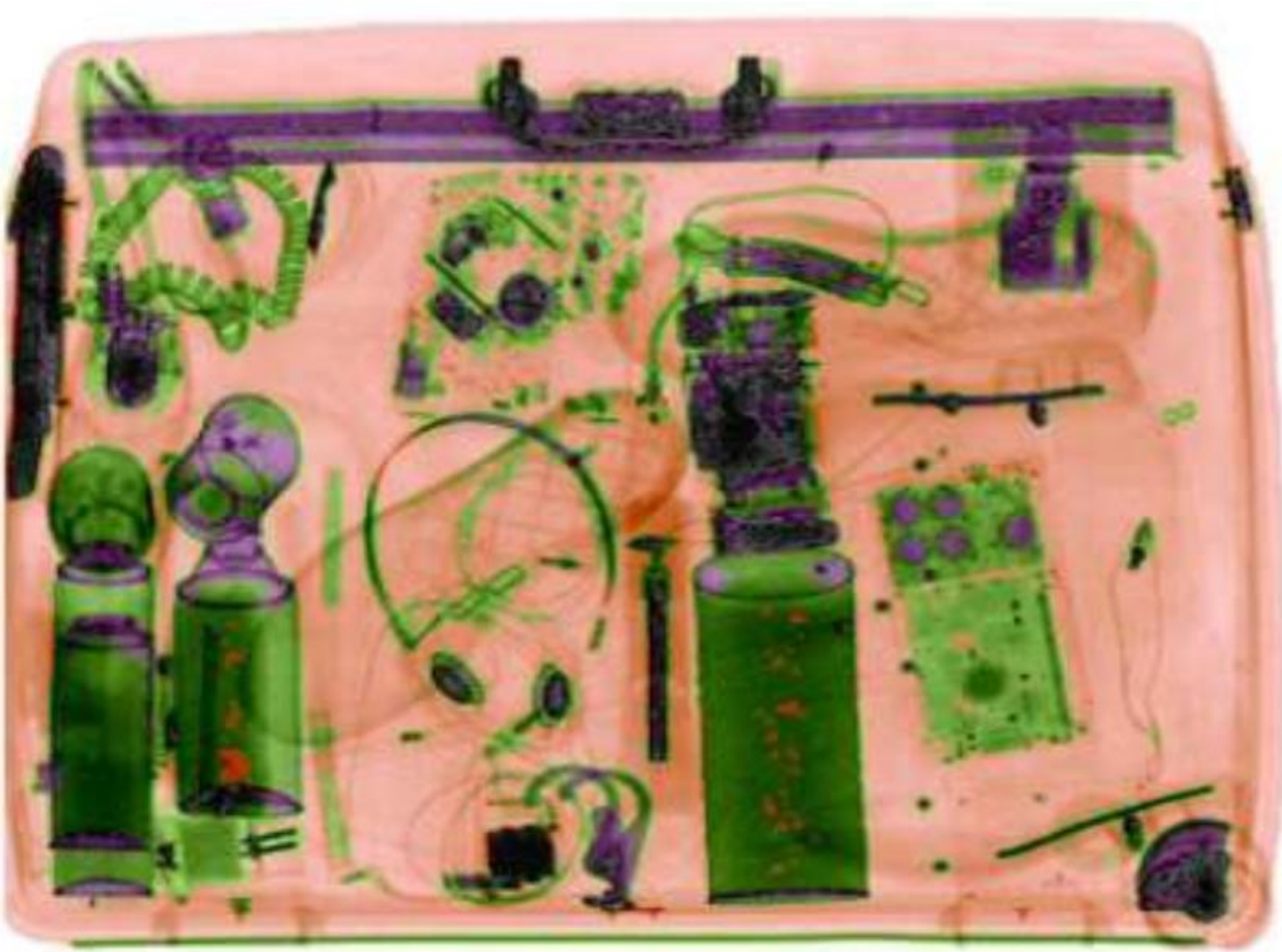
Hand mit Ringen (Hand with Rings): Wilhelm Rontgen's first "medical" X-ray, of his wife's hand, taken on 22 December 1895 and presented to Ludwig Zehnder of the Physik Institut, University of Freiburg, on 1 January 1896.

http://en.wikipedia.org/wiki/X-ray



http://snallabolaget.com/?page_id=666

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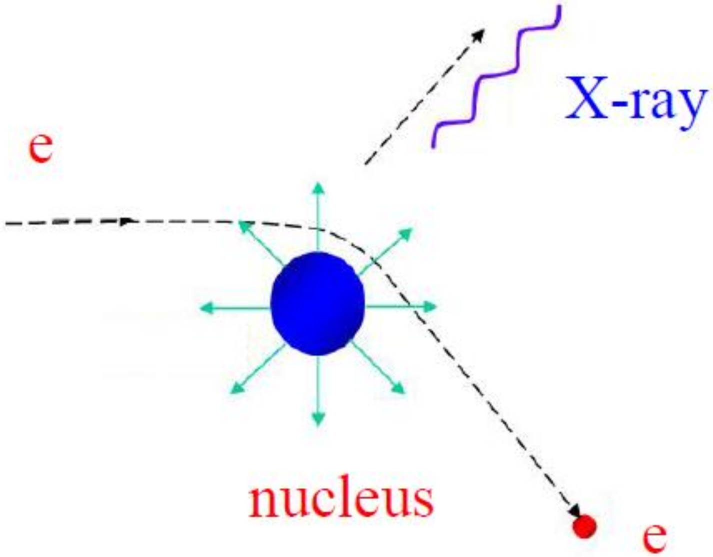
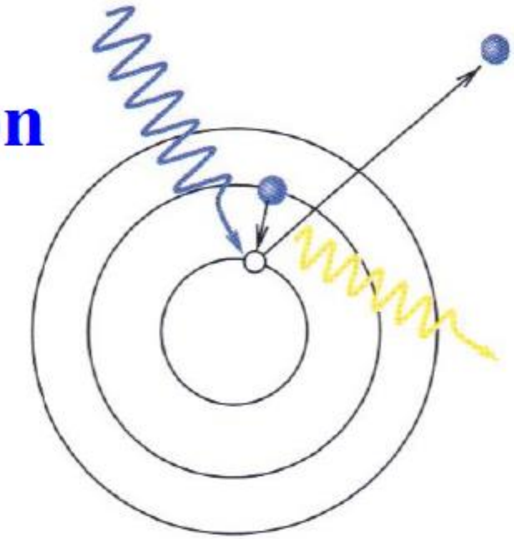
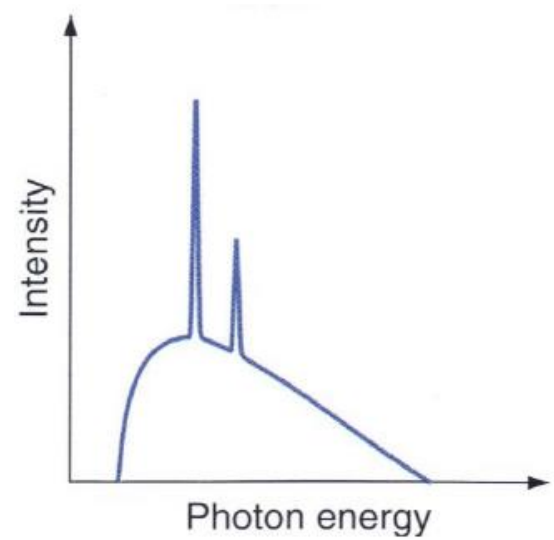
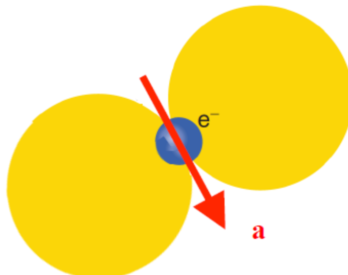
Characteristic X-ray emission



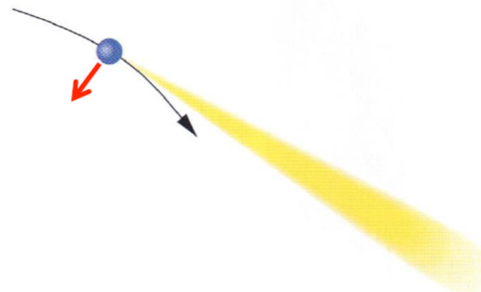




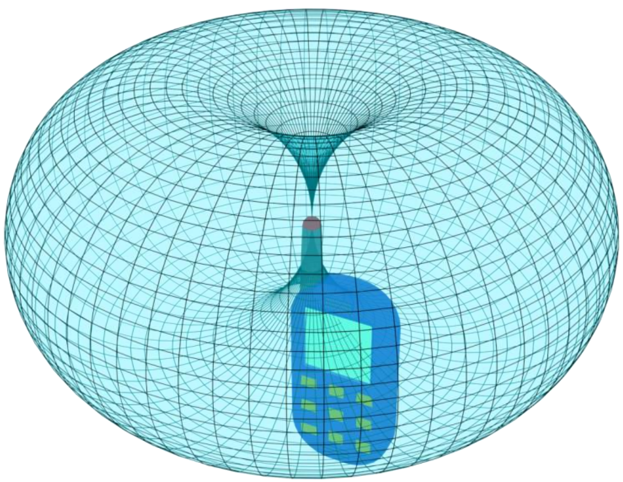
Electromagnetic wave from a moving charge

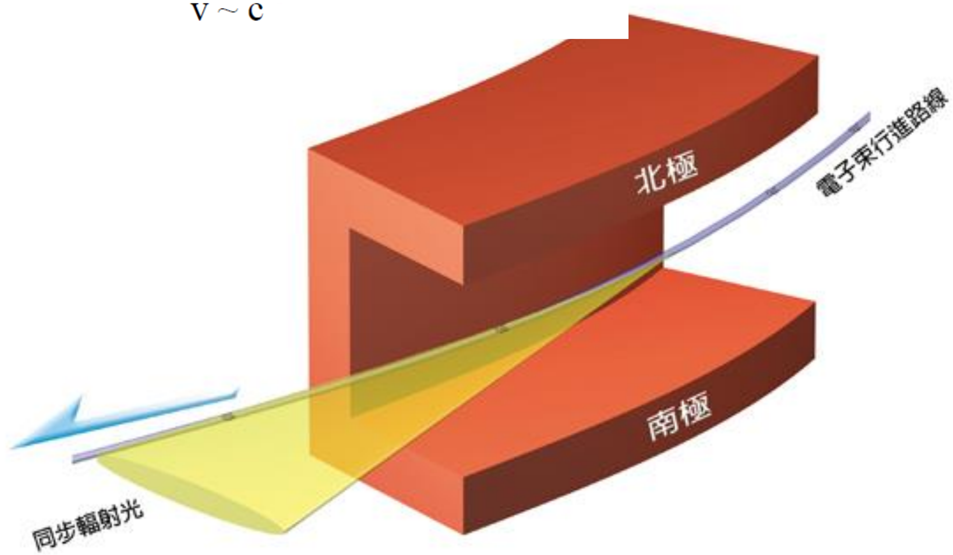


v << c



v ~ c

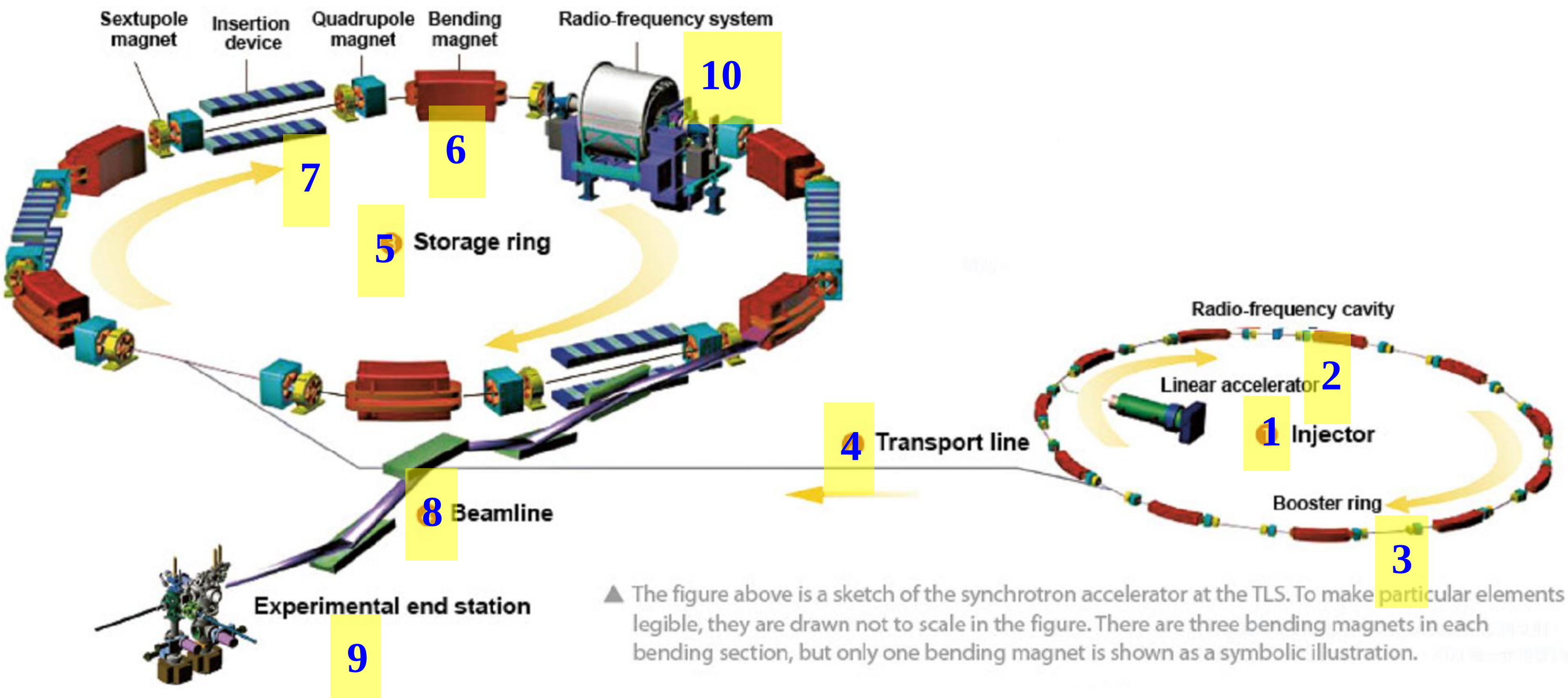




二極偏轉磁鐵

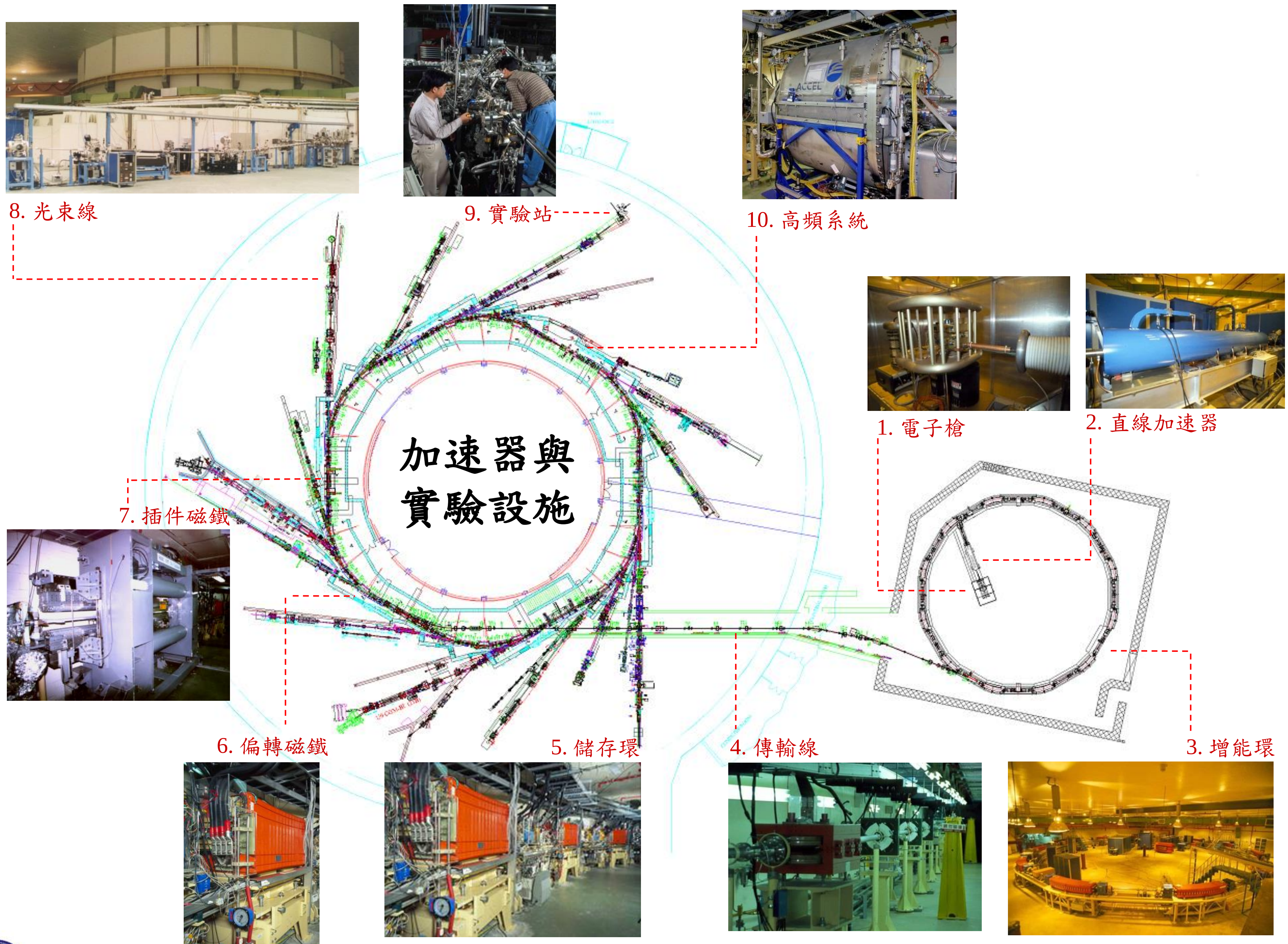
同步加速器光源的原理

- 電子在電子槍(1)內產生，經過直線加速器(2)加速至能量為5,000萬電子伏特。
- 電子束進入增能環(3)後，繼續增加能量至15億電子伏特(1.5GeV)，速度非常接近光速(0.99999995倍)。
- 電子束經由傳輸線(4)進入儲存環(5) 。
- 當儲存環累積足夠的電子束後，經由各個磁鐵的導引與聚焦，電子束在偏轉磁鐵(6)及插件磁鐵(7)發出同步加速器光源，經由光束線(8)將光源引導至實驗站(9)進行實驗。
- 電子束在發出同步加速器光源後，要靠高頻腔(10)來補充失去的能量。



▲ The figure above is a sketch of the synchrotron accelerator at the TLS. To make particular elements legible, they are drawn not to scale in the figure. There are three bending magnets in each bending section, but only one bending magnet is shown as a symbolic illustration.

加速器與實驗設施



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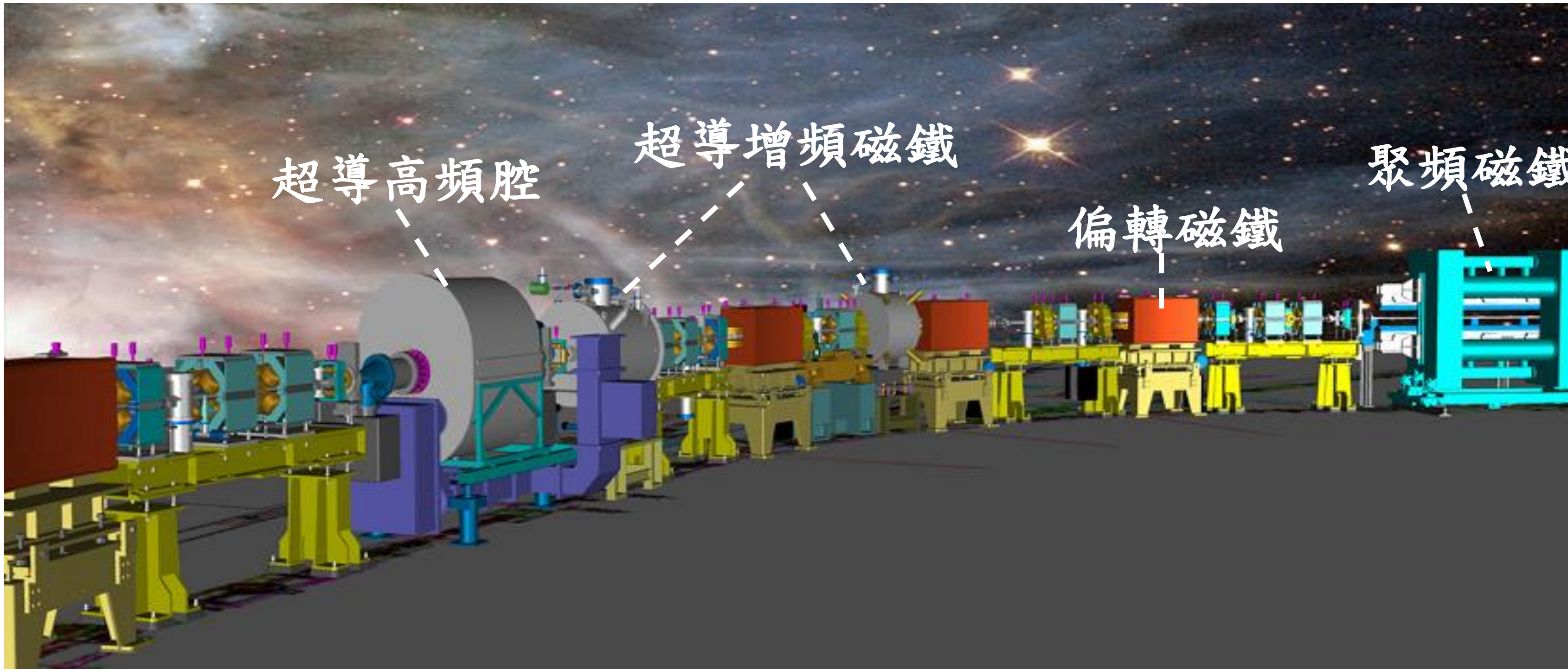
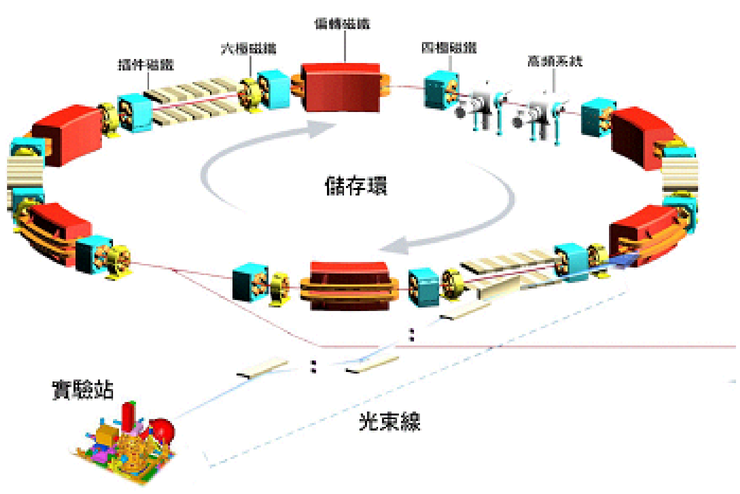
儲存環 3D 圖





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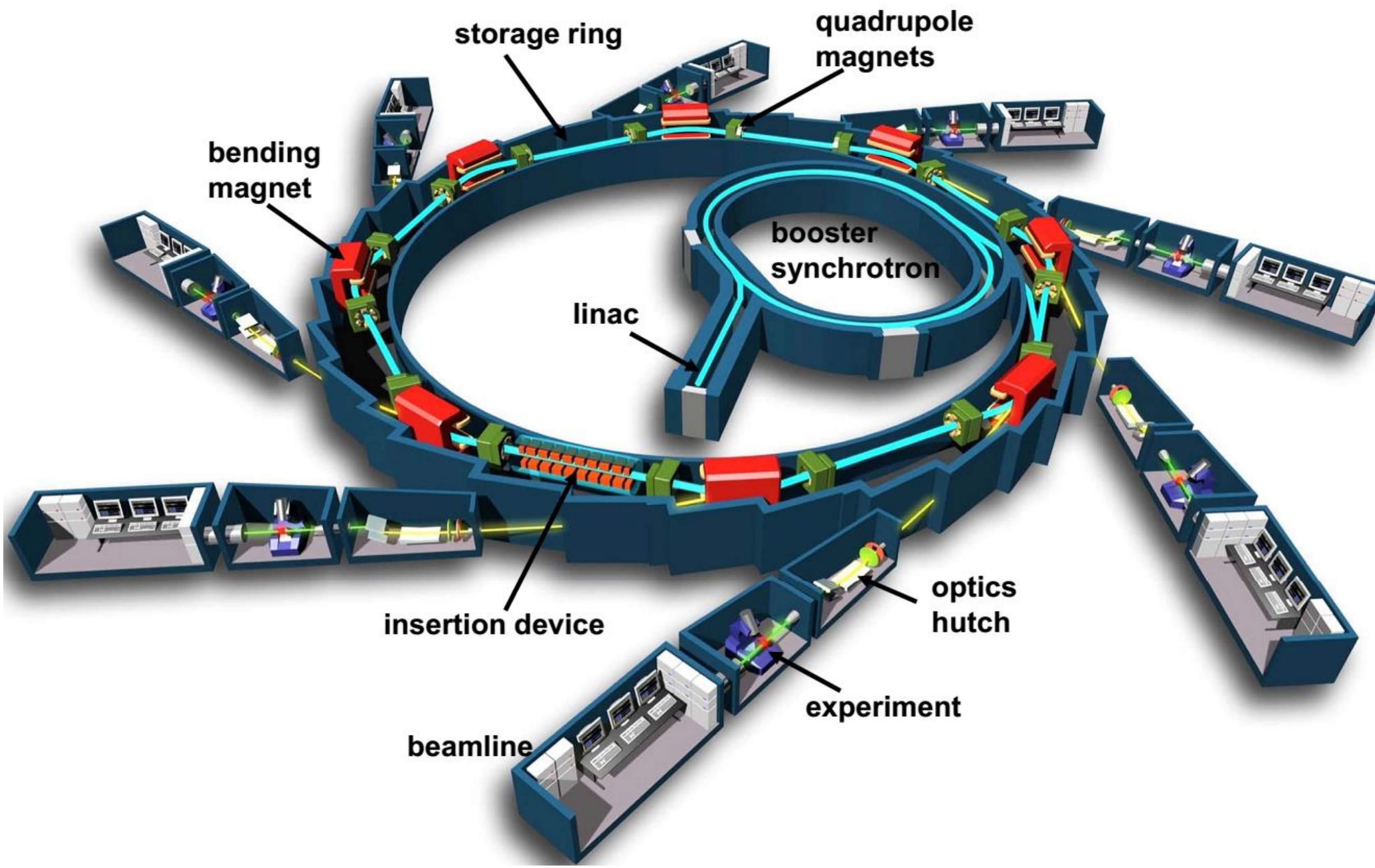
A Synchrotron Step by Step



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A brief history

- First observed:

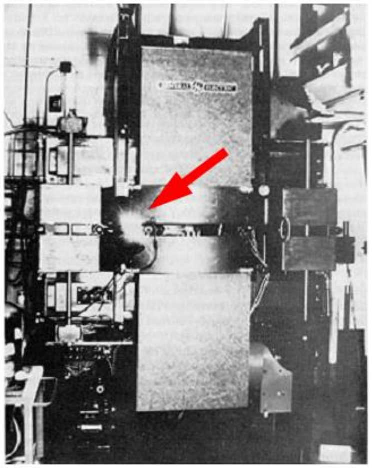
  1947, General Electric, 70 MeV synchrotron

- First user experiments:

  1956, Cornell, 320 MeV synchrotron

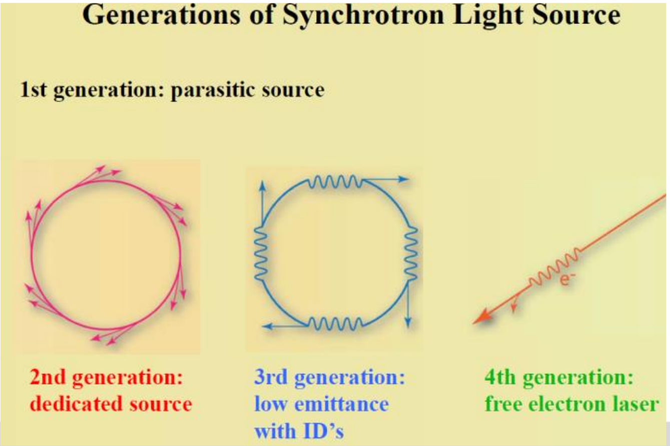
- First insertion Device:

  1979, 7 pole wiggler, SSRL



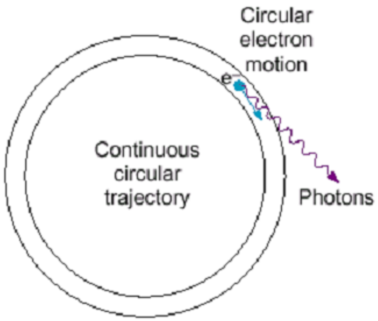
- 1st generation light sources: high energy physics synchrotrons and storage rings used parasitically for synchrotron radiation – eg DESY (Germany), INS-SOR (Tokyo), SPEAR (USA), (1960's, 1970's)
- 2nd generation light sources: purpose built synchrotron light sources, eg Photon Factory, NSLS, Daresbury (1980s onwards)
- 3rd generation light sources: optimised for high brilliance with low emittance and Insertion Devices; SPRing-8,ESRF, APS, Diamond, …(1990's onwards)
- Free Electron Laser sources: FLASH (Germany), LCLS (USA), SACLA (Japan), FERMI (Italy) … (2000's)
- Next??

2015 Cheiron School

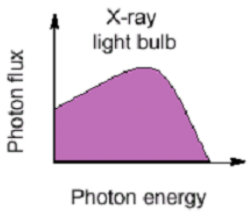


Third Generation Sources: Undulator Insertion Devices

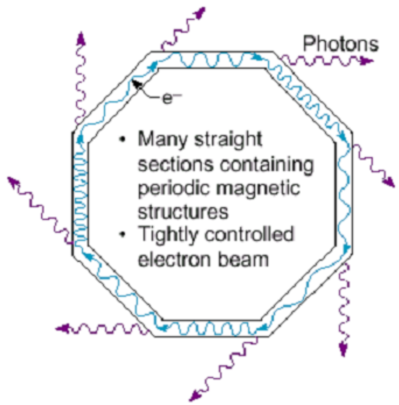
1st, 2nd Generation



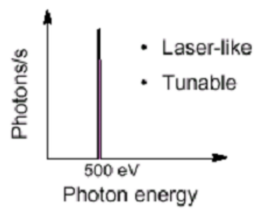
Bend Magnet Radiation

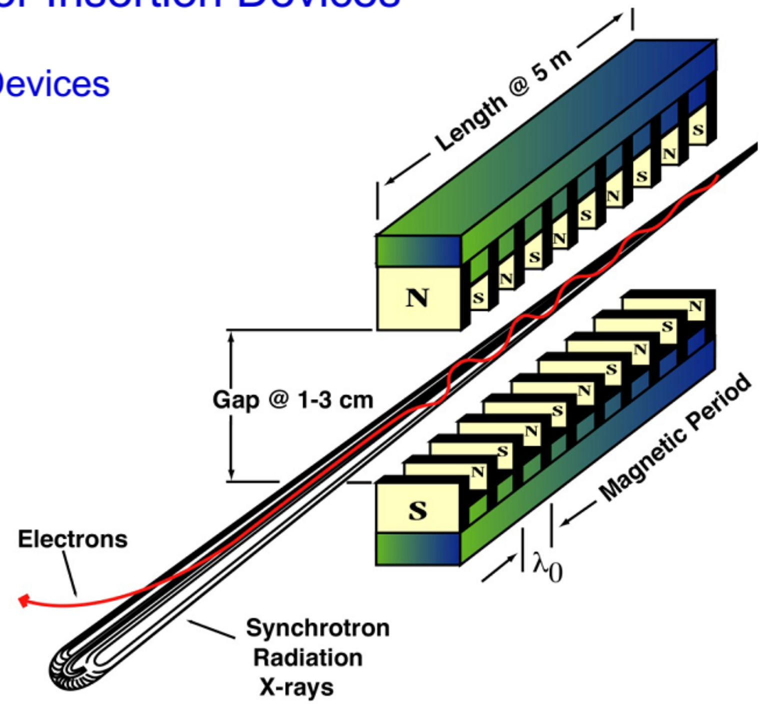


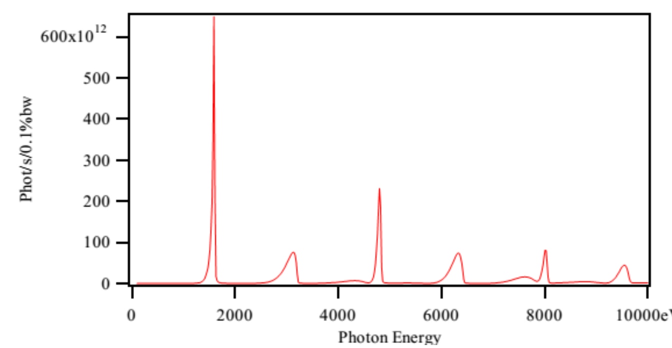
3rd Generation: Insertion Devices



Undulator Radiation

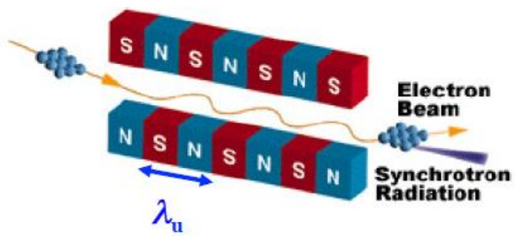




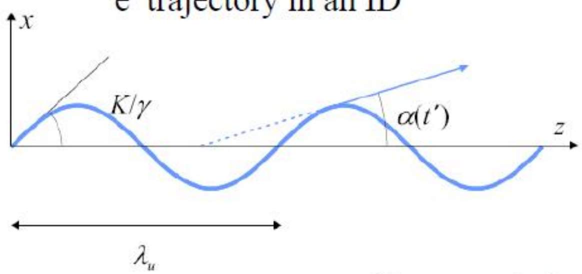


Angular distribution of synchrotron radiation emitted from various magnets

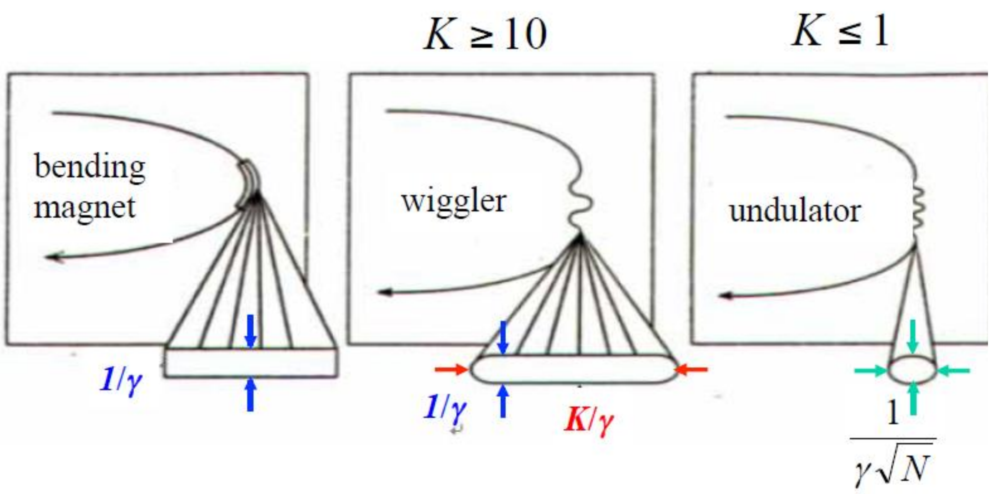
Wiggler or undulator

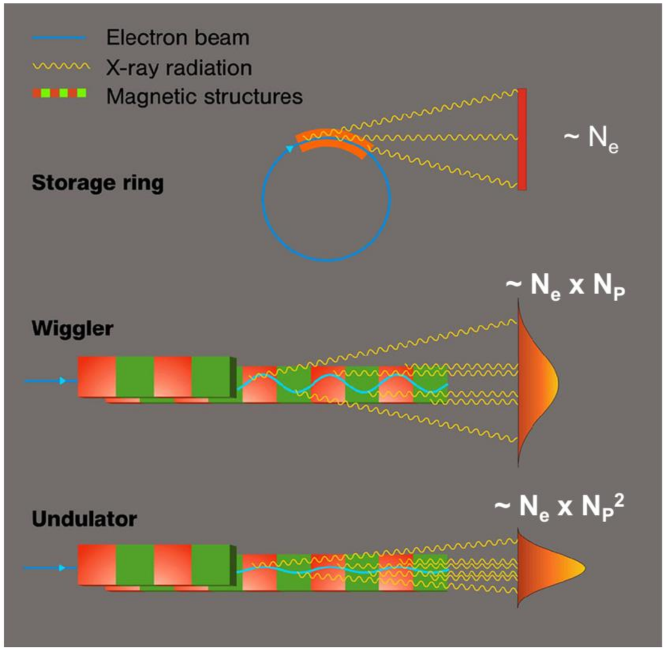


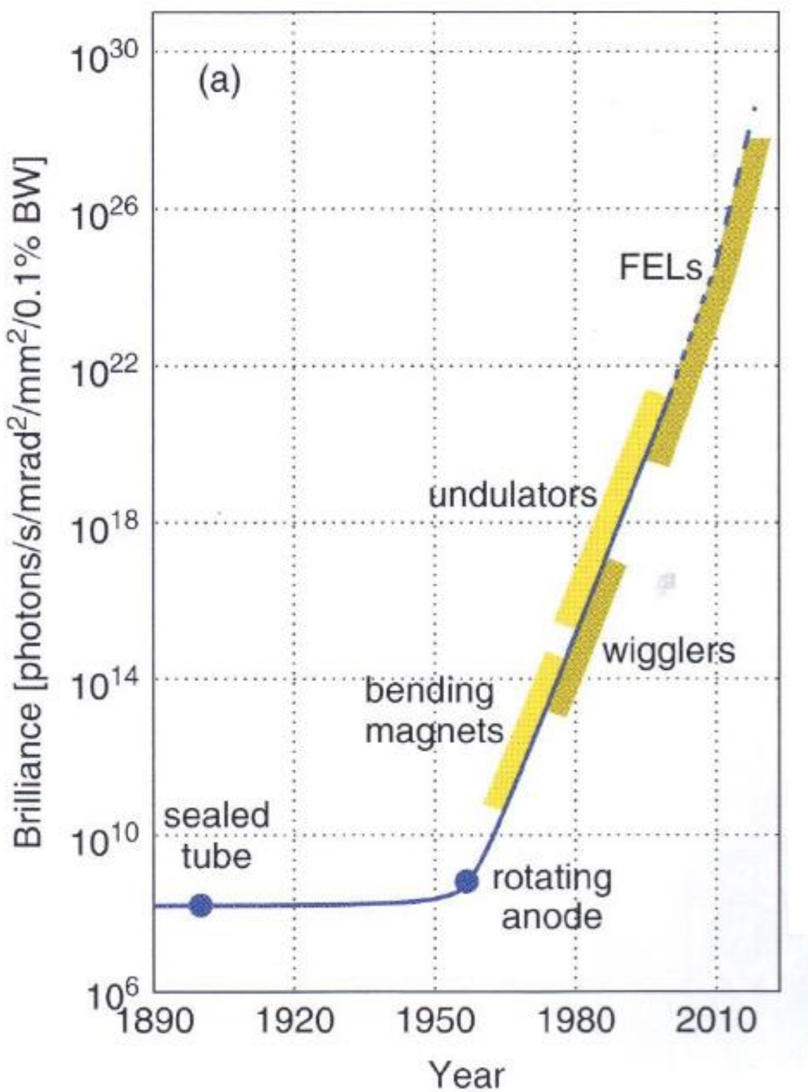
e^- trajectory in an ID

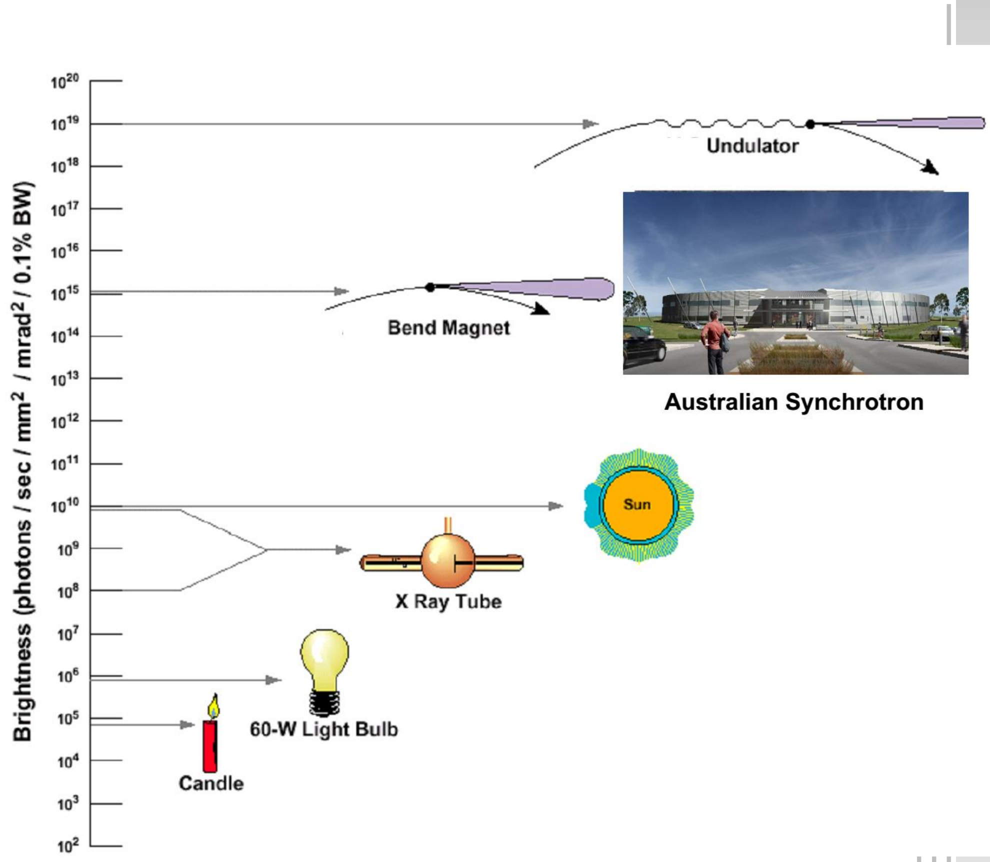


$$K = \alpha_{max.} / \gamma^{-1}$$









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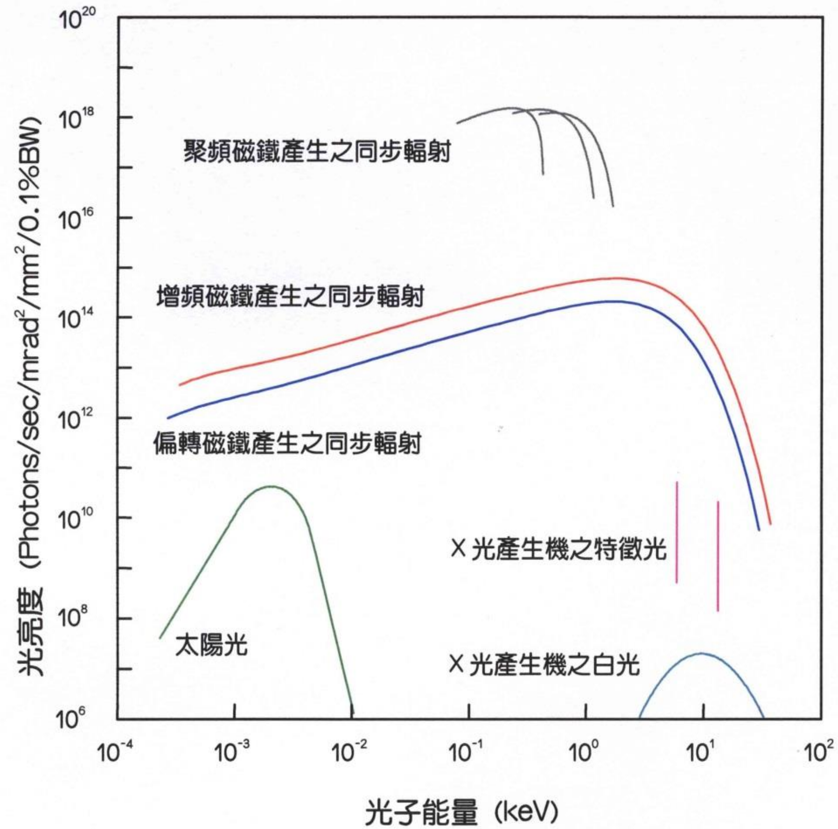
Unique Features of Synchrotron Light Source

- **High intensity**
- **Continuous spectrum**
- **Excellent collimation**
- **High polarization**
- **Pulsed-time structure**

以X光為例，同步加速器光源在這個波段的亮度比傳統X光機還要強百萬倍以上！過去需要幾個月才能完成的實驗，現在只需幾分鐘便能得到結果。以往因實驗光源亮度不夠而無法探測的結構，現在藉由同步加速器光源，都可分析得一清二楚，也因此得以開發新的研究領域。



- 光子能量：一般單位爲電子伏特(eV)，一電子伏特爲電子在真空中通過一伏特電位差所獲得的能量。
- 光亮度：指單位時間內通過單位立體角的單位頻寬光子數。

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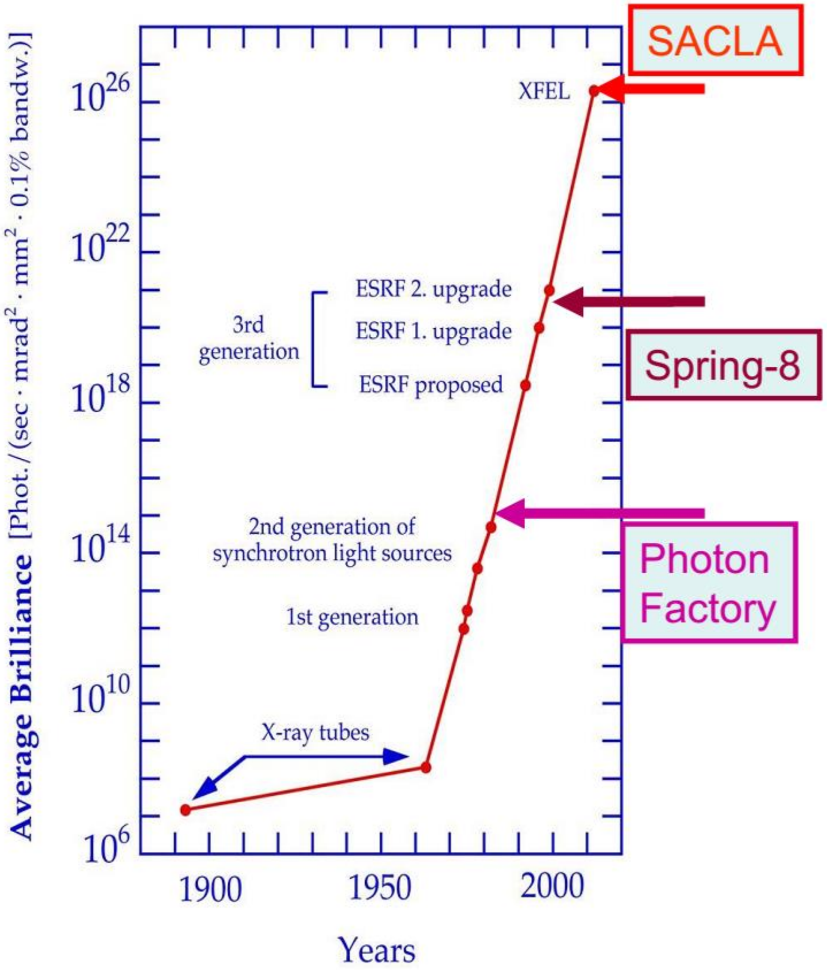
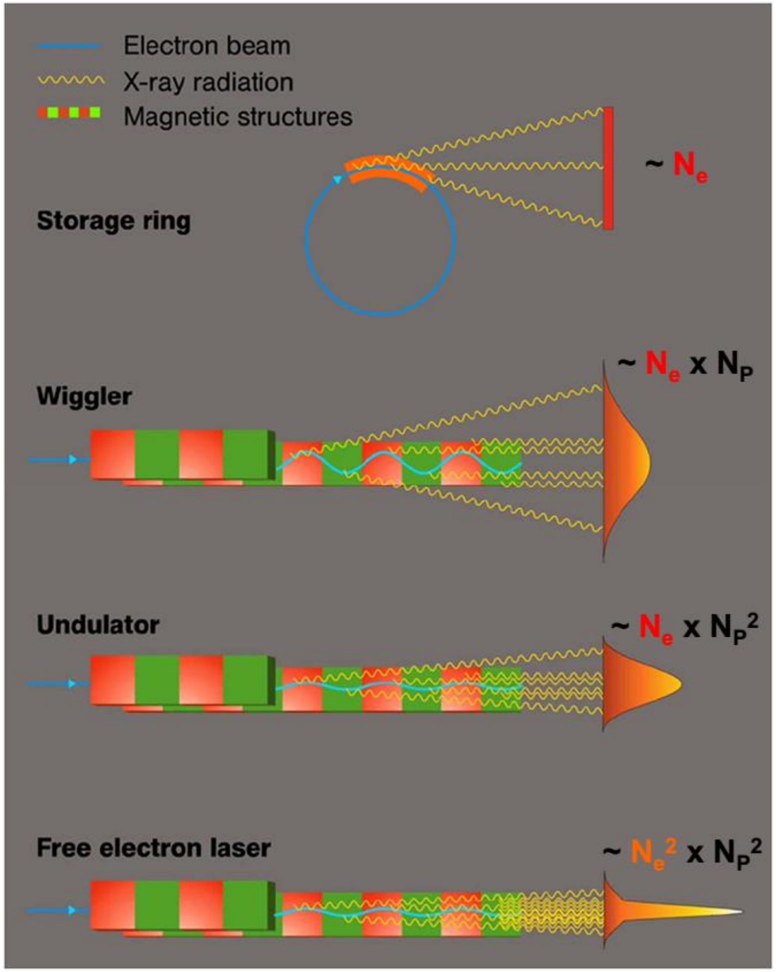
Next Step - X-ray Lasers? Yes ➔ FELs





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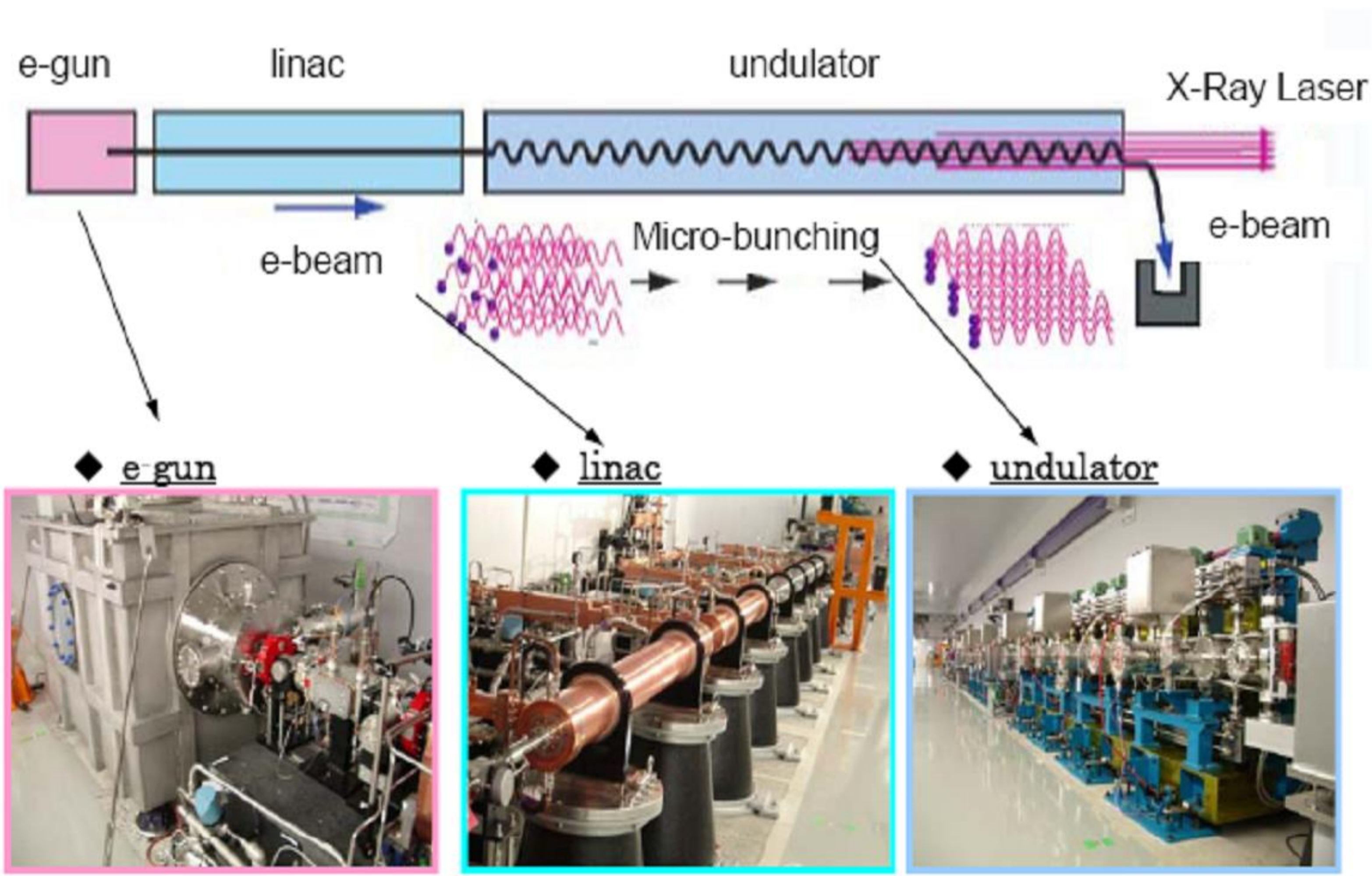
Linac-Based Free Electron Laser
Self-Amplified Spontaneous Emission (SASE)



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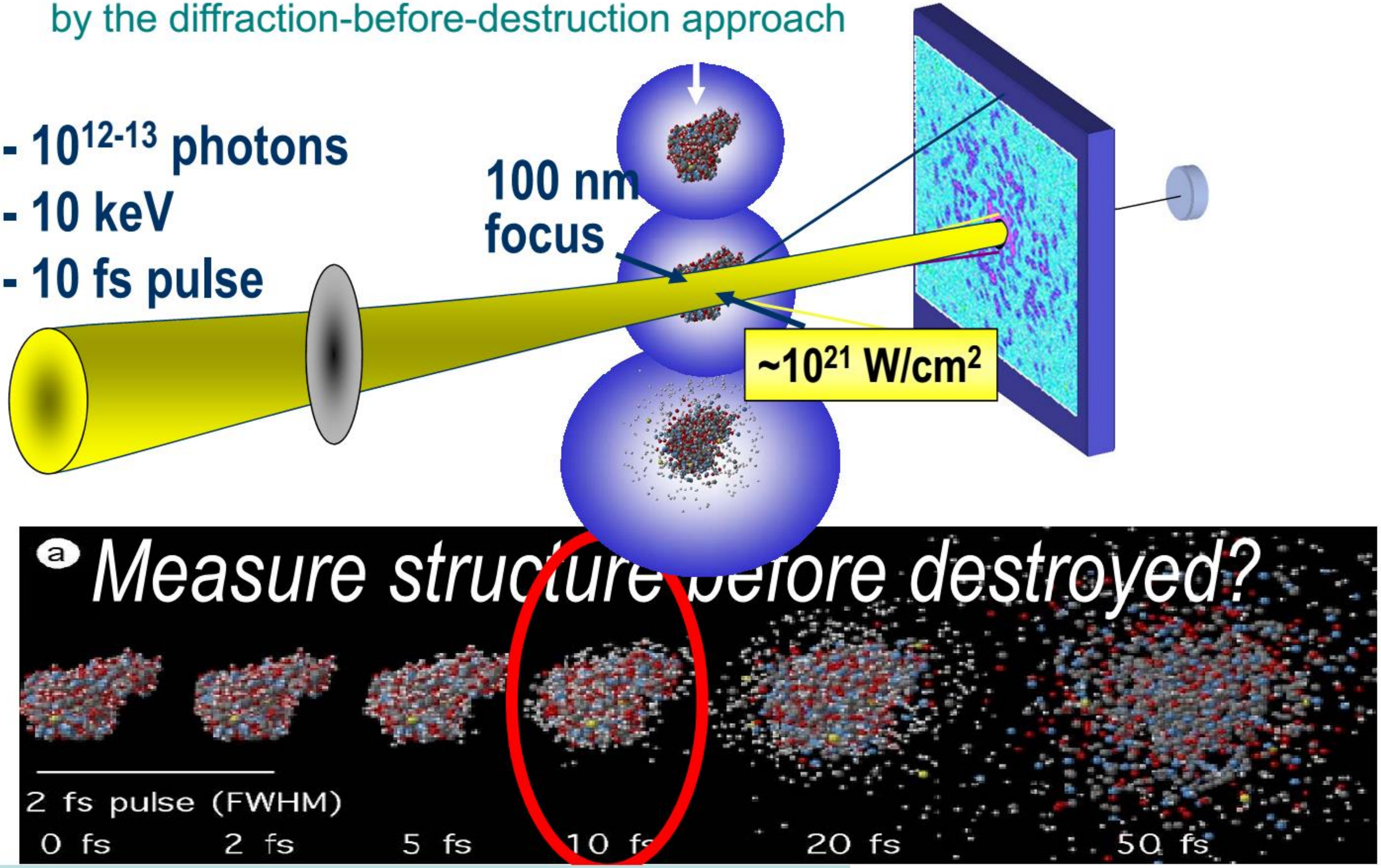
Coherent diffractive imaging of single particles

by the diffraction-before-destruction approach



Calculations. in vacuum Neutze et al., Nature 2000

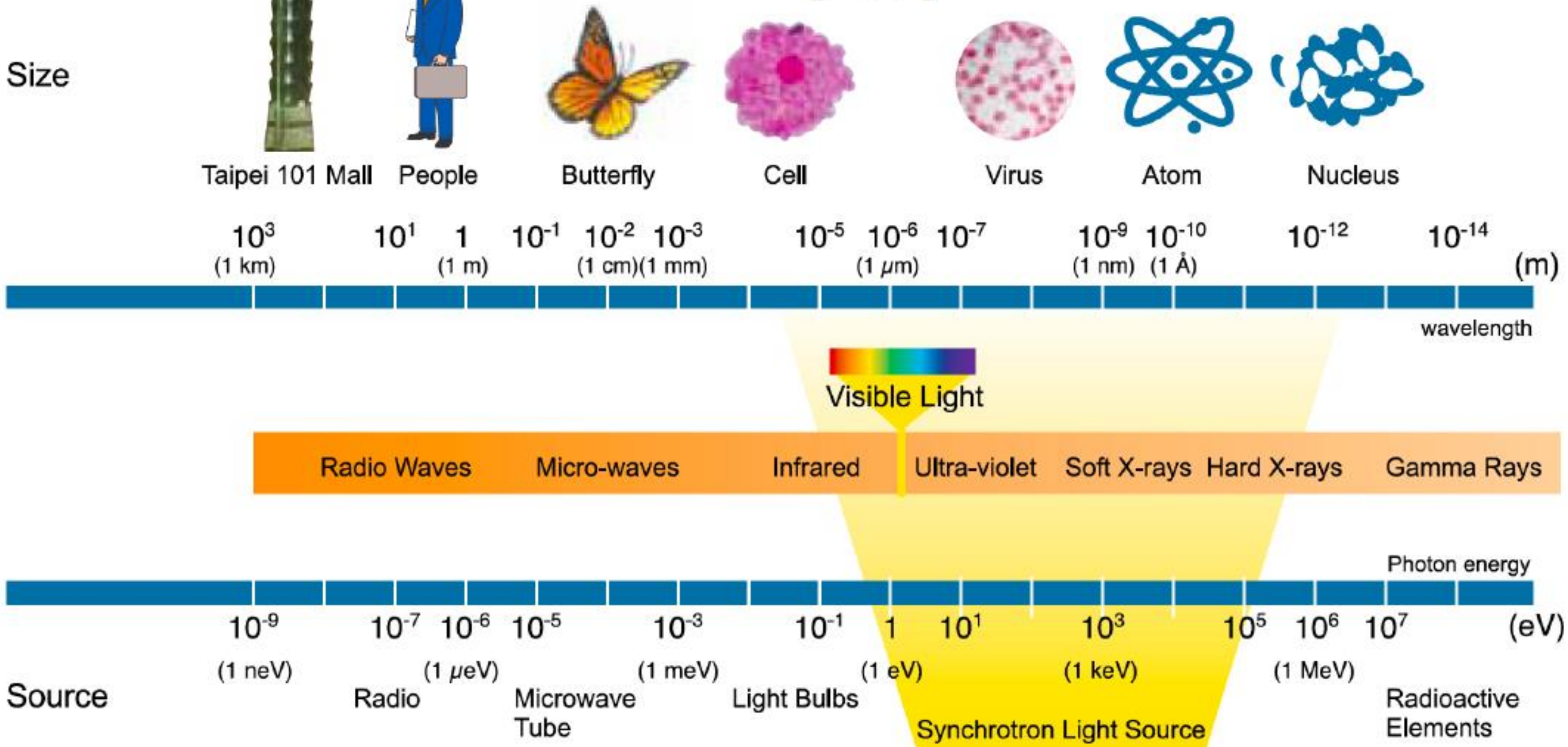
$$E = h\nu = hc/\lambda,$$

$$h = 6.626 \times 10^{-34}\,\mathrm{J\,s}$$

$$c = 2.9979 \times 10^{8}\,\mathrm{m\,s^{-1}}$$

Electromagnetic Spectrum

$$\lambda\,[\text{Å}] = \frac{12.3984}{E\,[\text{keV}]}$$



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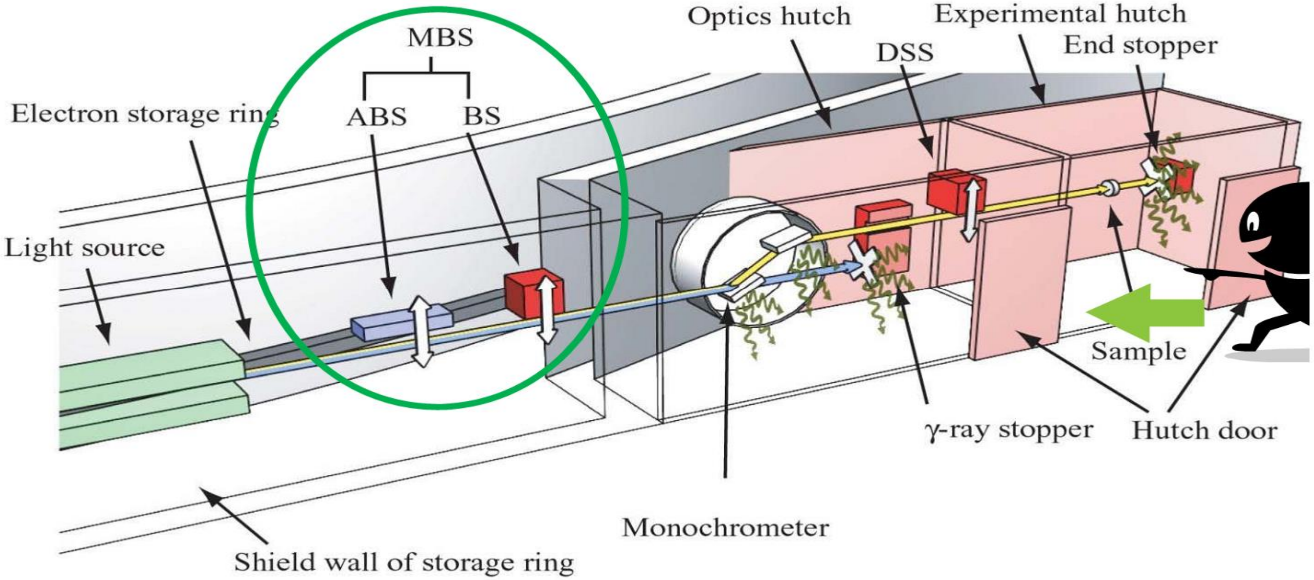
Beamline



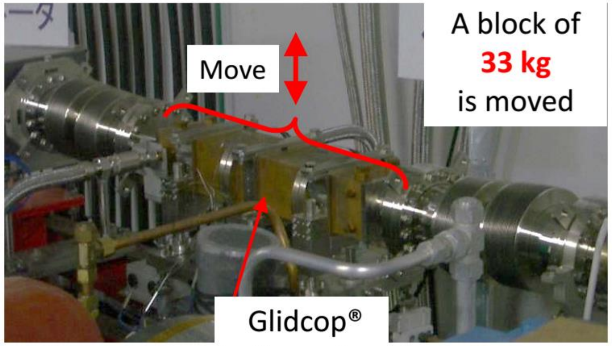
For safety

When we operate a main beam shutter (MBS), what happens ?

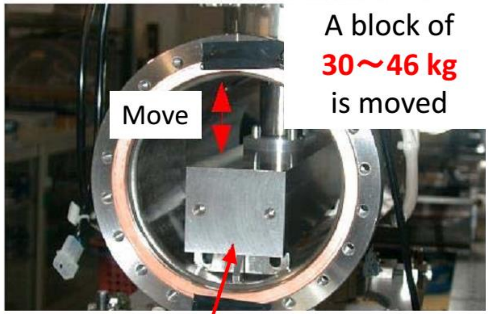
X-ray → Absorber (Abs) → Beam shutter (BS)

to protect BS from heat load

to shield you against radiation



(copper that is dispersion-strengthened with ultra-fine particles of aluminum oxide)



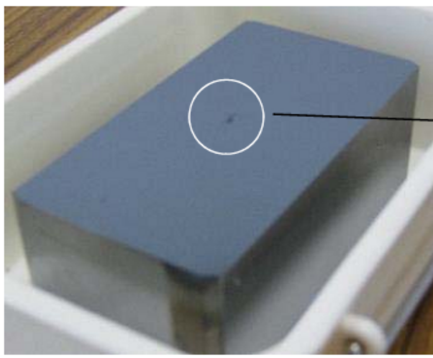
Heavy metal
(alloy of tungsten)

the thermal conductivity not so high

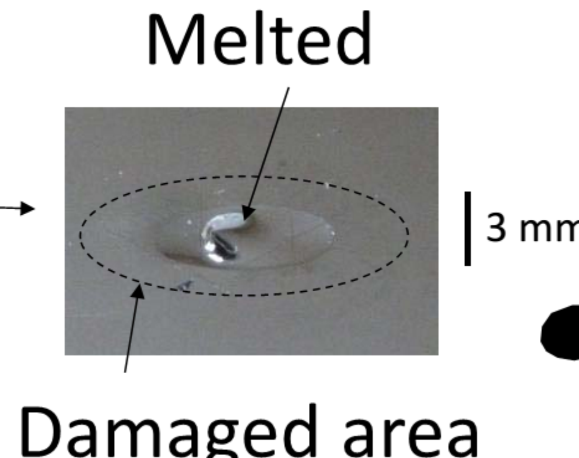
If an optical component is irradiated by too much power ....

One user opened FE slit excessively.

2kW

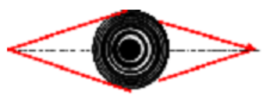
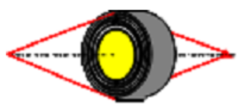


LN2-cooled Si crystal



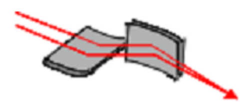
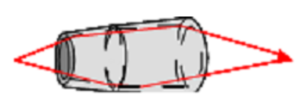
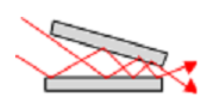
Slit : *"Too much is as bad as too little"*

Overview of x-ray focusing devices

Diffraction	focus size, focal length [energy]	energy range	aberration -coma -chromatic -figure error
 Fresnel Zone Plate	12 nm, f = 0.16 mm [0.7 keV], 30 nm, f = 8 cm [8 keV]	soft x-ray hard x-ray	-coma small -chromatic exist -figure error small
 Sputter sliced FZP	0.3 µm, f = 22 cm [12.4 keV], 0.5 µm, f = 90 cm [100 keV]	8-100 keV	-coma small -chromatic exist -figure error large→small
 Bragg FZP	2.4 µm, f = 70 cm [13.3 keV]	mainly hard x-ray	-coma small -chromatic exist -figure error small
 Multilayer Laue Lens	16 nm(1D), f = 2.6 mm [19.5 keV], 25nm × 40nm, f=2.6mm,4.7mm [19.5 keV]	mainly hard x-ray	-coma large -chromatic exist -figure error small

Refraction	focus size, focal length [energy]	energy range	aberration -coma -chromatic -figure error
 Pressed Lens	1.5 µm, f = 80 cm [18.4 keV], 1.6 µm, f = 1.3 m [15 keV]	mainly hard x-ray	-coma small -chromatic exist -figure error large
 Etching Lens	47nm × 55nm, f = 1cm, 2cm [21 keV]	mainly hard x-ray	-coma small -chromatic exist -figure error small

Reflection

 Kirkpatrick-Baez Mirror	7 nm × 8nm, f=7.5cm [20 keV]	soft x-ray hard x-ray	-coma large -chromatic not exist -figure error small
 Wolter Mirror	0.7 µm, f = 35 cm [9 keV]	<10 keV	-coma small -chromatic not exist -figure error large
 X-ray Waveguide	95 nm, [10 keV]	soft x-ray hard x-ray	-coma large -chromatic not exist -figure error large

World Map of Synchrotron Facilities

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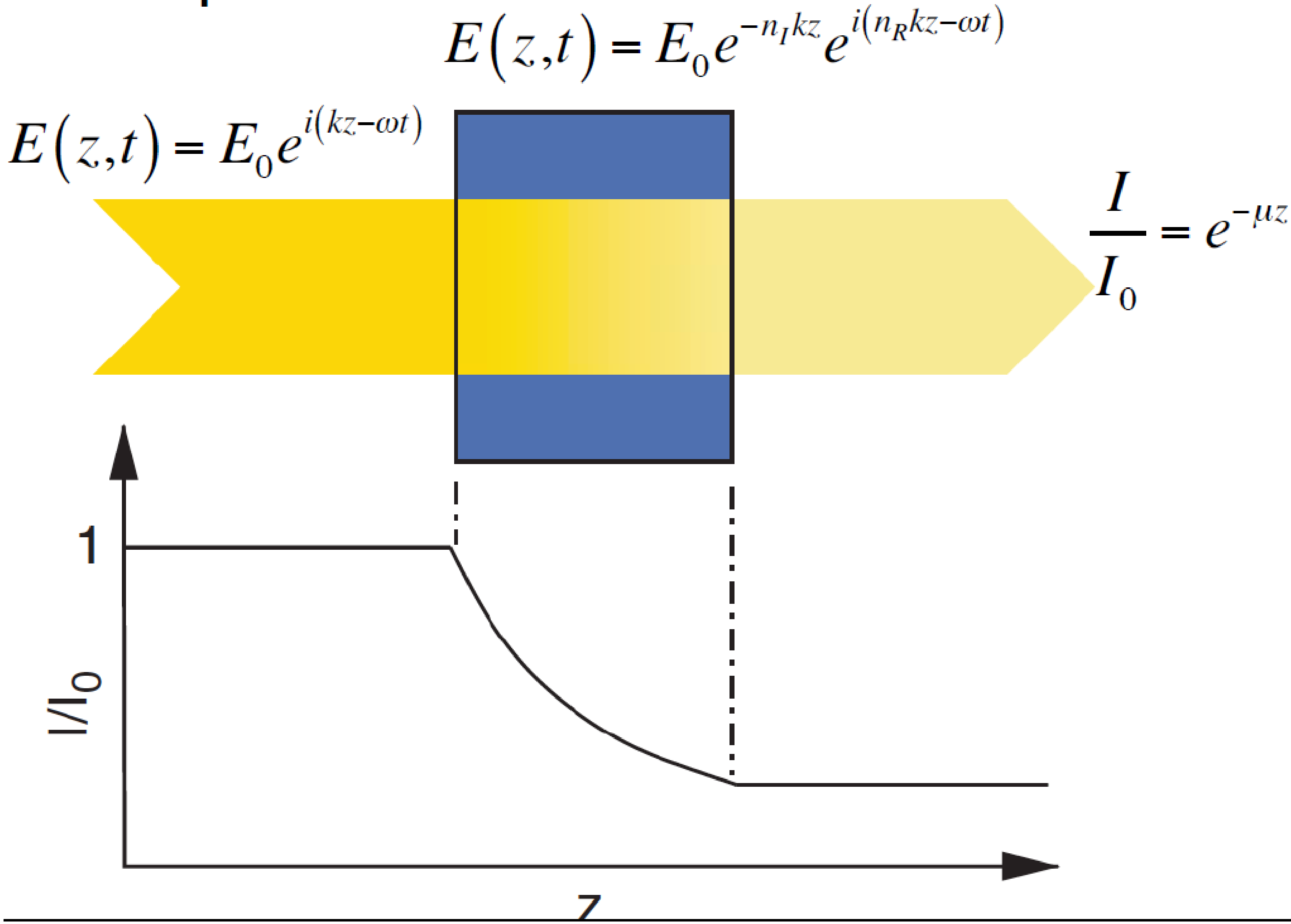
- Synchrotron Light Source
- Application of Synchrotron Light
- X-ray nano probe at TPS

Absorption



$E(z,t) = E_0 e^{-n_I kz} e^{i(n_R kz - \omega t)}$
$E(z,t) = E_0 e^{i(kz - \omega t)}$
$\frac{I}{I_0} = e^{-\mu z}$
1
I/I0
z

absorption coefficient

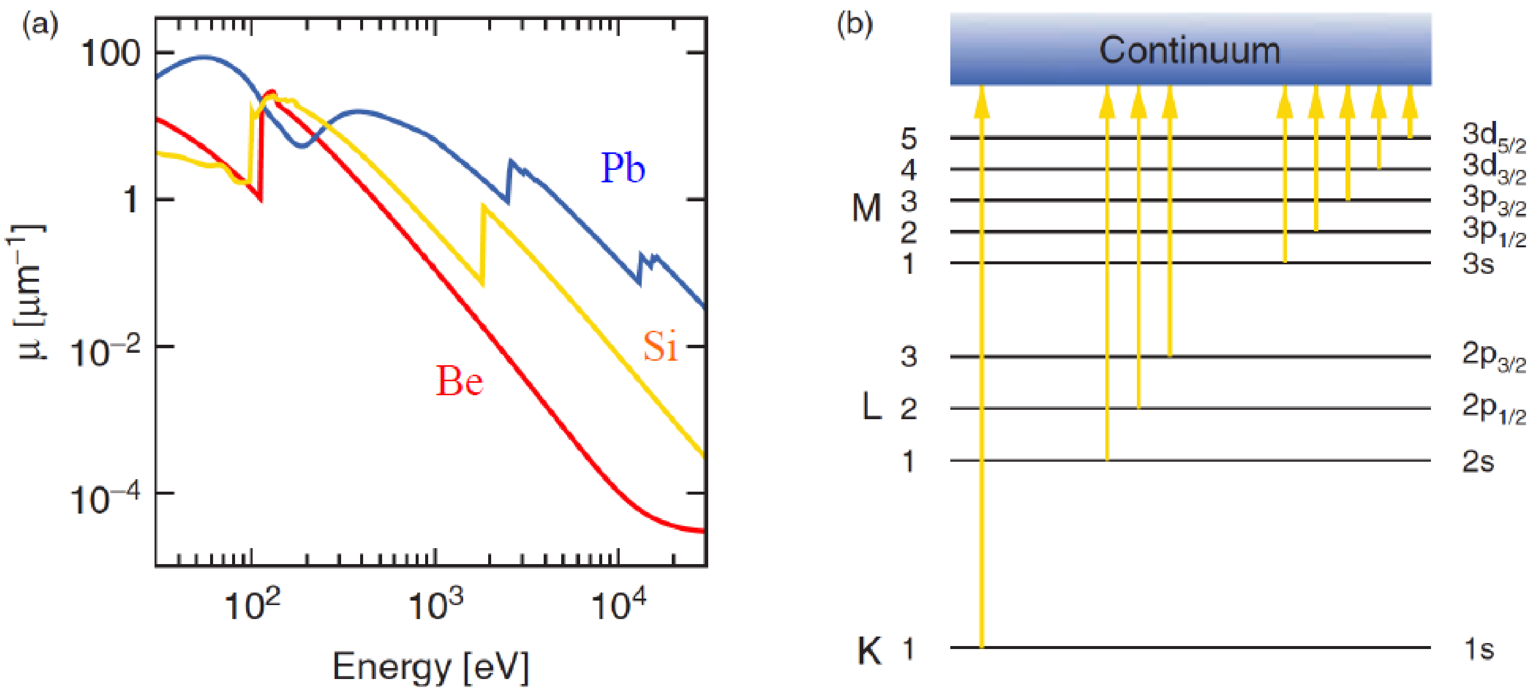
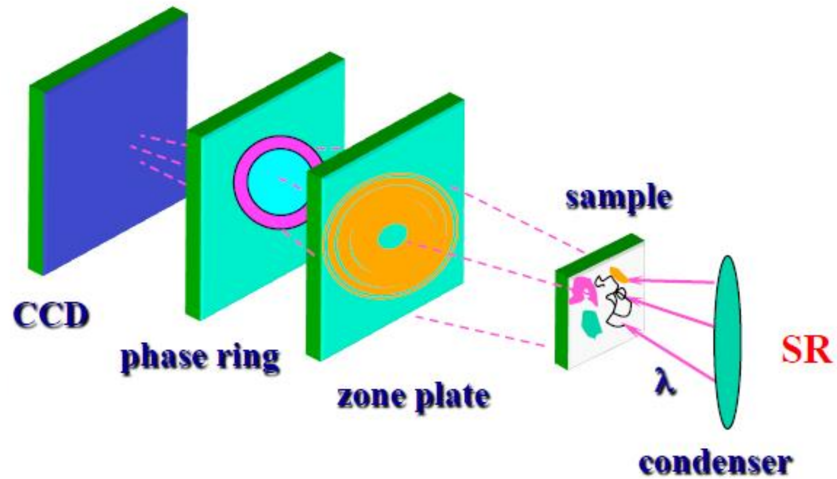


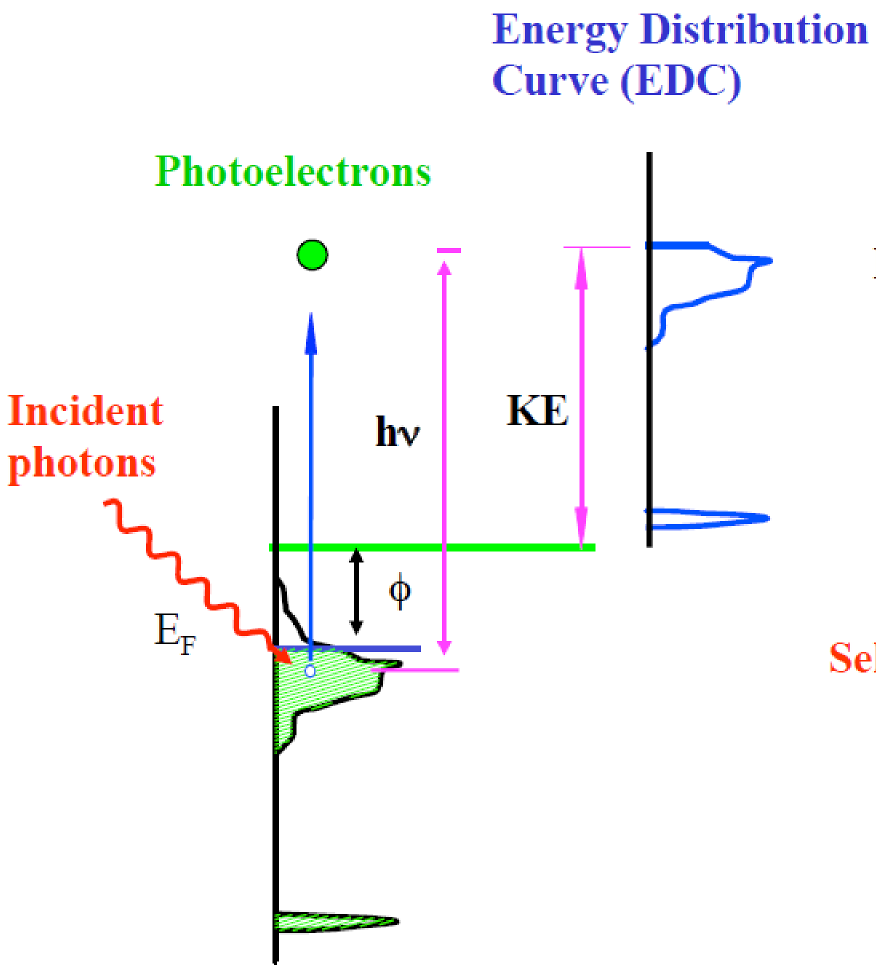
Figure 2.16 *(a) The x-ray absorption coefficient μ for beryllium (red curve), silicon (yellow) and lead (blue) as a function of the photon energy. (b) Sharp increases in the absorption occur when the photon energy is just sufficient to eject the electron from the electronic orbital to the continuum. The x-ray absorption (left) and atomic orbital labellings (right) are shown.*

Transmission X-ray Microscope (TXM)



energy: 8 keV
3D tomography
spatial resolution = 60 nm

Photoemission Spectroscopy



KE = hν-BE-ϕ

$$\frac{d\sigma}{d\Omega} \propto \sum \left| \left\langle \Psi_f \middle| A \cdot P \middle| \Psi_i \right\rangle \right|^2 \cdot \delta\left(E_f - E_i - h\nu\right)$$

Selection rule: $\Delta\, l = \pm 1$

$\Delta\, m_l = 0$ (linearly polarized)

$\Delta\, m_l = +1$ (L. circularly polarized)

$\Delta\, m_l = -1$ (R. circularly polarized)

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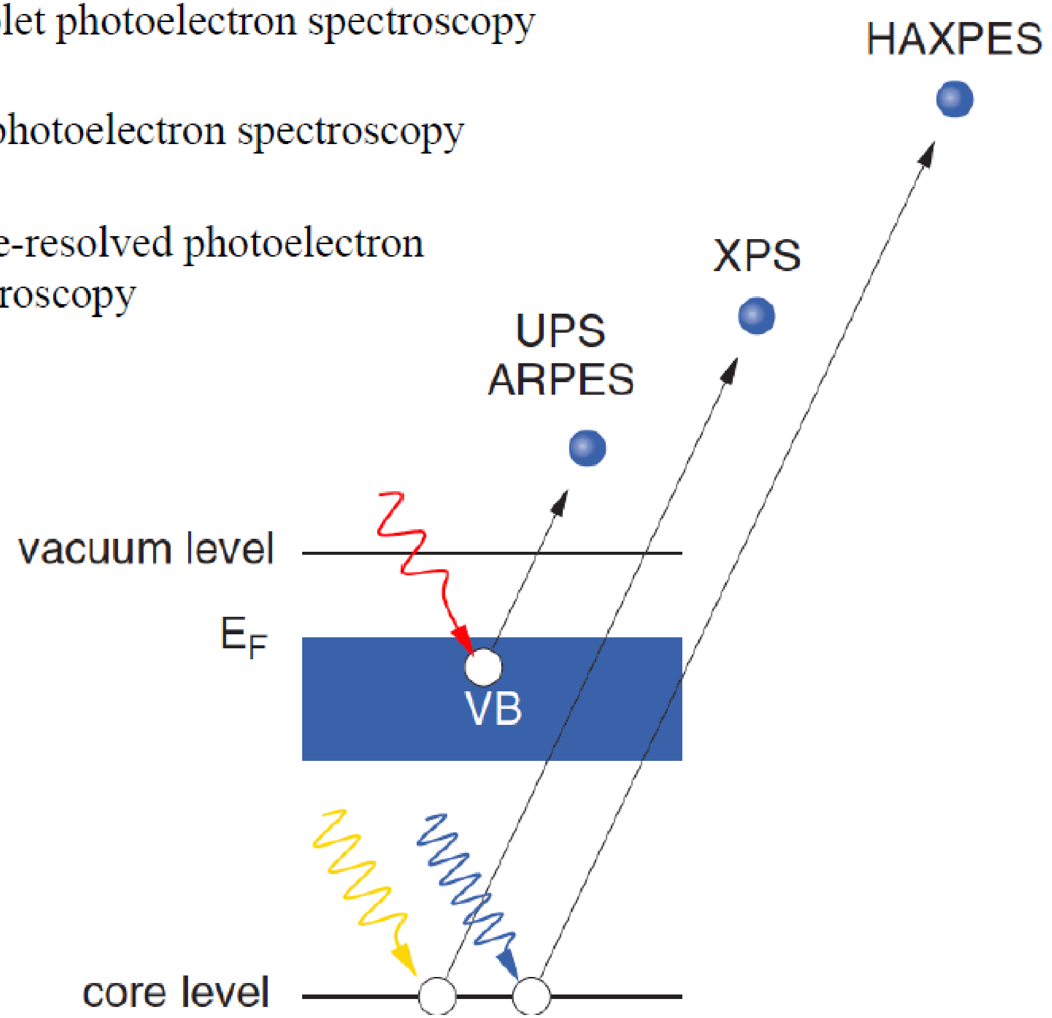
HAXPES = Hard X-ray photoelectron spectroscopy

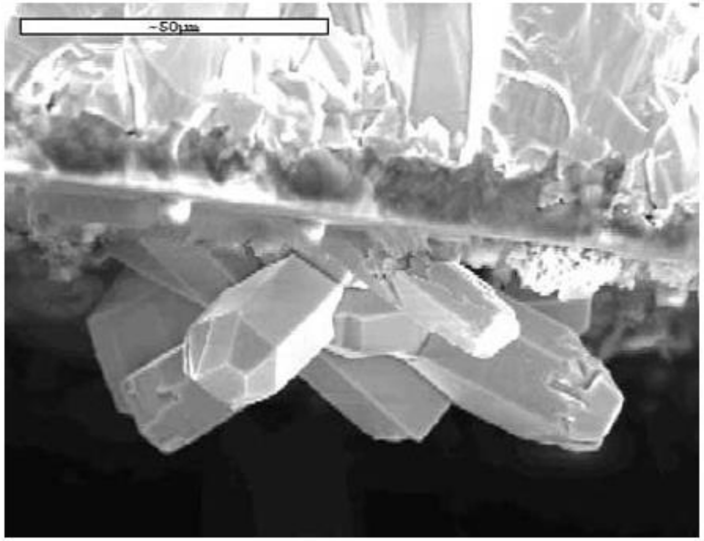
UPS = ultraviolet photoelectron spectroscopy

XPS = X-ray photoelectron spectroscopy

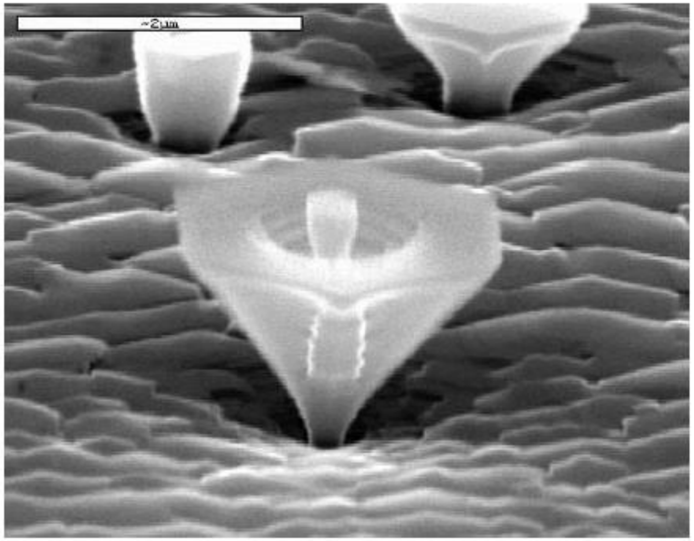
ARPES = angle-resolved photoelectron spectroscopy



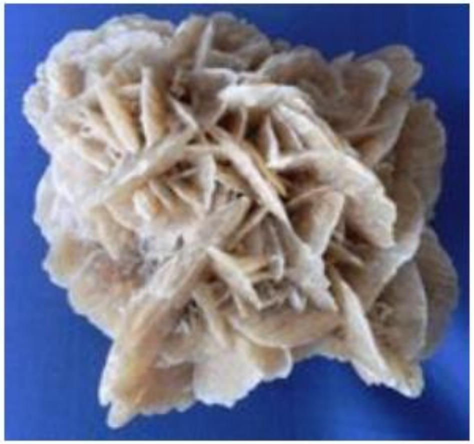
“Crystals”



GaN (hexagonal) crystal cluster grown by hydride vapor phase epitaxy



AlN pyramids grown by MBE



Sand Rose of gypsum (石膏) crystals

Bragg Law - X-ray reflected by the (hkl) planes

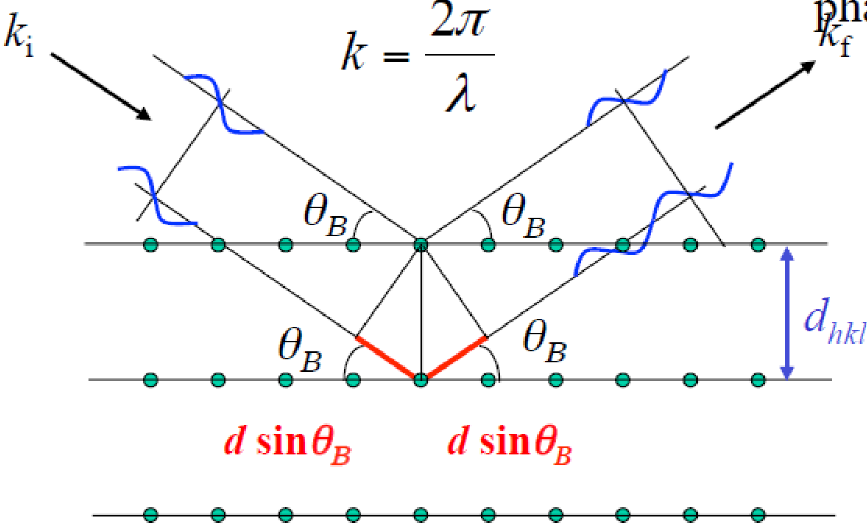
$$\vec{E} = E_0 e^{i(\vec{k}\cdot\vec{r}-\omega t)}$$

$$k = \frac{2\pi}{\lambda}$$

Path Difference $L = 2d_{hkl}\sin\theta_B$

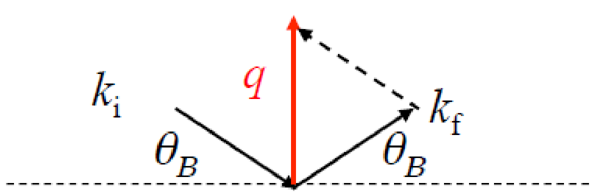
Constructive interference: $L = n\lambda$

phase difference $\phi = k\,L$



Bragg Law: $2d_{hkl}\sin\theta_B = n\lambda$

$$2\pi\frac{2}{\lambda}\sin\theta_B = 2\pi\frac{1}{d_{hkl}} = G_{hkl}$$



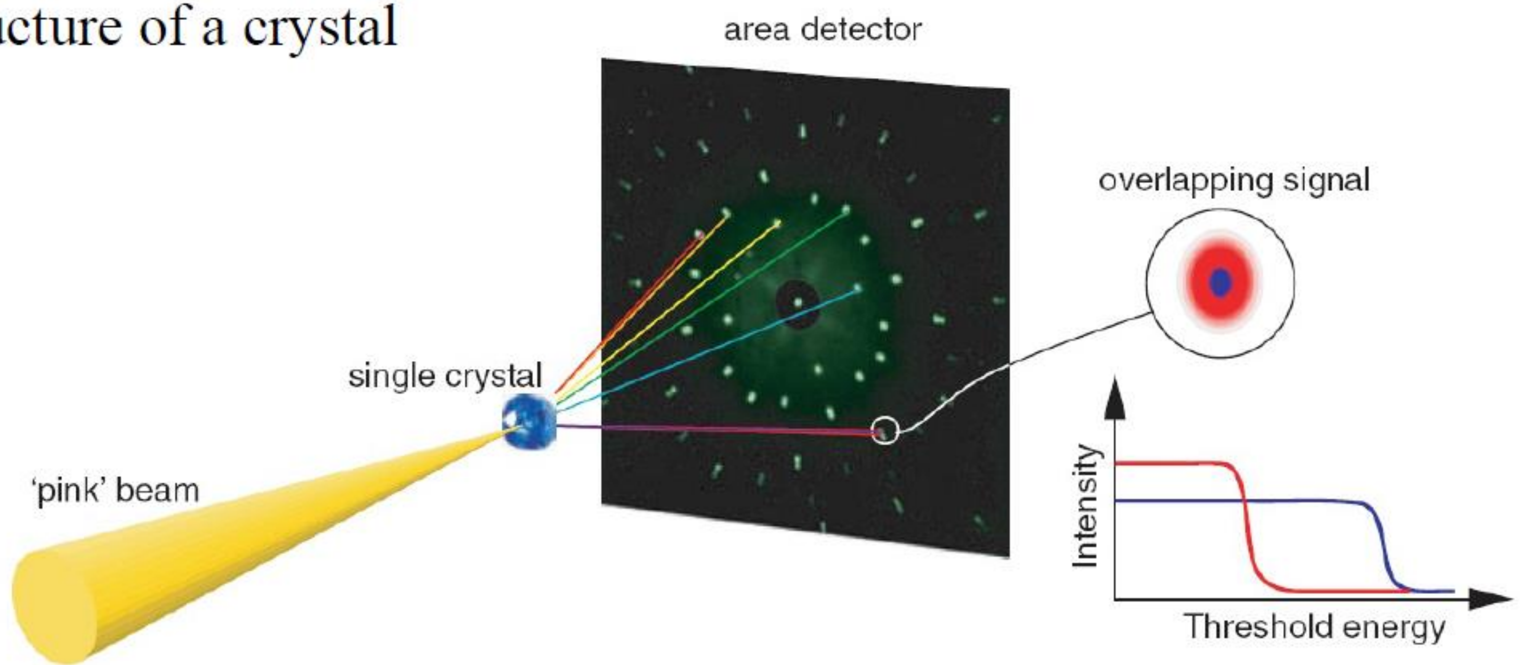
scattering vector $\vec{q} = \vec{k}_f - \vec{k}_i$ $\quad q = 2\frac{2\pi}{\lambda}\sin\theta_B$

$$q = G_{hkl}$$

In terms of diffraction, two key characteristics of a set of crystal planes :
$1/d$ and orientation

Single Crystal Diffraction - Laue Diffraction

•Method: stationary
•Light source: a polychromatic 'pink' beam (e.g. ΔE <1 keV @ 10 keV)
•Applications: orient single crystals, determine their crystal quality, dynamical studies of transient crystalline states (time-resolved study)
•Disadvantage: not well-suited for determining the full atomic structure of a crystal



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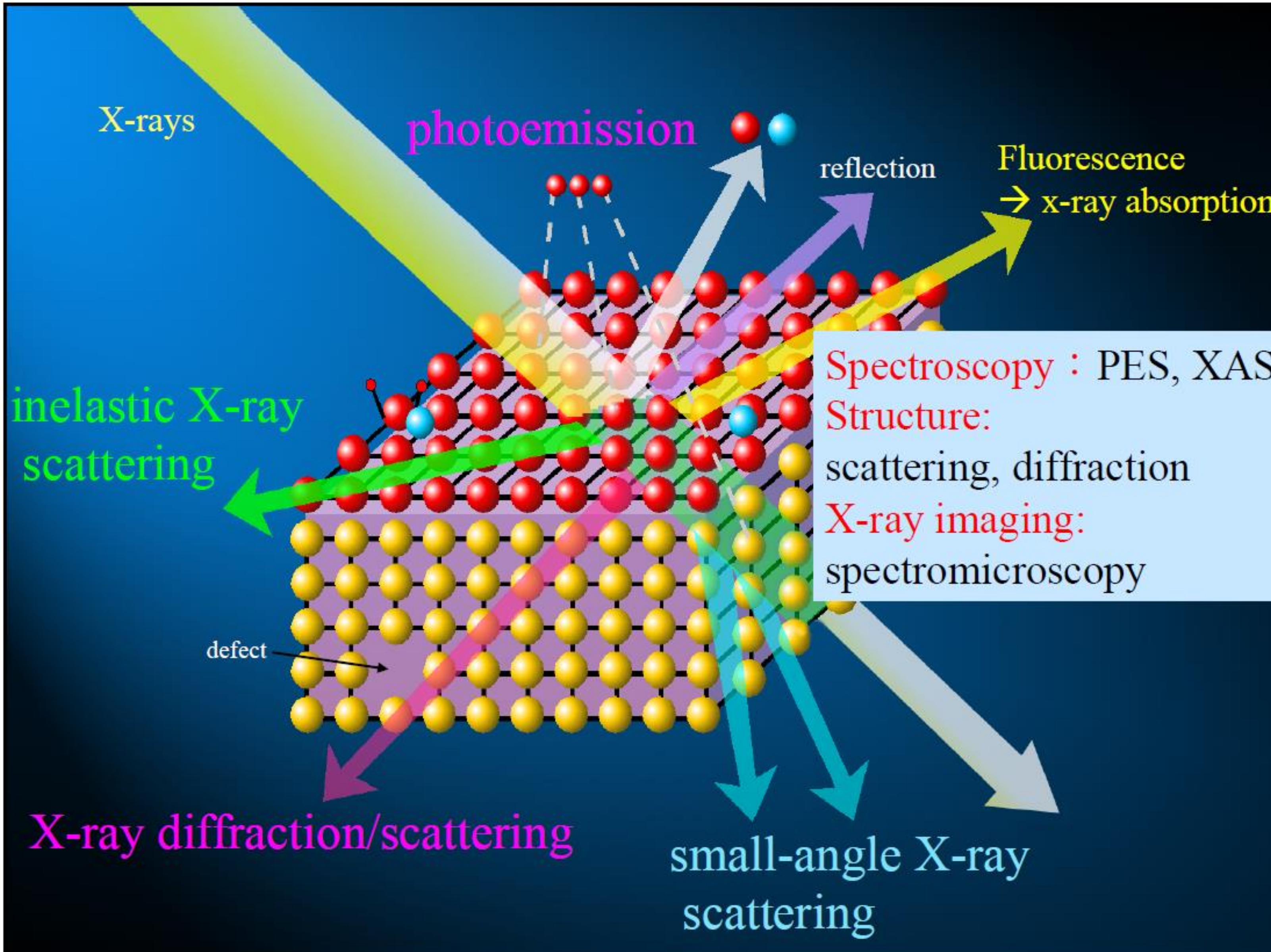

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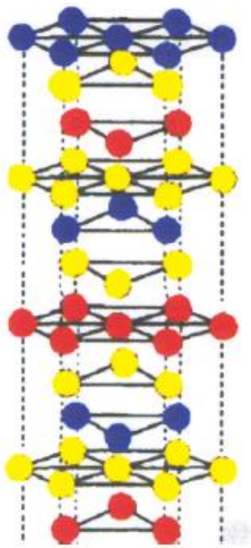
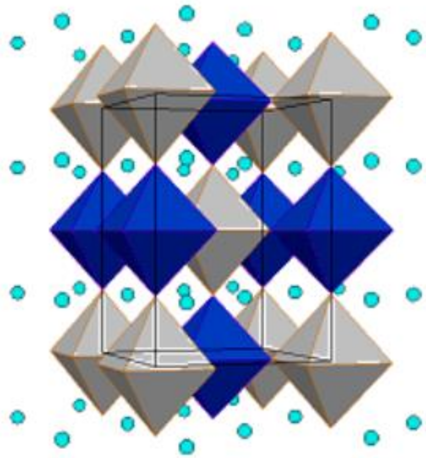
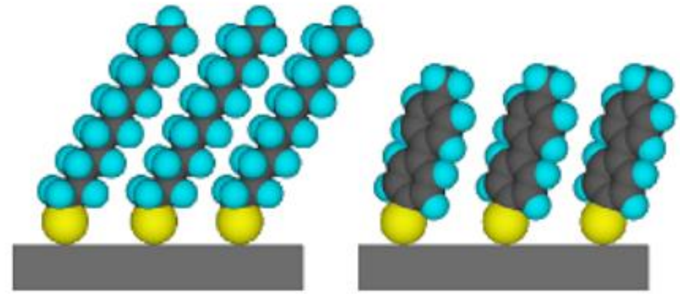
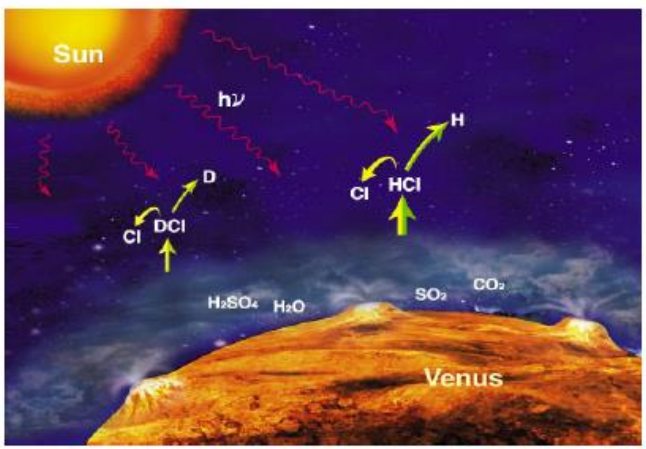
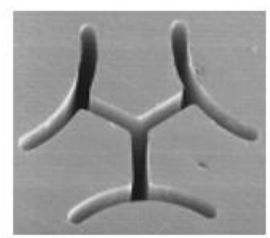
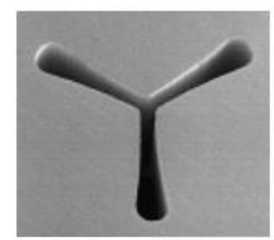






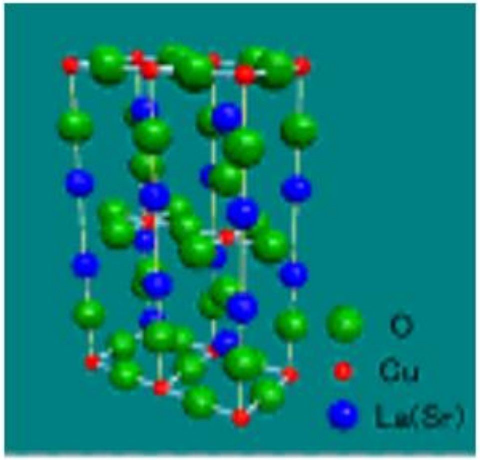




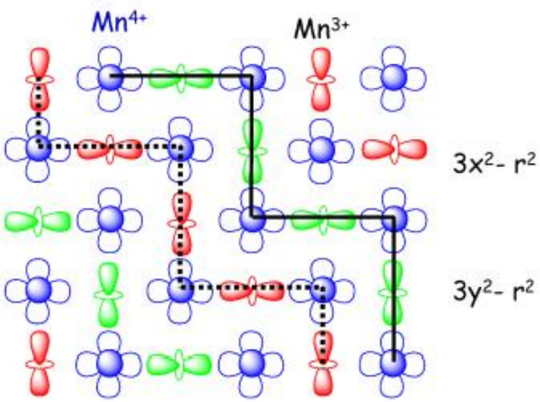


Synchrotron light source is a powerful tool for basic and applied studies in physics, chemistry, materials, biology and medicine, and their many subfields.

Condensed-Matter Physics



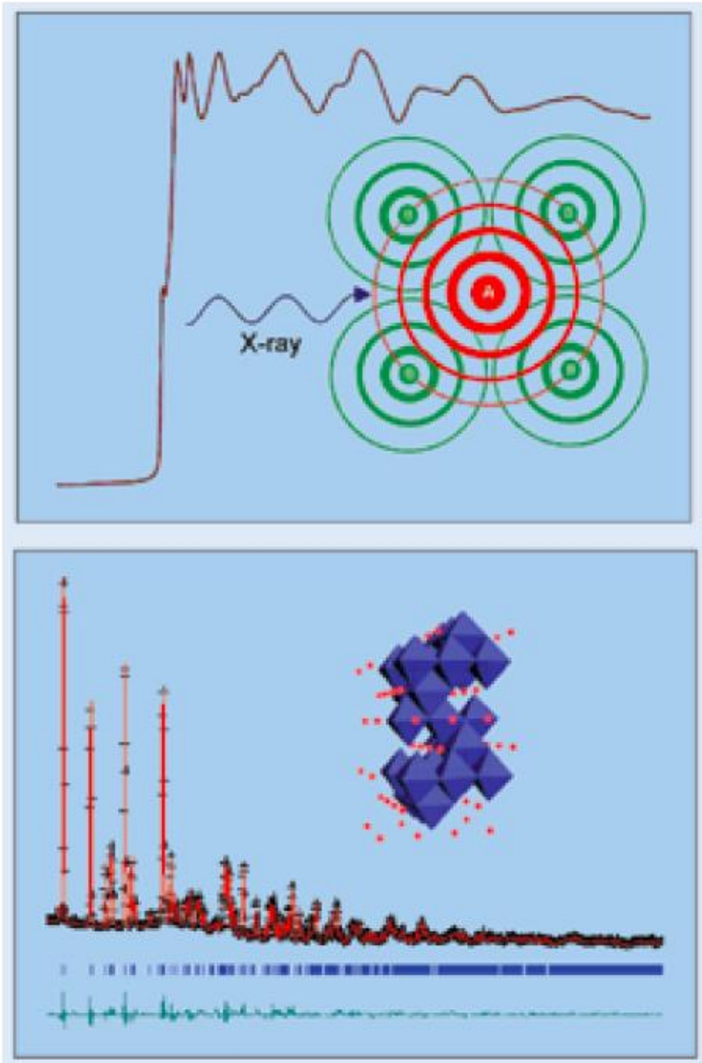
Electronic properties of novel materials can be revealed with X-ray scattering.

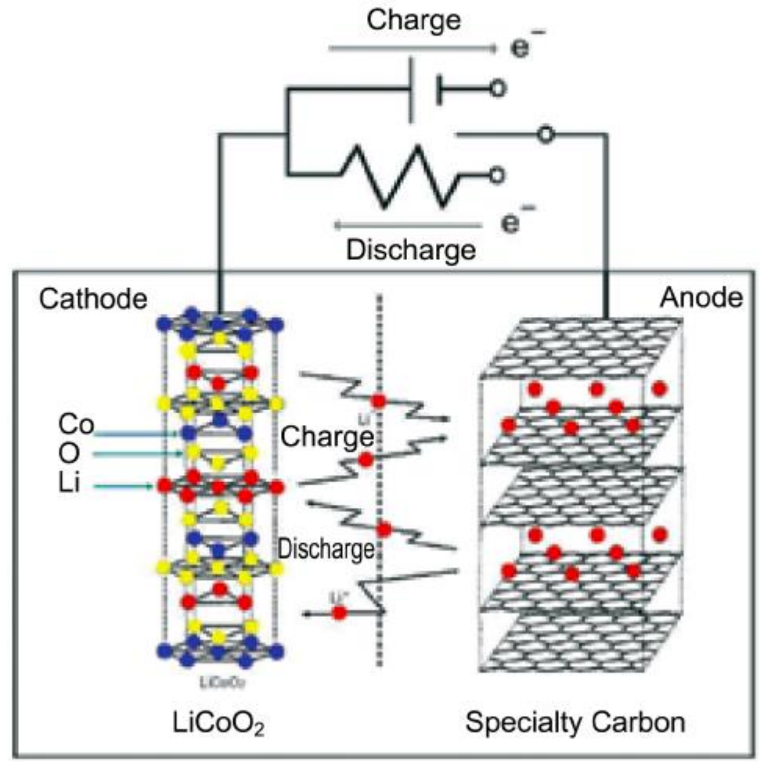


$La_{0.5}Sr_{1.5}MnO_4$

(Source: website of Railway Technical Research Institute, Japan)

Energy Science





structure ←→ electrochemical properties of electrode

develop novel electrode materials.

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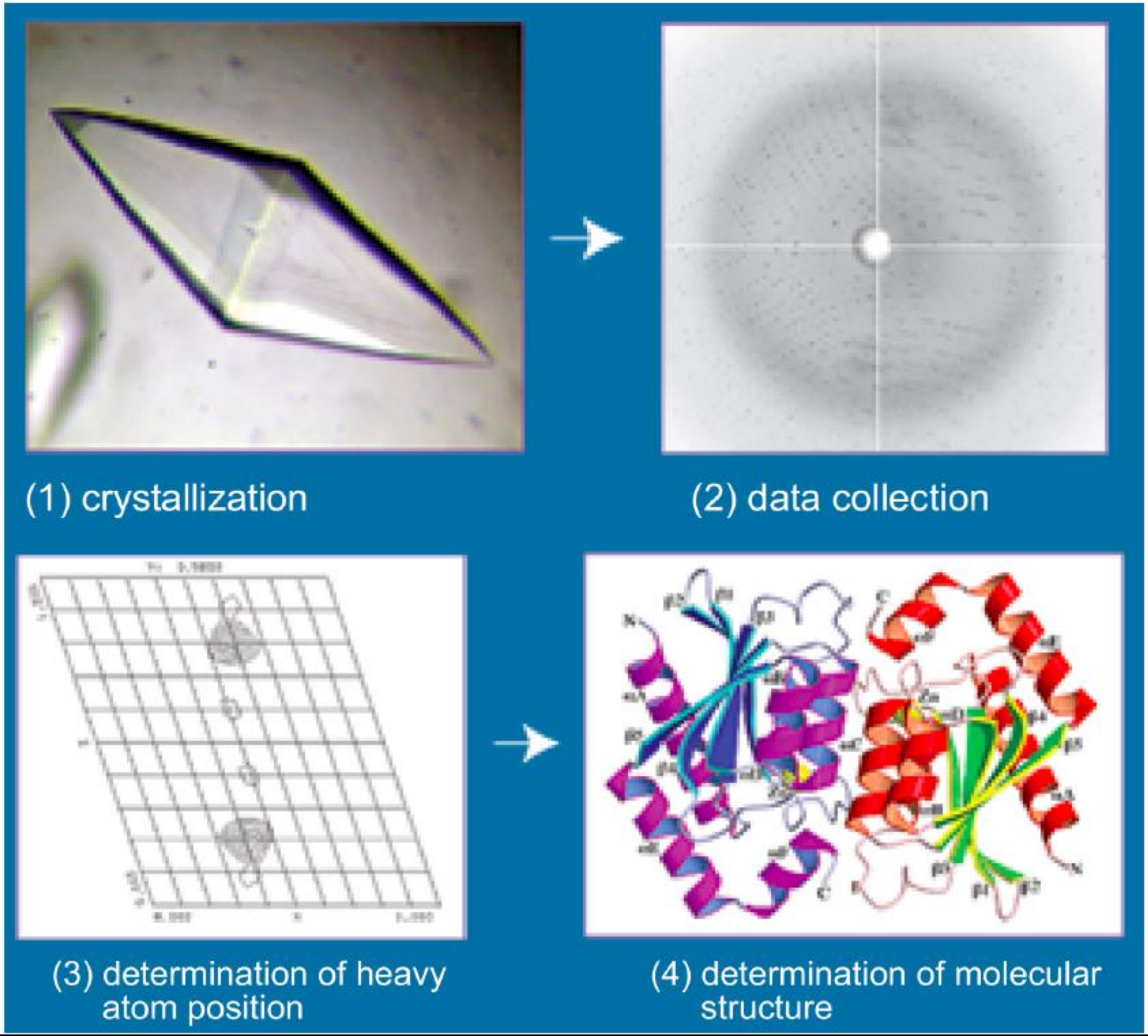
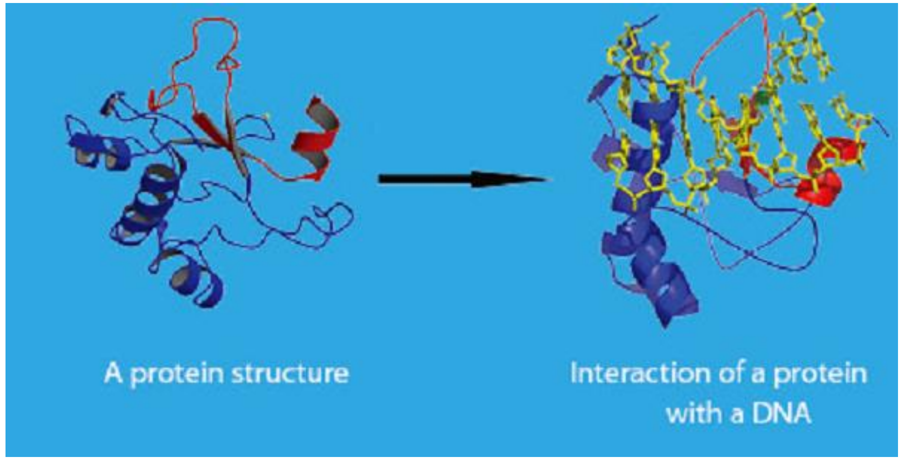
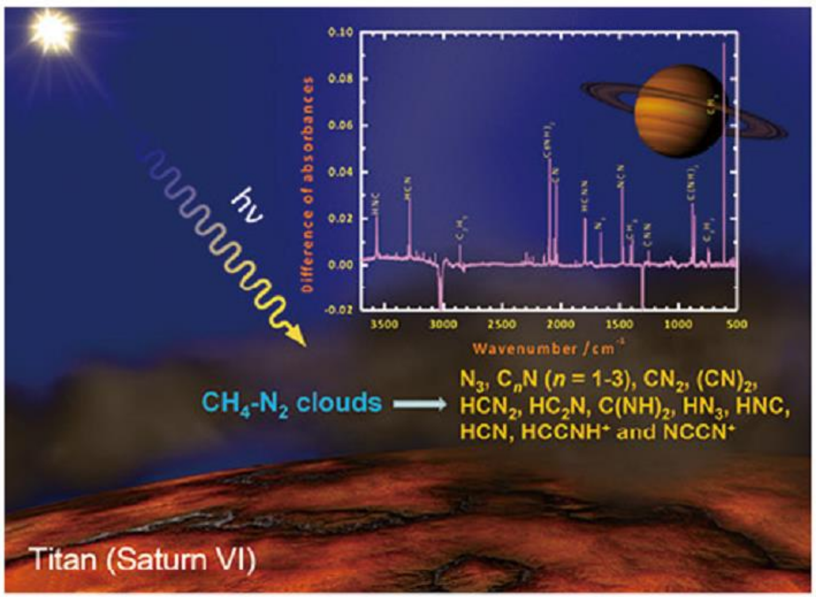
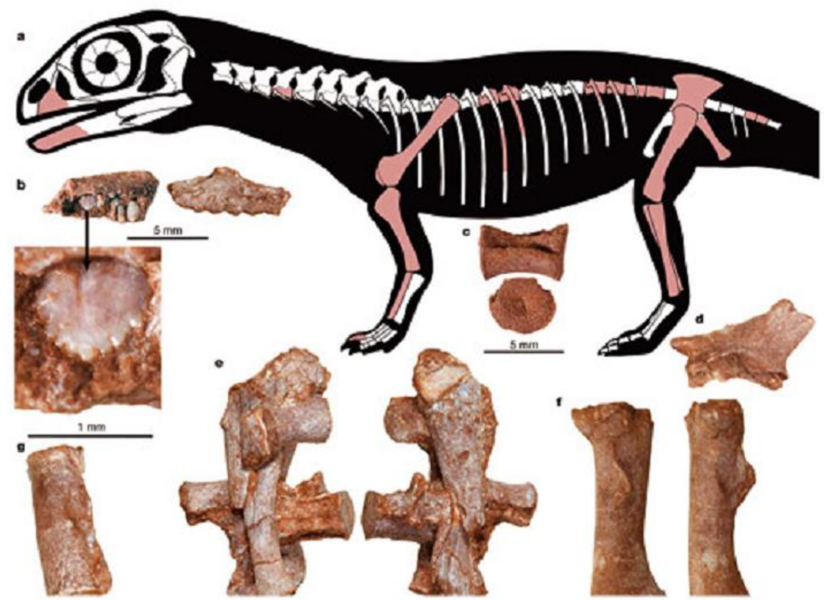
Biological structure: protein crystallography



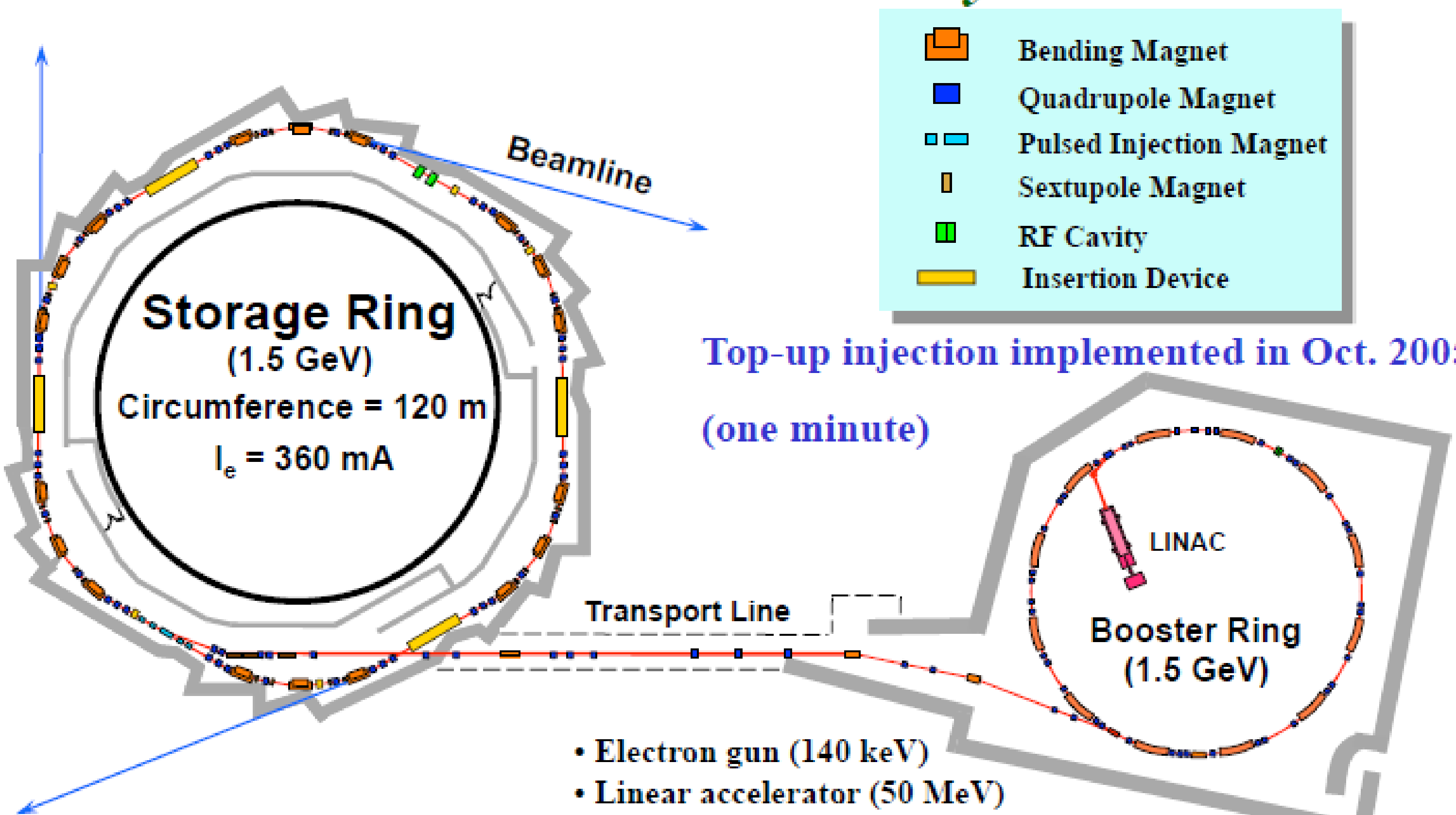

A protein structure
Interaction of a protein with a DNA


hv
Difference of absorbances
Wavenumber / cm-1
CH_4-N_2 clouds
N_3, C_nN (n = 1-3), CN_2, $(CN)_2$, HCN_2, HC_2N, $C(NH)_2$, HN_3, HNC, HCN, $HCCNH^+$ and $NCCN^+$
Titan (Saturn VI)


5 mm
1 mm
5 mm

Taiwan Light Source (TLS)

Accelerator Facility



Top-up injection implemented in Oct. 2005

(one minute)

- Electron gun (140 keV)
- Linear accelerator (50 MeV)
- Booster ring (50 MeV ~ 1.5 GeV)

TLS Experimental Hall

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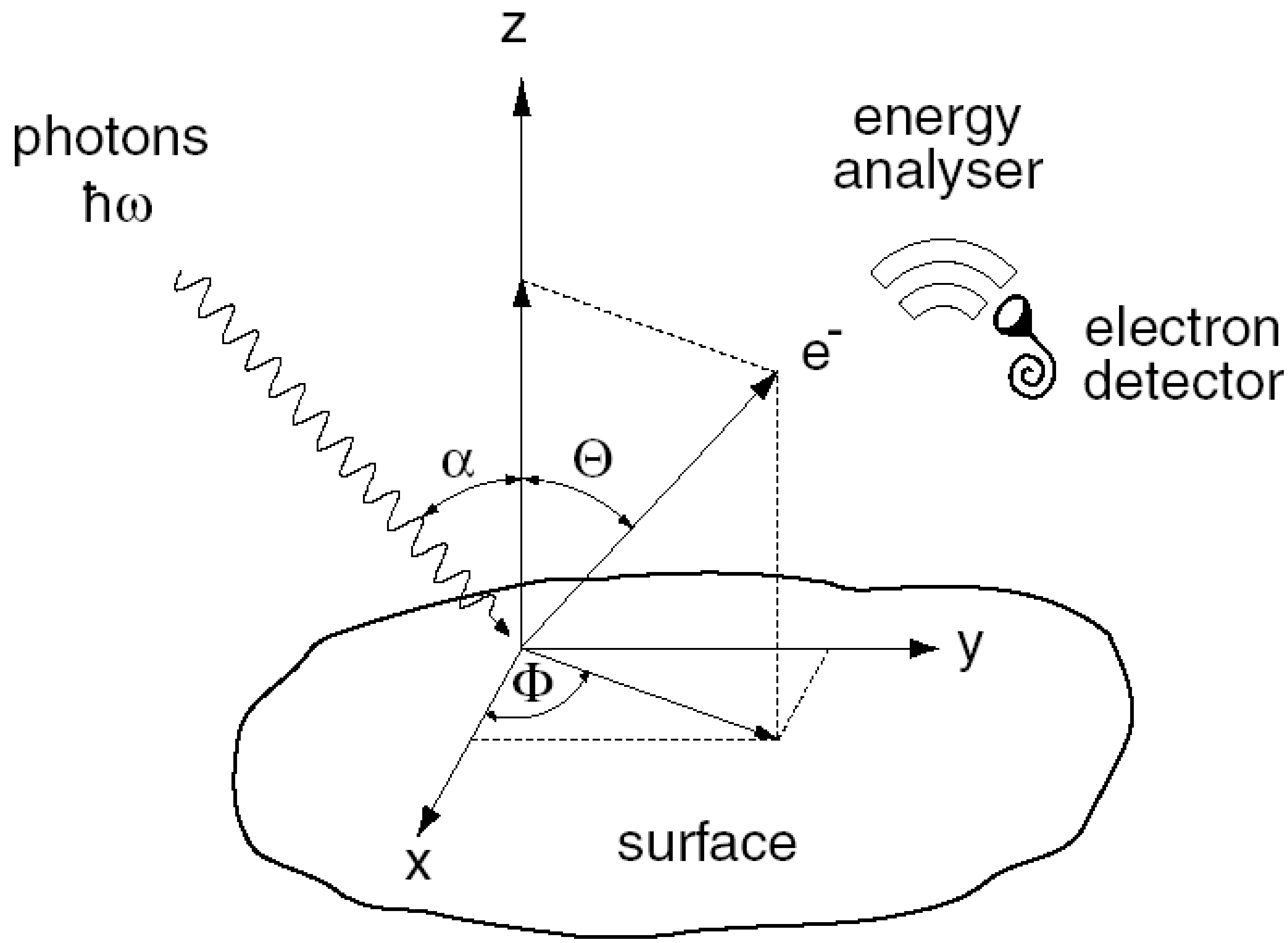
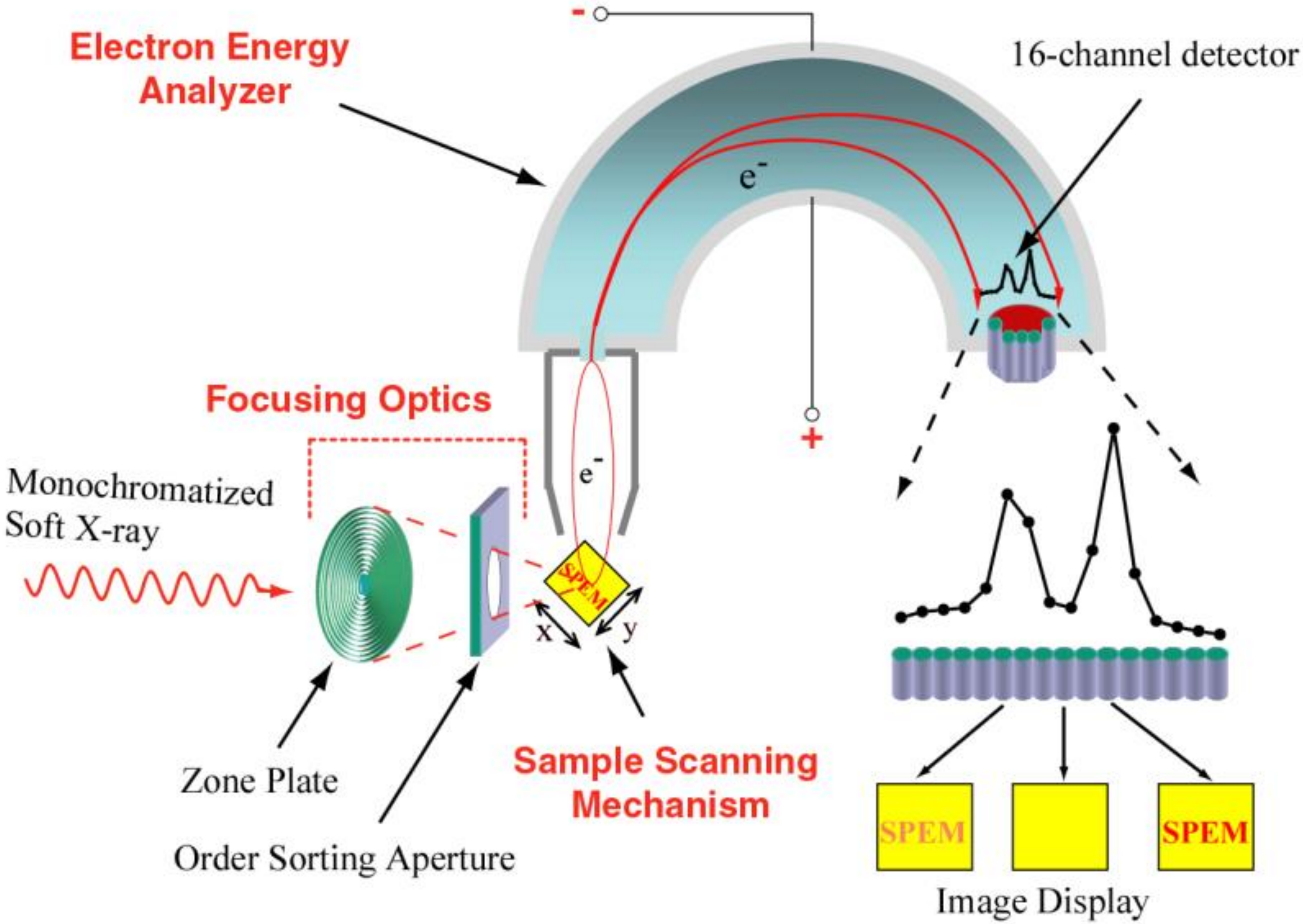
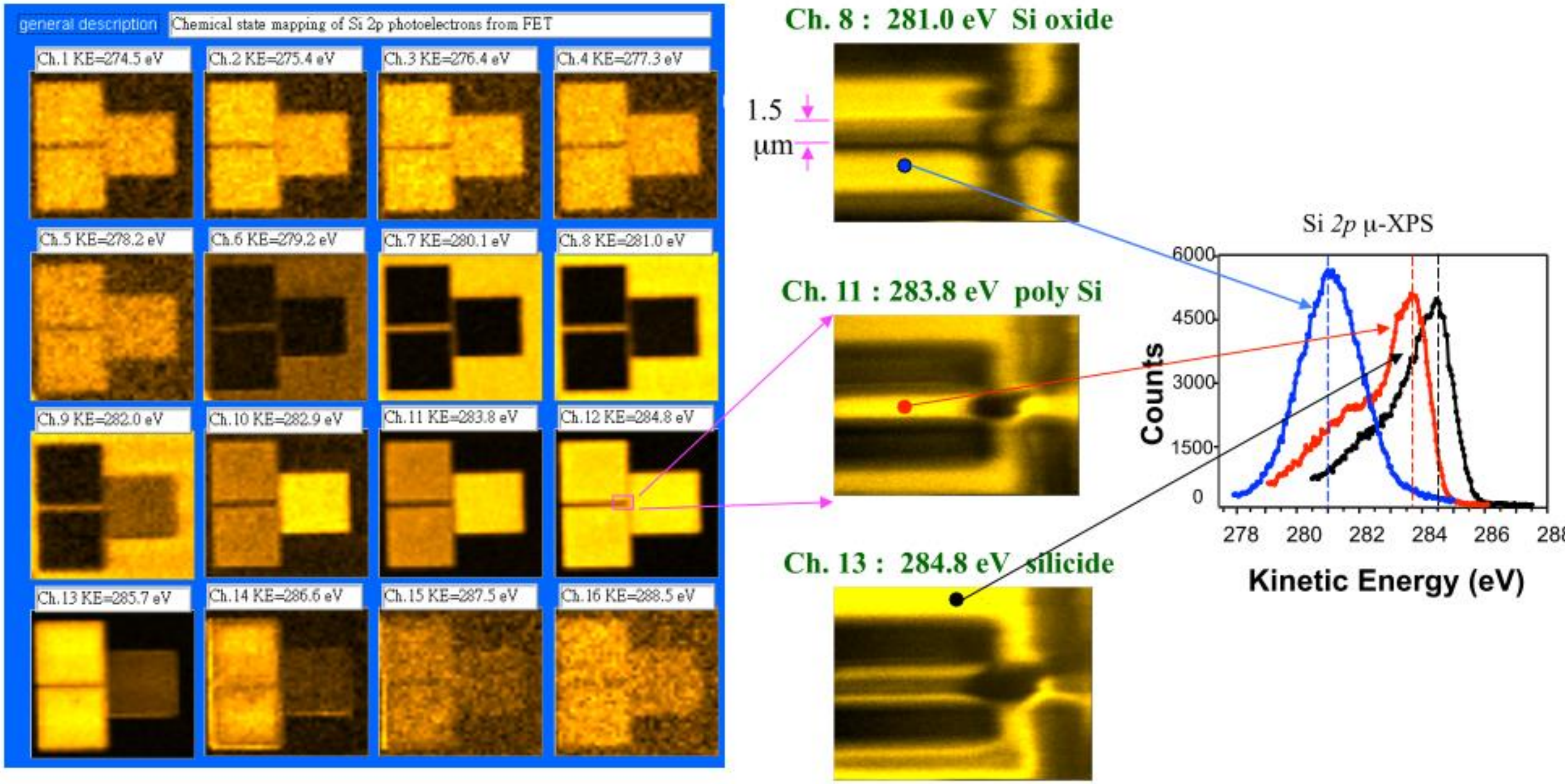
光電子能譜術（Photoemission Spectroscopy）




Electron Energy Analyzer
16-channel detector
e⁻
-
+
Focusing Optics
Monochromatized Soft X-ray
e⁻
SPEM
x
y
Zone Plate
Order Sorting Aperture
Sample Scanning Mechanism
SPEM
SPEM
Image Display

Parallel Imaging for Chemical State Mapping (PICSM)



MOSFET 240 µm × 240 µm

12 µm × 12 µm, 0.1 µm/pixel

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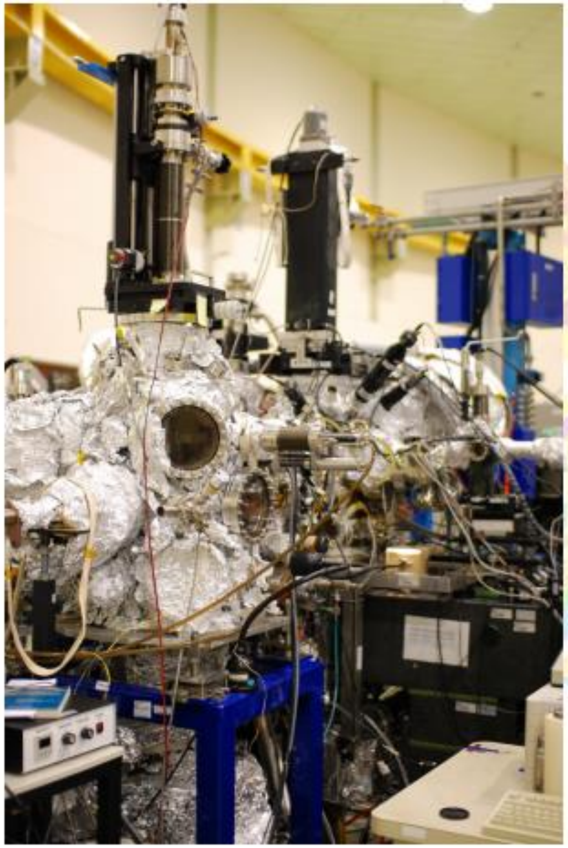
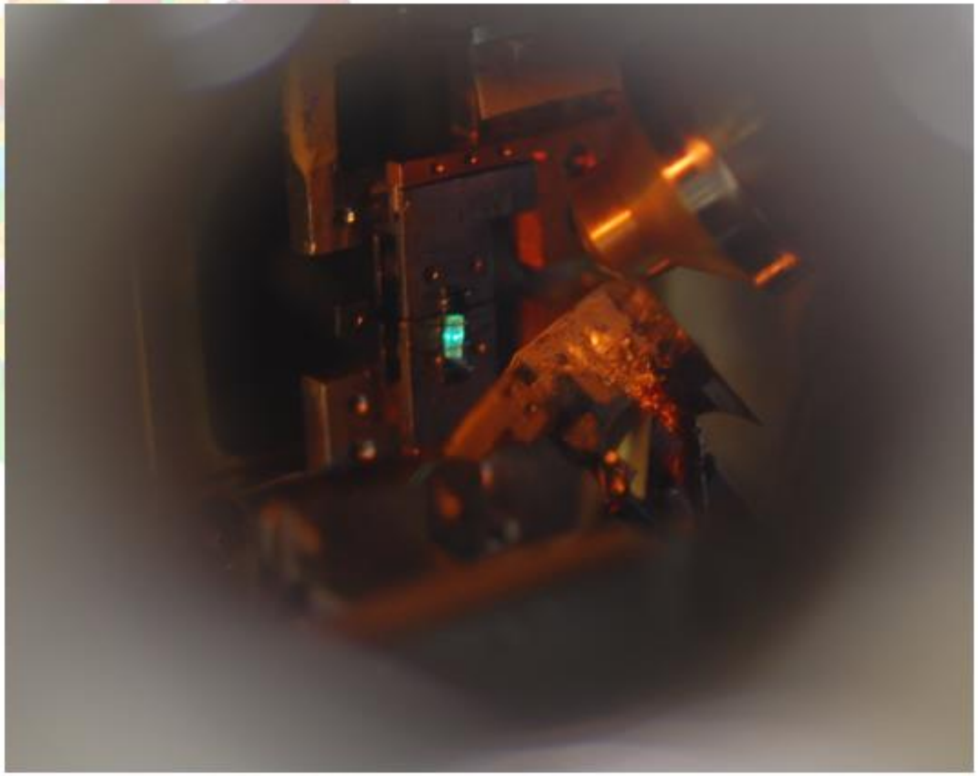
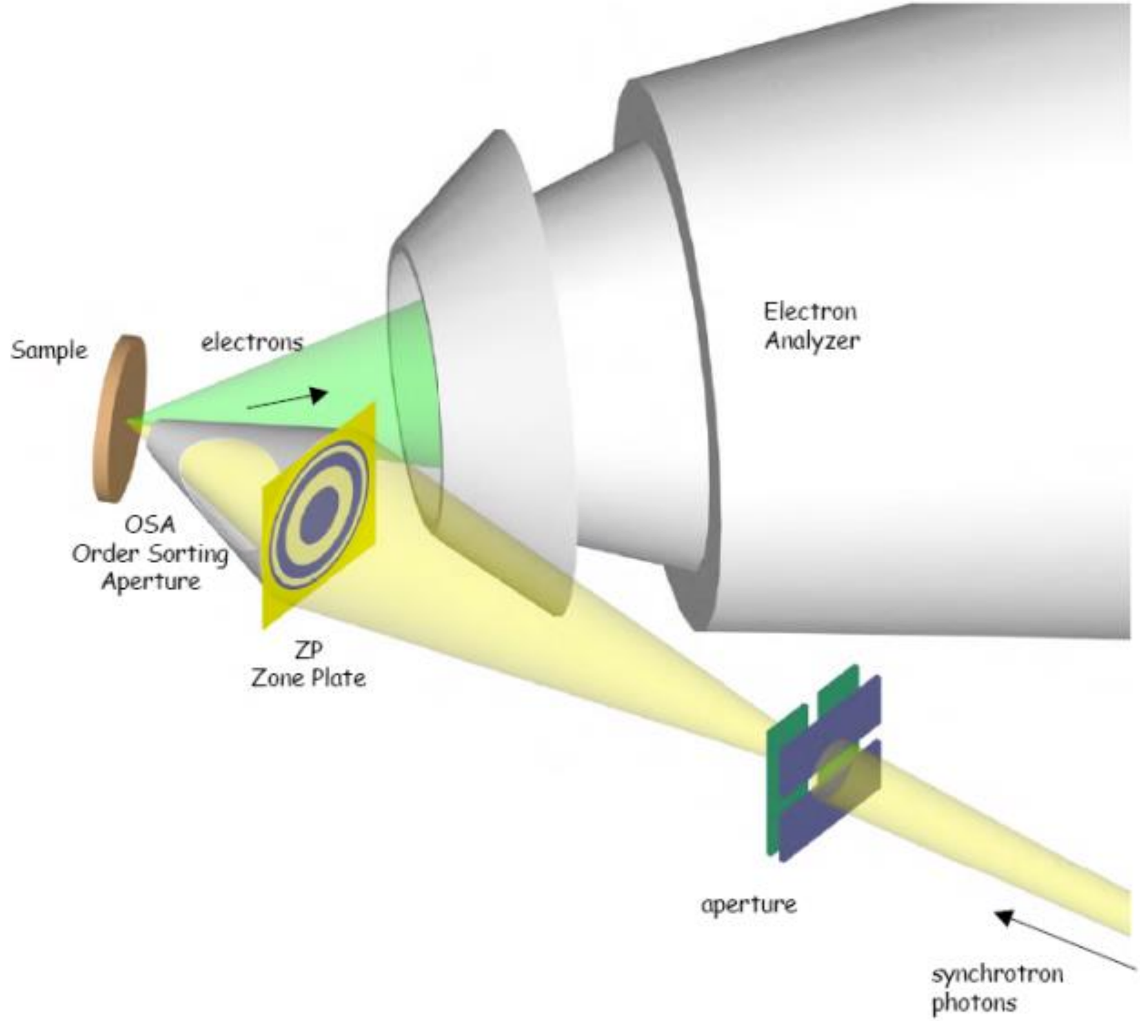
SPEM 實驗站

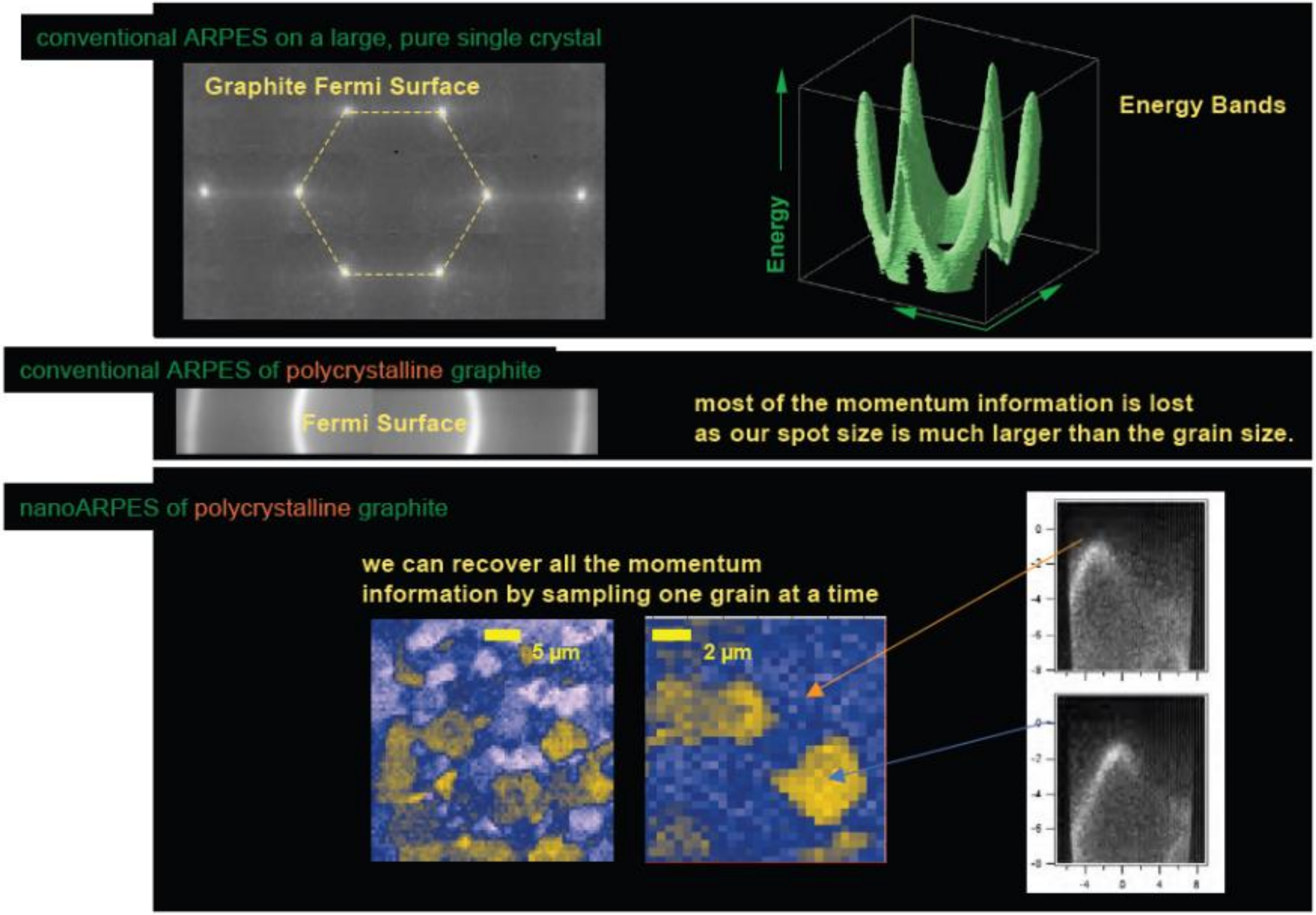


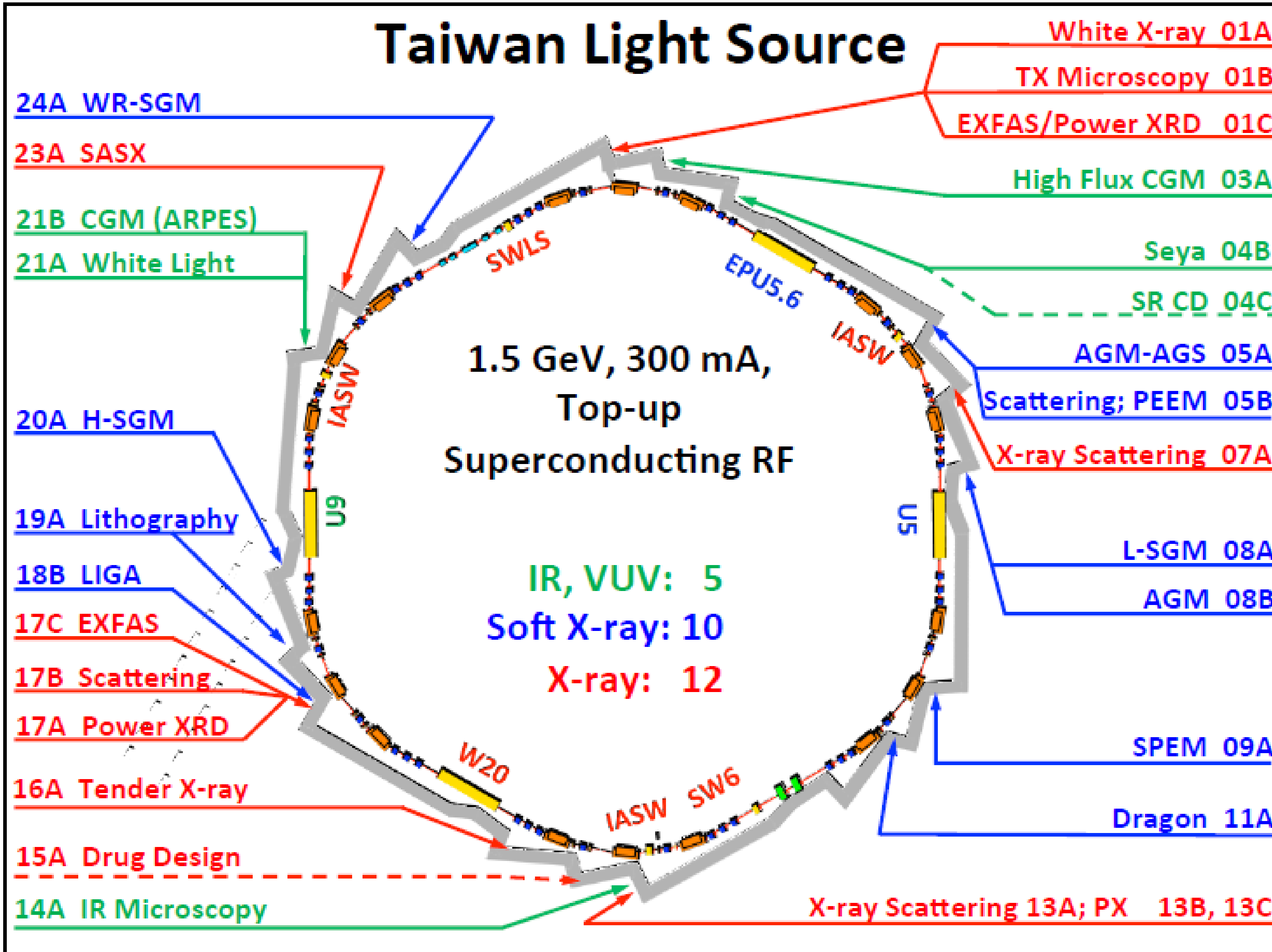


新型態同步輻射顯微術簡介

Spatially resolved ARPES




conventional ARPES on a large, pure single crystal
Graphite Fermi Surface
Energy
Energy Bands
conventional ARPES of polycrystalline graphite
Fermi Surface
most of the momentum information is lost
as our spot size is much larger than the grain size.
nanoARPES of polycrystalline graphite
we can recover all the momentum
information by sampling one grain at a time
5 µm
2 µm



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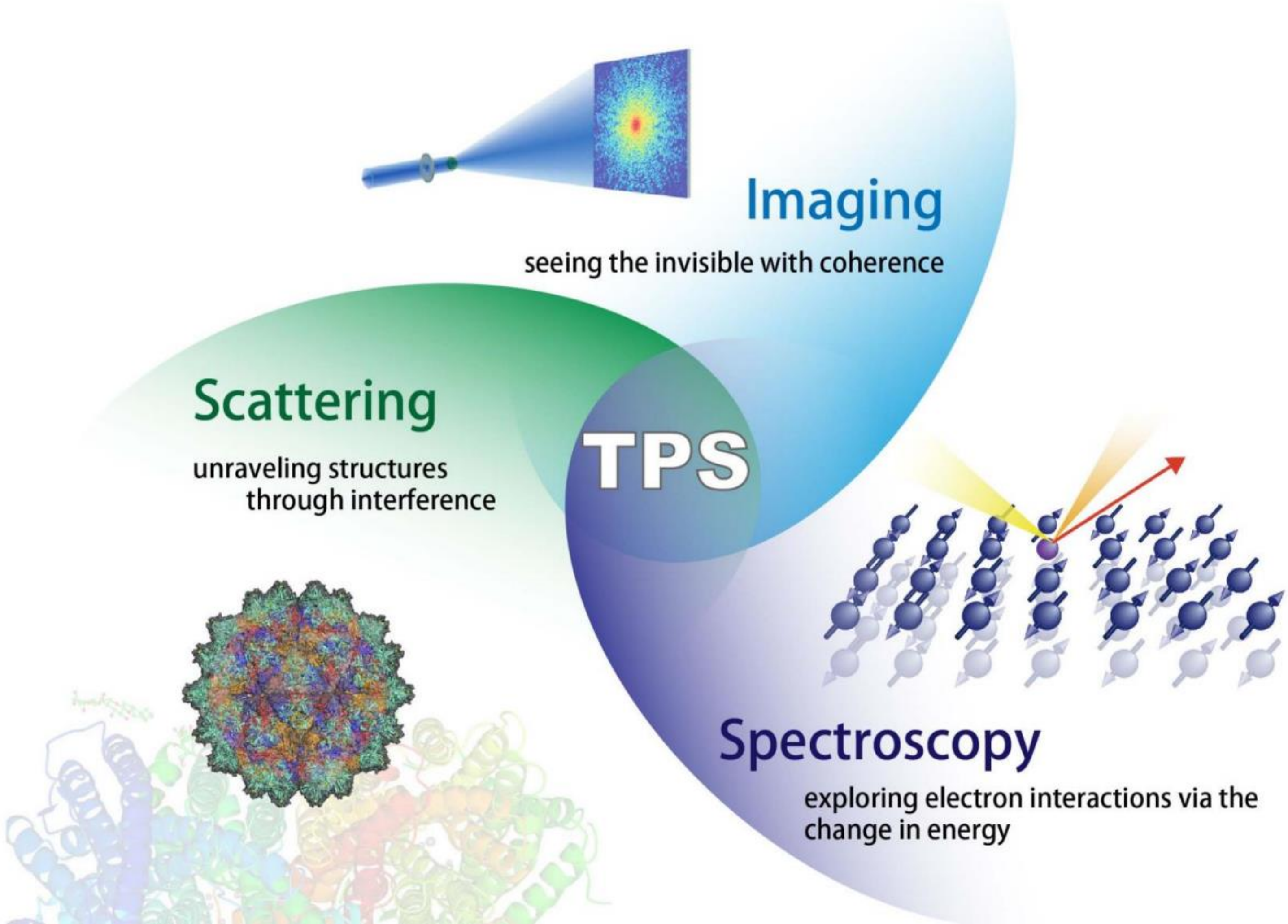
NSRRC is constructing a low-emittance synchrotron-based light source, Taiwan Photon Source (TPS)

TPS provides opportunities for scientists to reveal electrons, spins, and lattices, covering a wide range of applications.

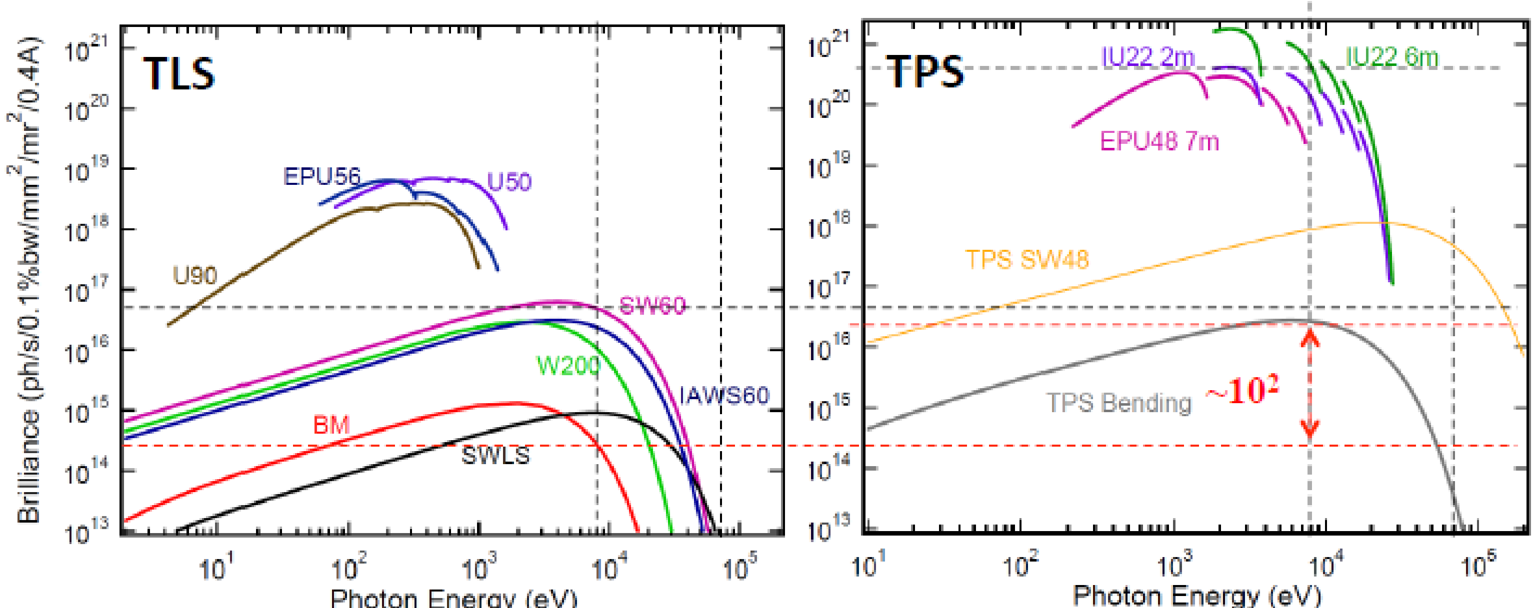


Comparison of Brilliance between TLS and TPS

The X-ray spectrum (photon energy 8 keV - 70 keV):

the brightness of bending magnet >10^2.

the brightness of IDs: 4～6 orders of mag.

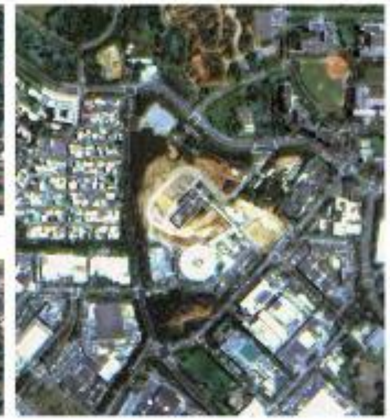


中心現址衛星圖
(太空中心提供)

Groundbreaking
2010-02-07

2010-02-10

2010-05-21



2010-08-04

2011-02-05

2011-09-27

2012-05-14

2013-01-16

Civil Construction of TPS

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Taiwan Photon Source (TPS)

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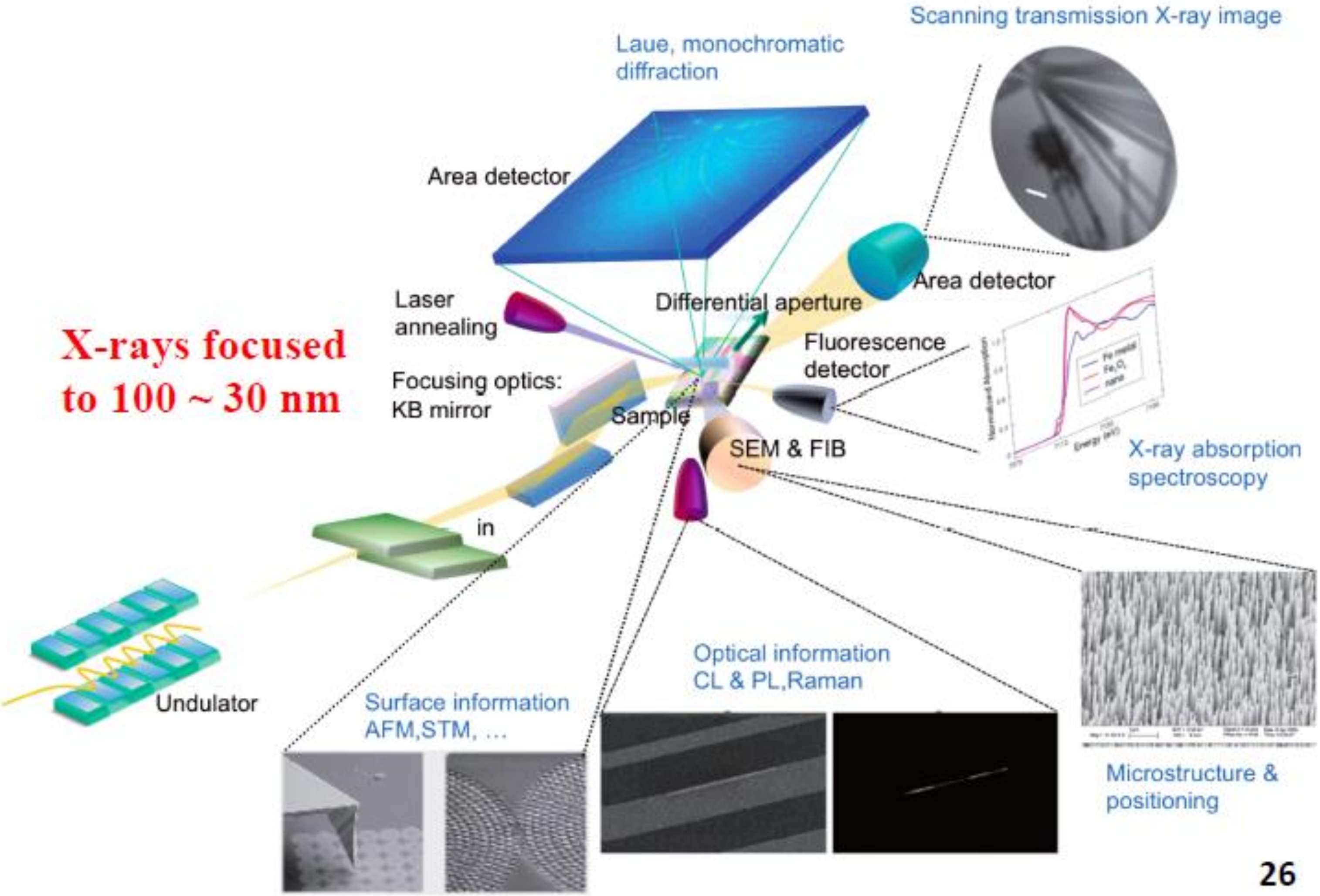
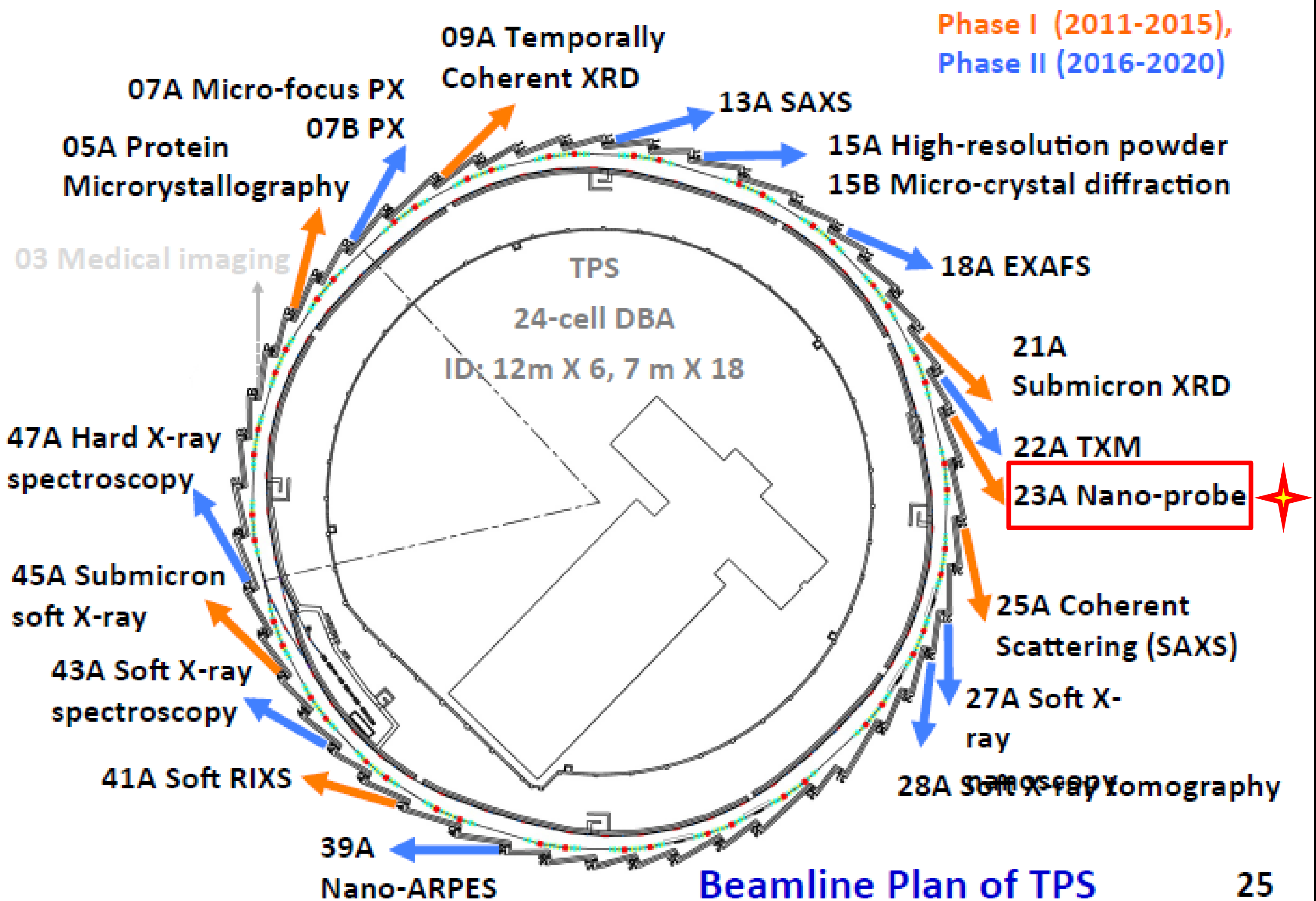
TPS will brighten the future of scientific discovery.

X-rays focused to 100 ~ 30 nm



The user operation of the TPS will begin in 2015.



Beamline Plan of TPS

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2015年是台灣光子源值得紀念的一年

The first synchrotron light from TPS (December 31, 2014)

104年第一季:
儲存電流達到100毫安培
(室溫RF共振腔 (Petra))

↓

104年第二季及第三季:
安裝2台超導RF共振腔
(KEKB) & 10台插件磁鐵

↓

104年第四季:
TPS & 第一期7條光束線
試車

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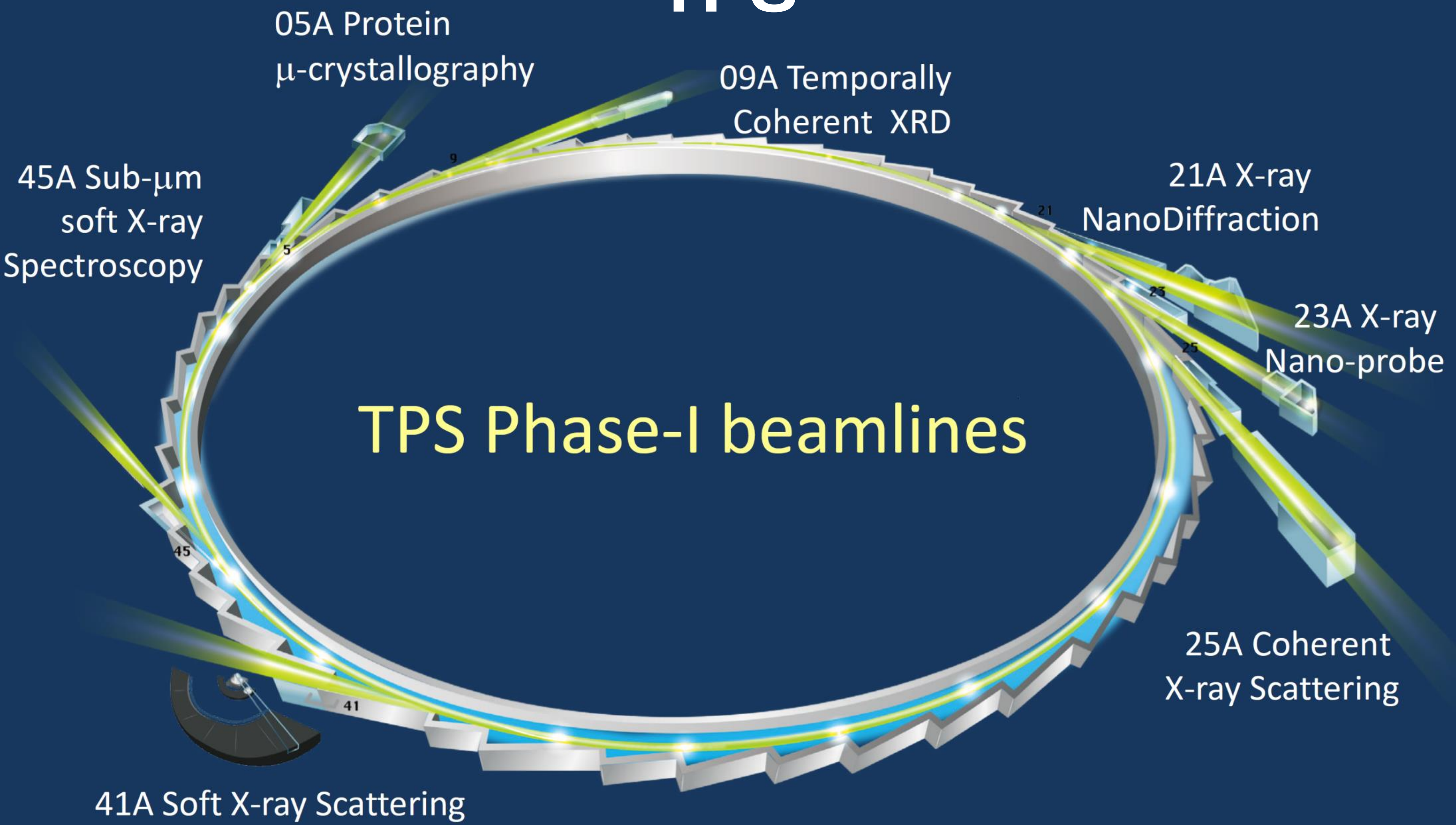
Outline

- Synchrotron Light Source
- Application of Synchrotron Light
- X-ray nano probe at TPS

Nanoprobe project is in the first phase at TPS



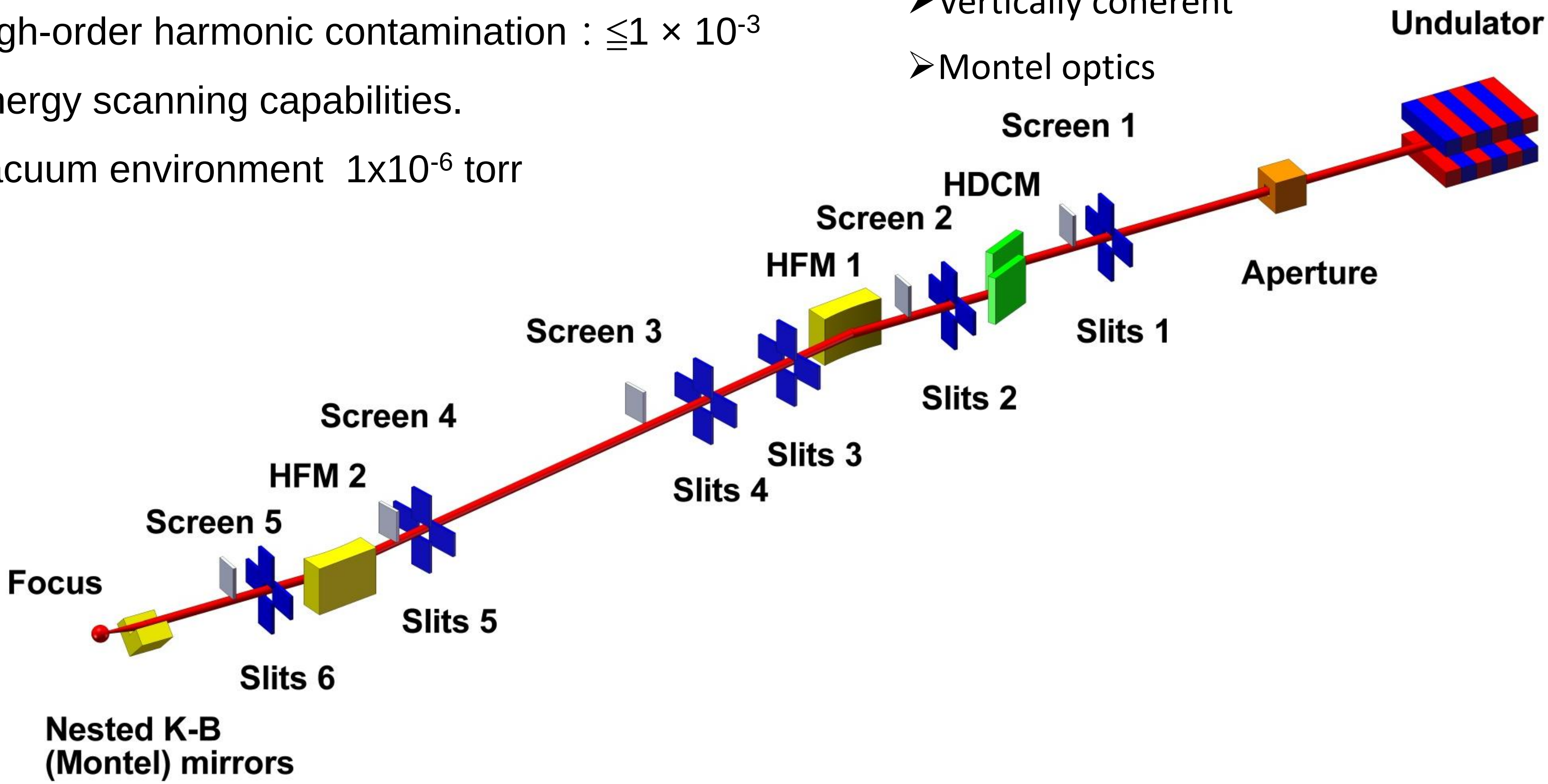
Optical Layout

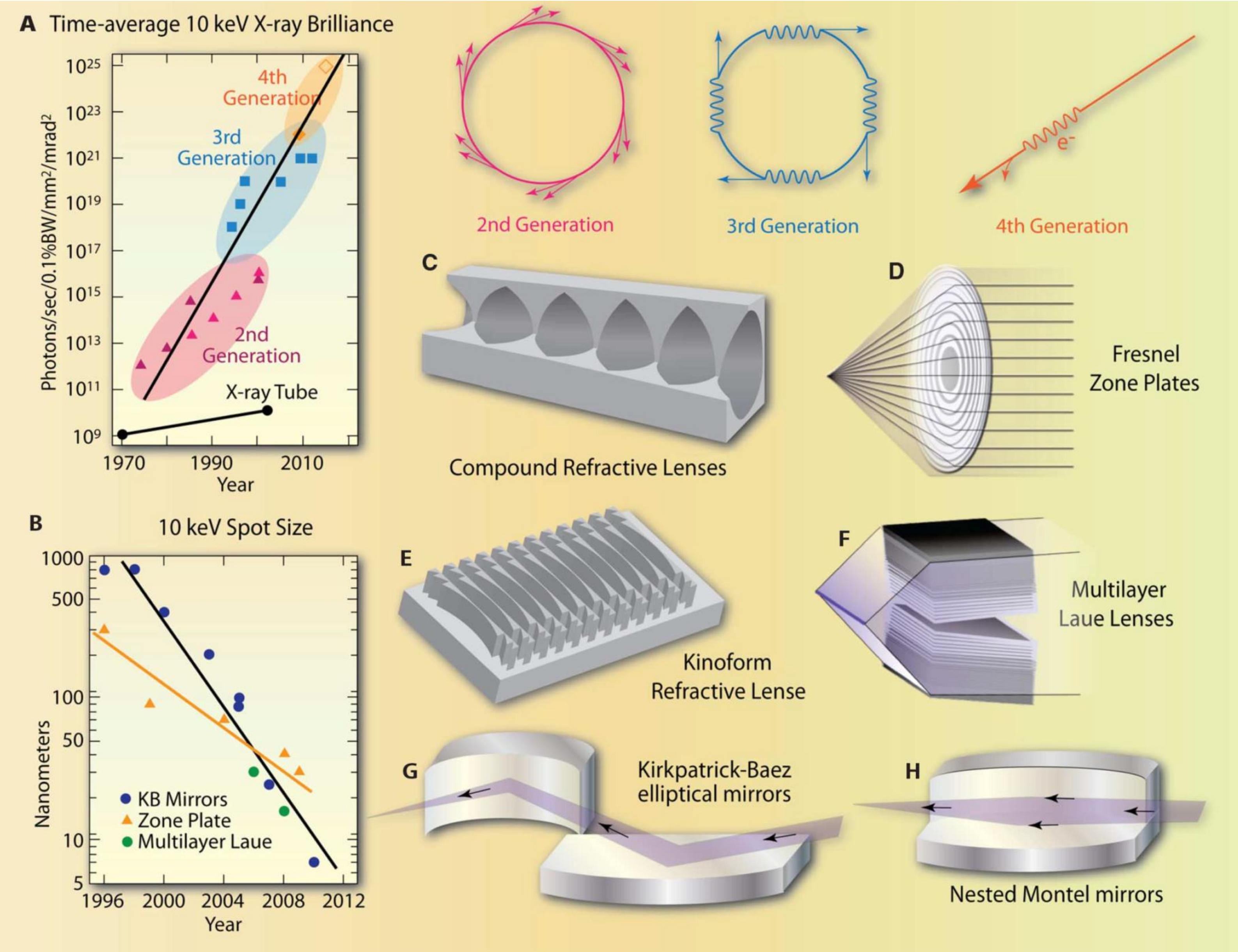
Expected Beamline performance

- Energy range : 4 - 15 kev
- Photon flux : 10^{10} ~ 10^{11} photons/sec
- Energy resolution : < 2×10^{-4} with Si(111) crystals
- Beam size : ~ 40 nm at 10 keV (H × V, FWHM)
- High-order harmonic contamination : $\leqq 1 \times 10^{-3}$
- Energy scanning capabilities.
- Vacuum environment 1×10^{-6} torr

Features

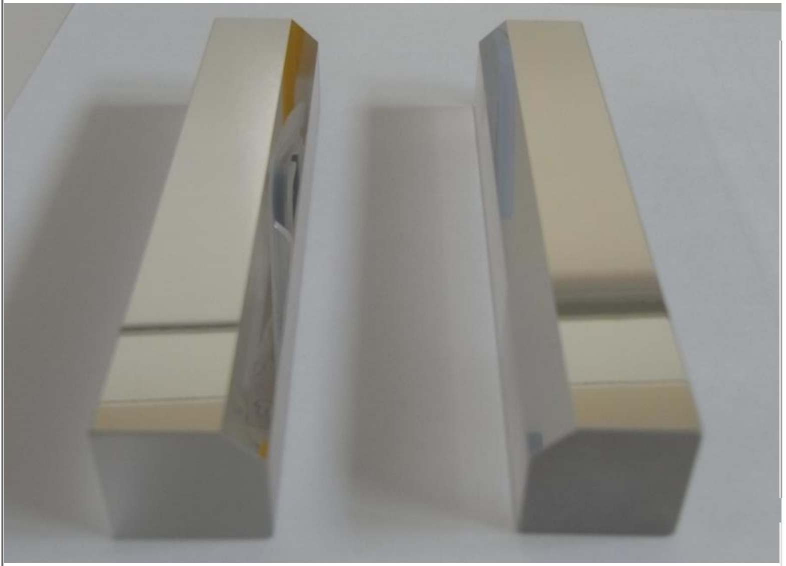
- 2-stage Horizontal focusing
- Horizontal DCM
- Short in length (<70 m)
- Windowless
- Vertically coherent
- Montel optics

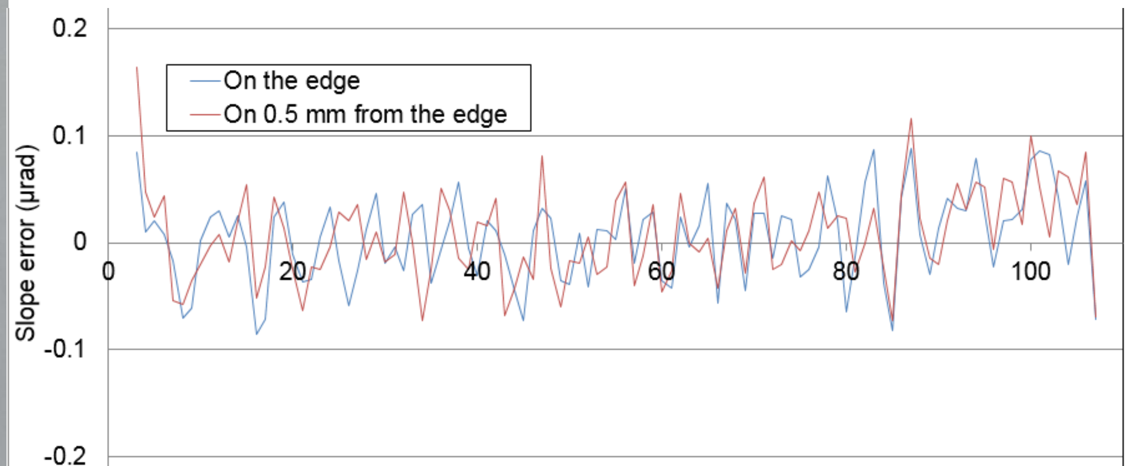


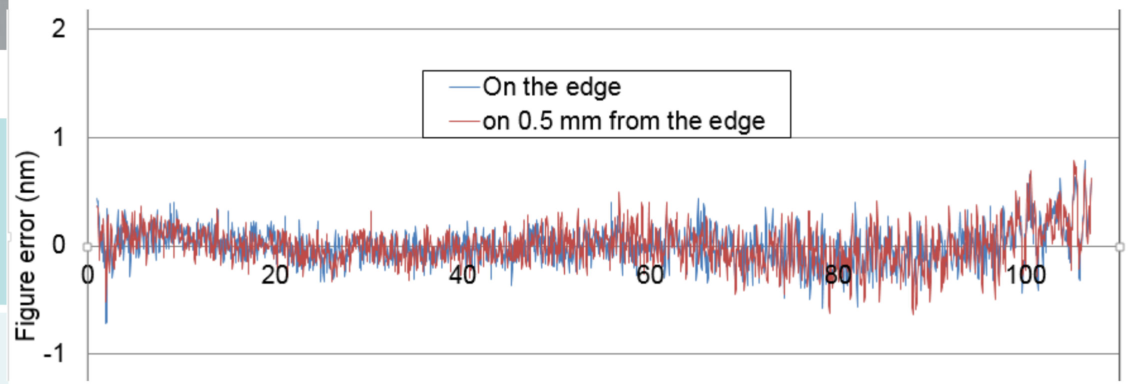


A Time-average 10 keV X-ray Brilliance
Photons/sec/0.1%BW/mm²/mrad²
4th Generation
3rd Generation
2nd Generation
X-ray Tube
1970
1990
2010
Year
2nd Generation
3rd Generation
4th Generation
e-
C
Compound Refractive Lenses
D
Fresnel Zone Plates
B
10 keV Spot Size
Nanometers
KB Mirrors
Zone Plate
Multilayer Laue
1996
2000
2004
2008
2012
Year
E
Kinoform Refractive Lense
F
Multilayer Laue Lenses
G
Kirkpatrick-Baez elliptical mirrors
H
Nested Montel mirrors

1. nano-optics: Montel mirrors







	Slope error RMS	Roughness (nm) RMS
Mirror 1	0.042 (μrad)	0.135 (nm)
Mirror 2	0.039 (μrad)	0.142 (nm)

No crack at edge is observed by Optical microscope

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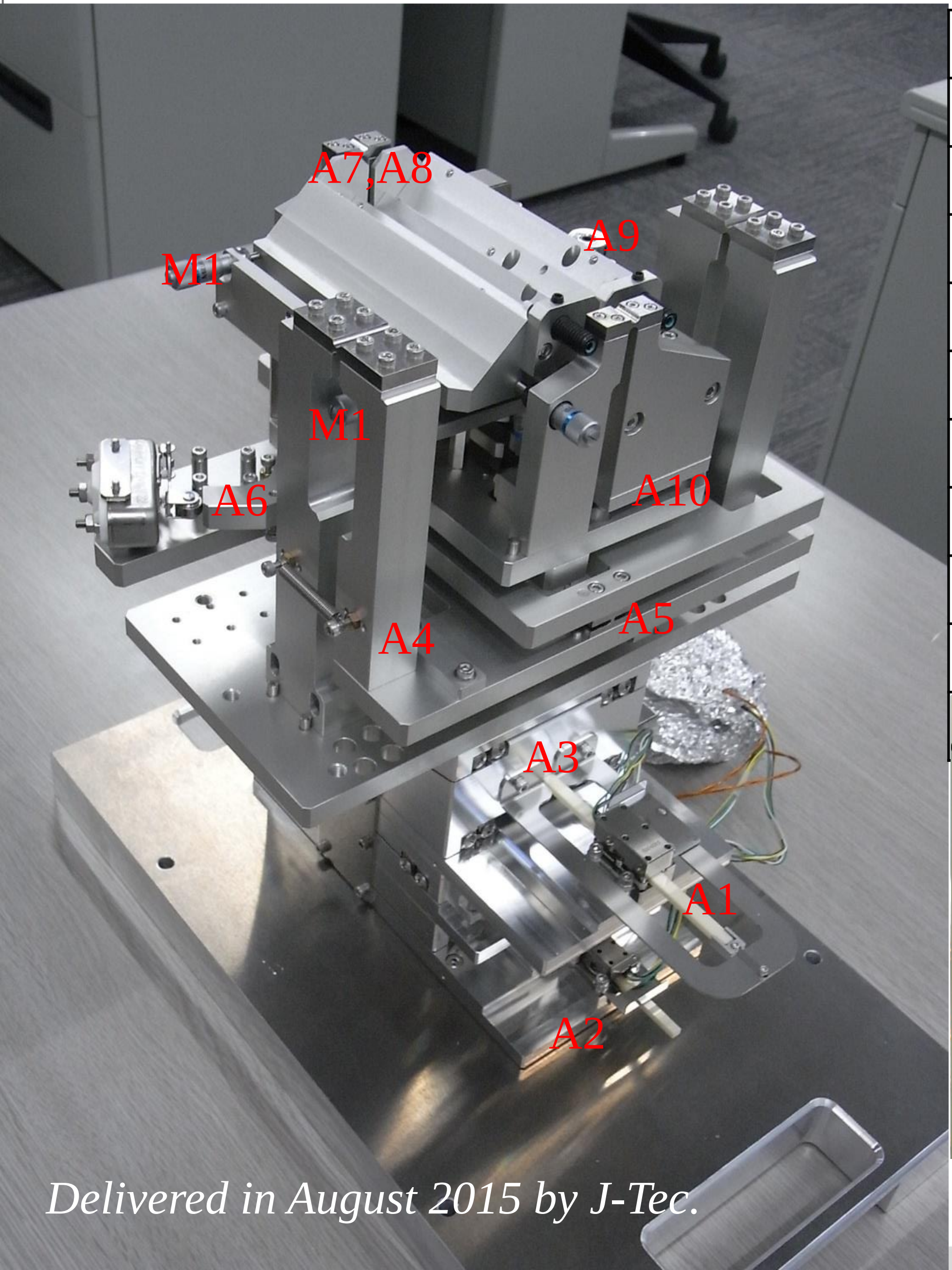
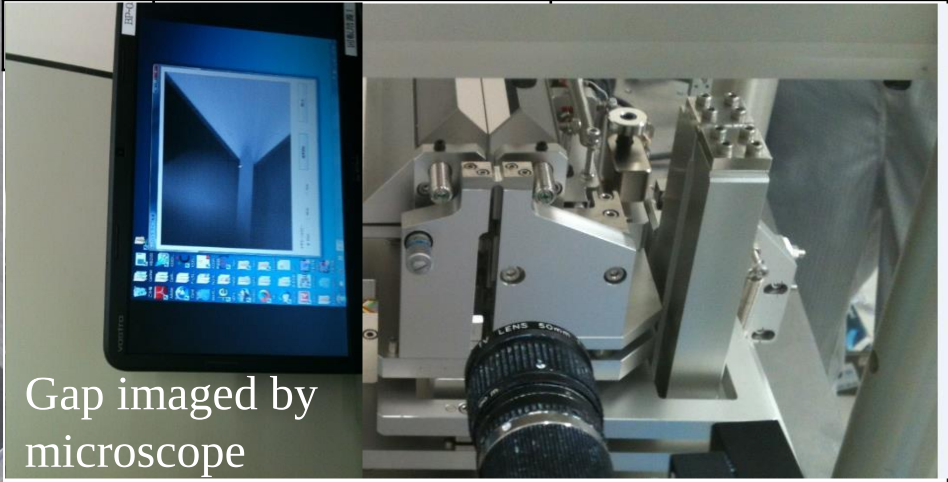
Delivered in June 2015 by J-Tec

Mirror holders



Delivered in August 2015 by J-Tec.

A1	X	Optical encoder
A2	Y	Optical encoder
A3	Z	Optical encoder
A4	Pitch	Laser interferometer
A5	Roll	Laser interferometer
A6	Yaw	Laser interferometer
A7	Top-Y	Pre-aligned
A8	Top-Z	Pre-aligned
A9	Top-Pitch (X)	Pre-aligned
A10	Top-Roll (Y)	Pre-aligned



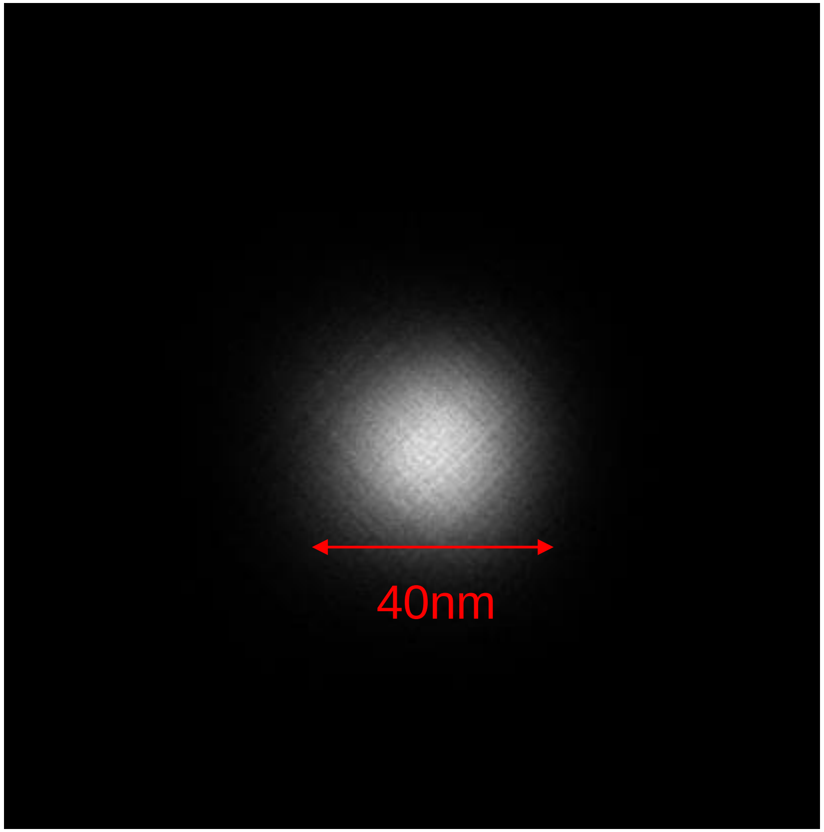
Gap imaged by microscope

Montel Mirrors in the holder

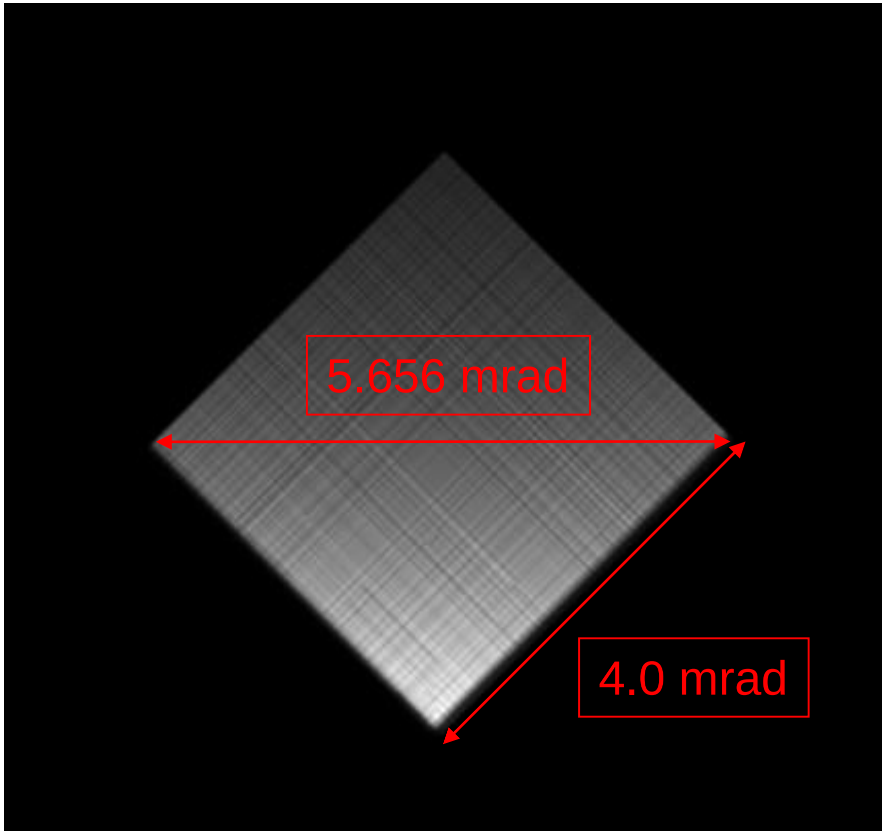
Simulation of Focus Spot

Simulation at 10 keV, average reflection=0.802, by ray tracing

Source size	12.5 μm x 12.5 μm
Source divergence	6μrad x 6μrad
FHWM	25nm x 25nm,



Simulated
Focus spot size



Simulated
Divergence

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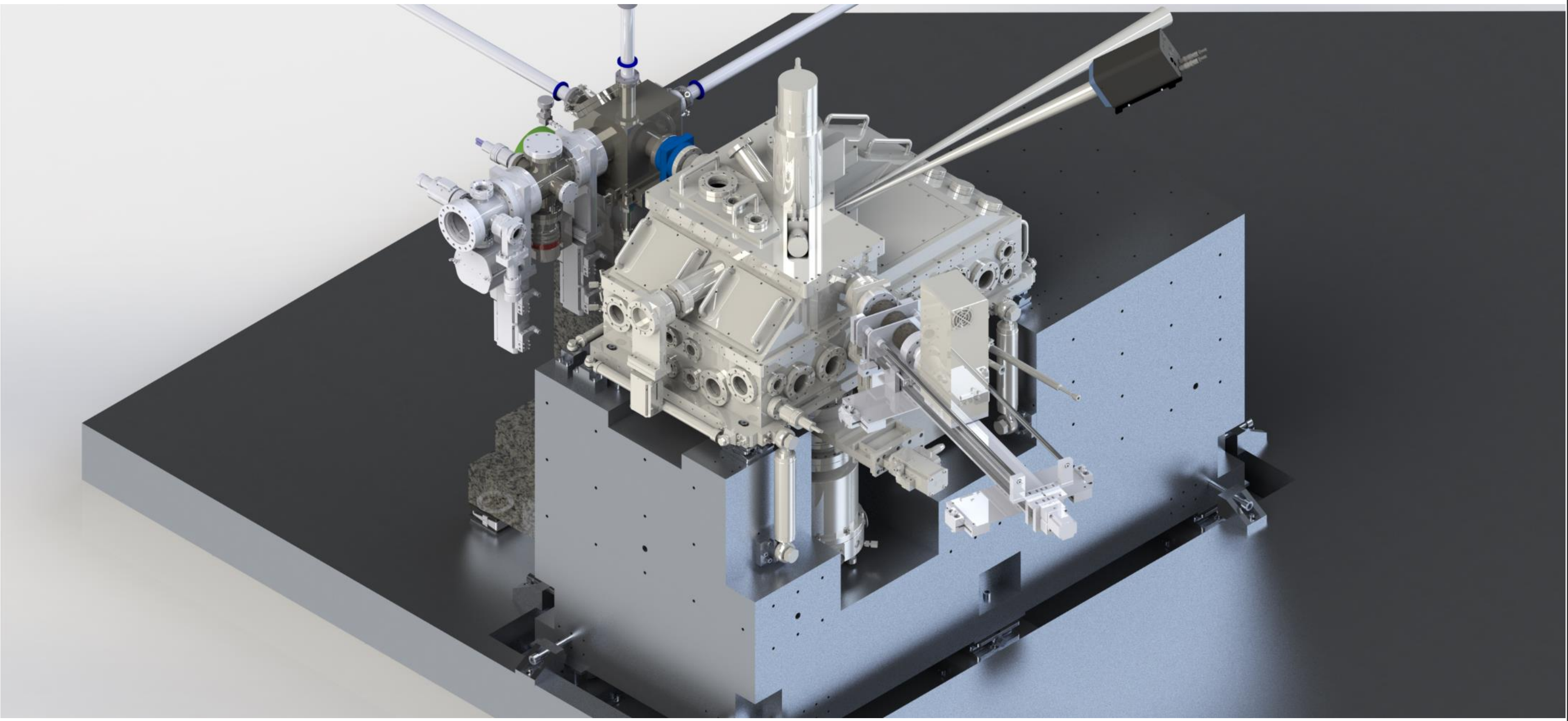
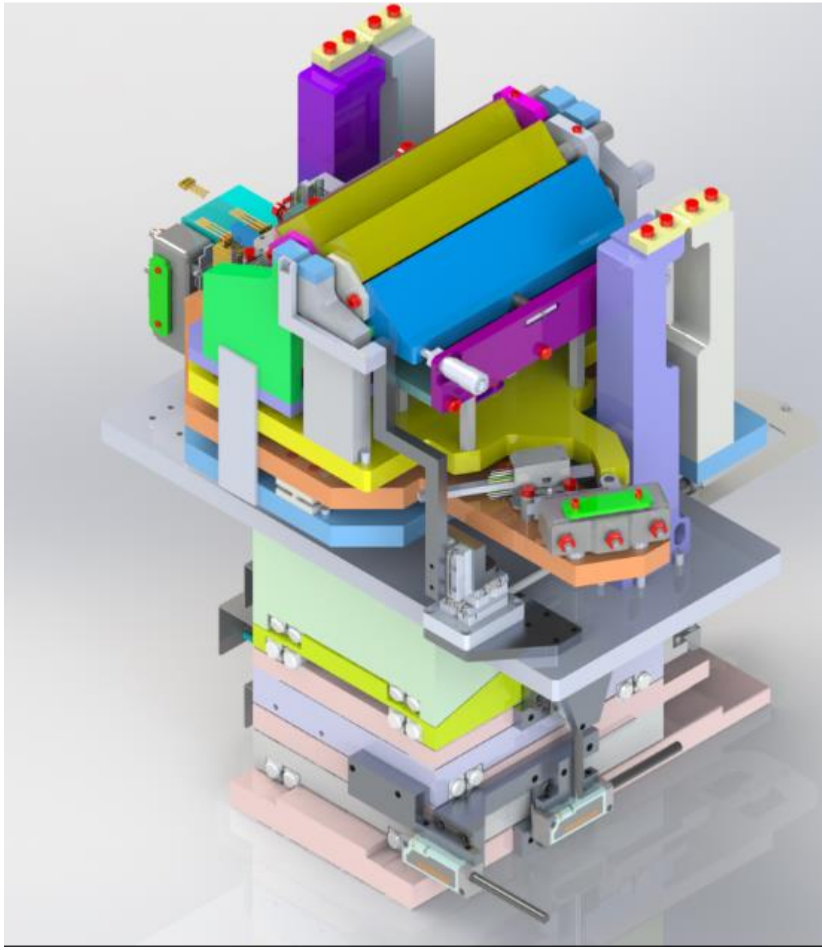
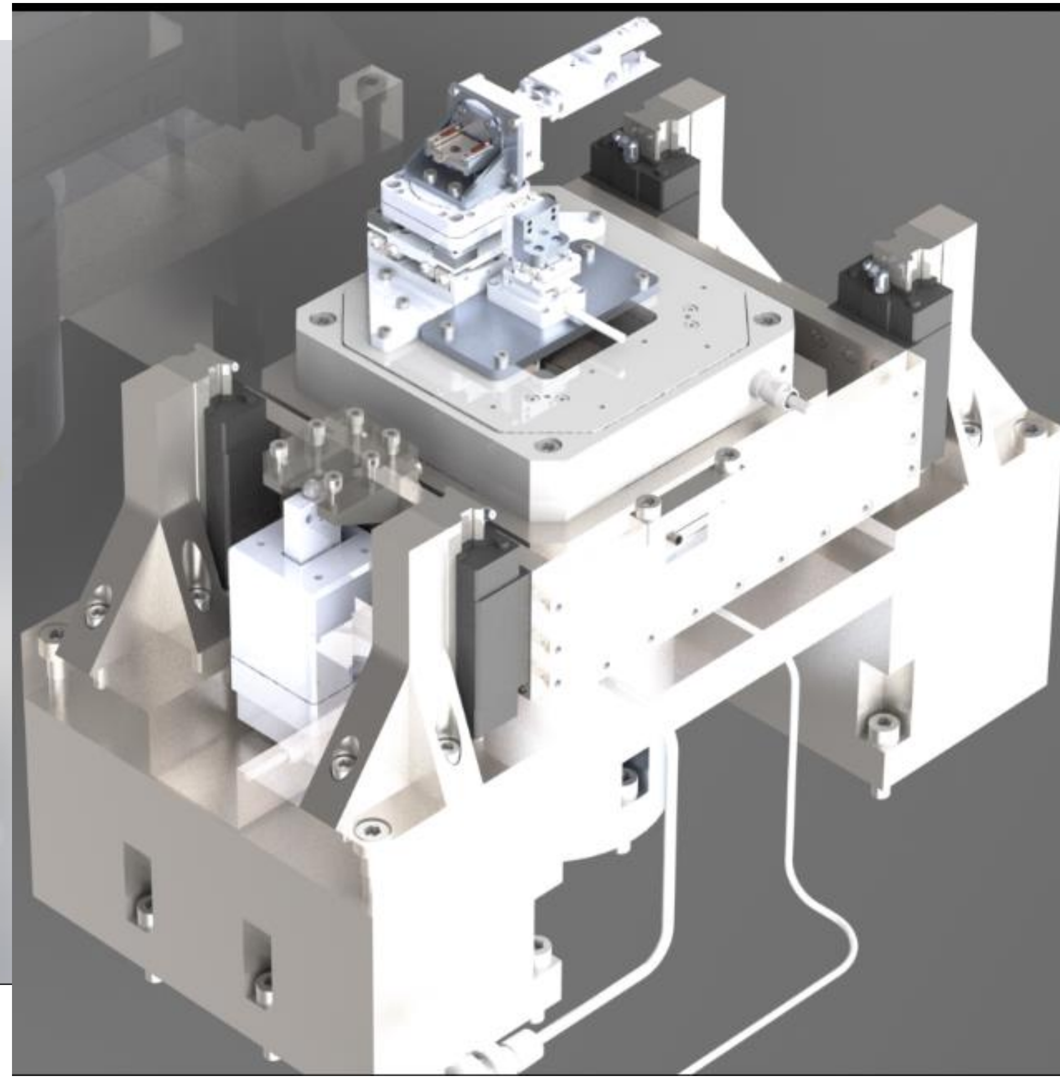
By Gung-Chian Yin

Experimental Station



Experimental Station





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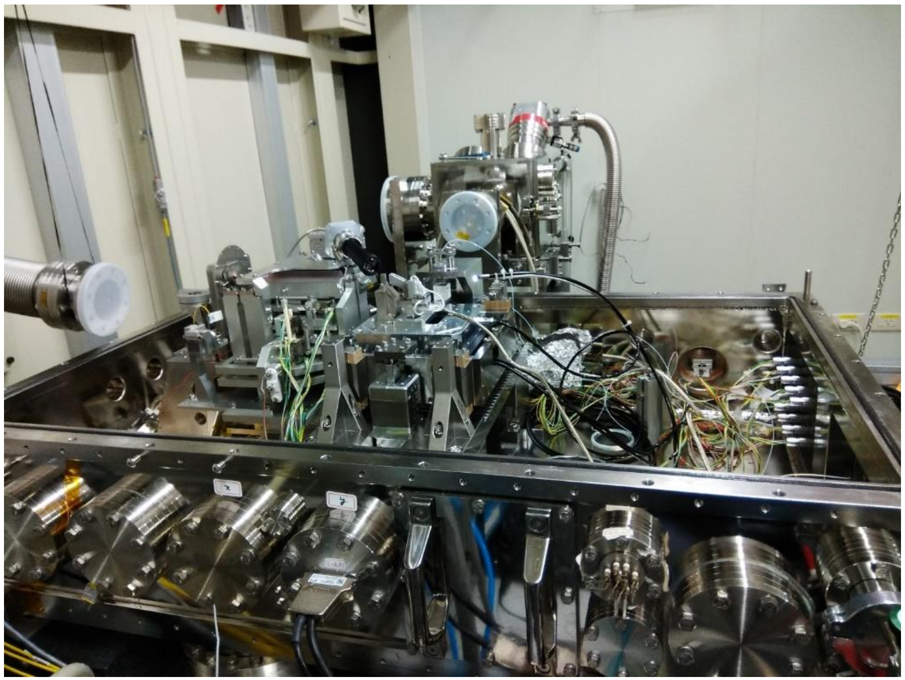

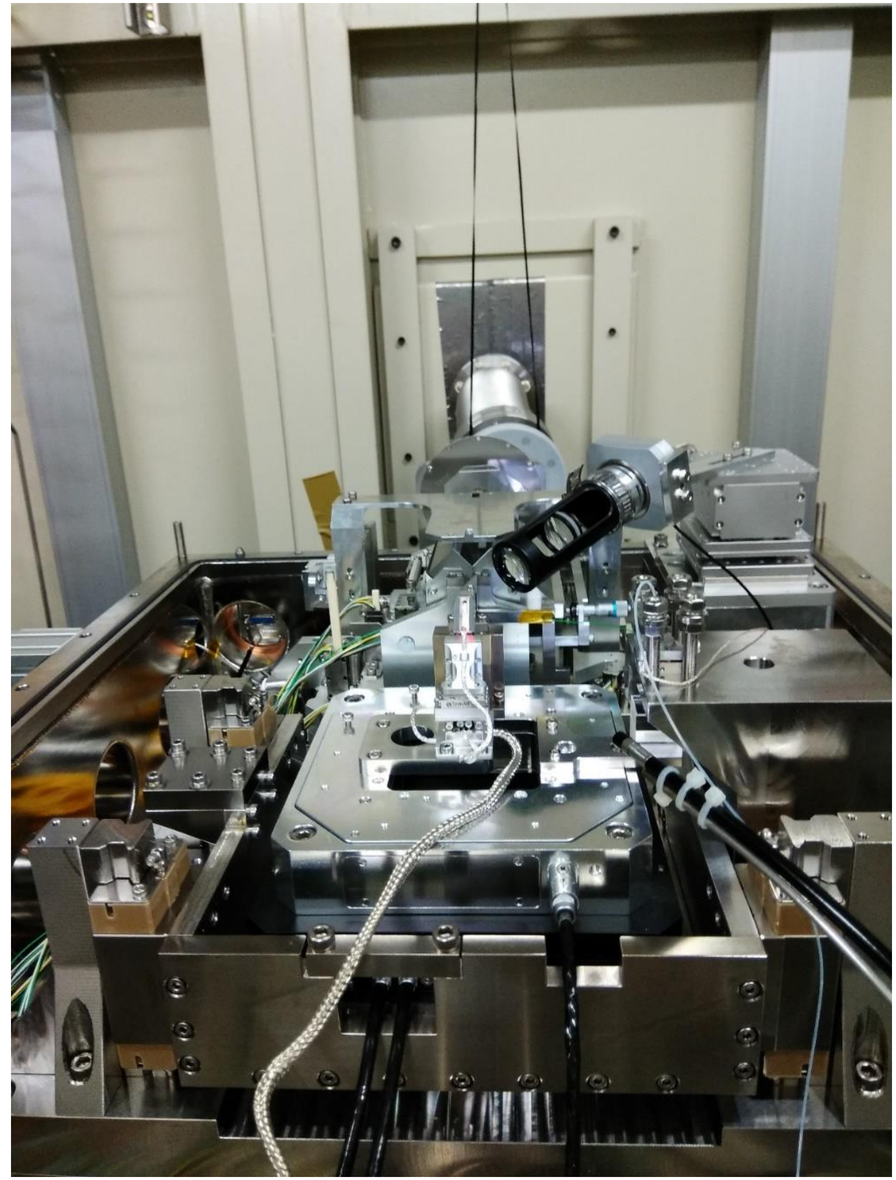

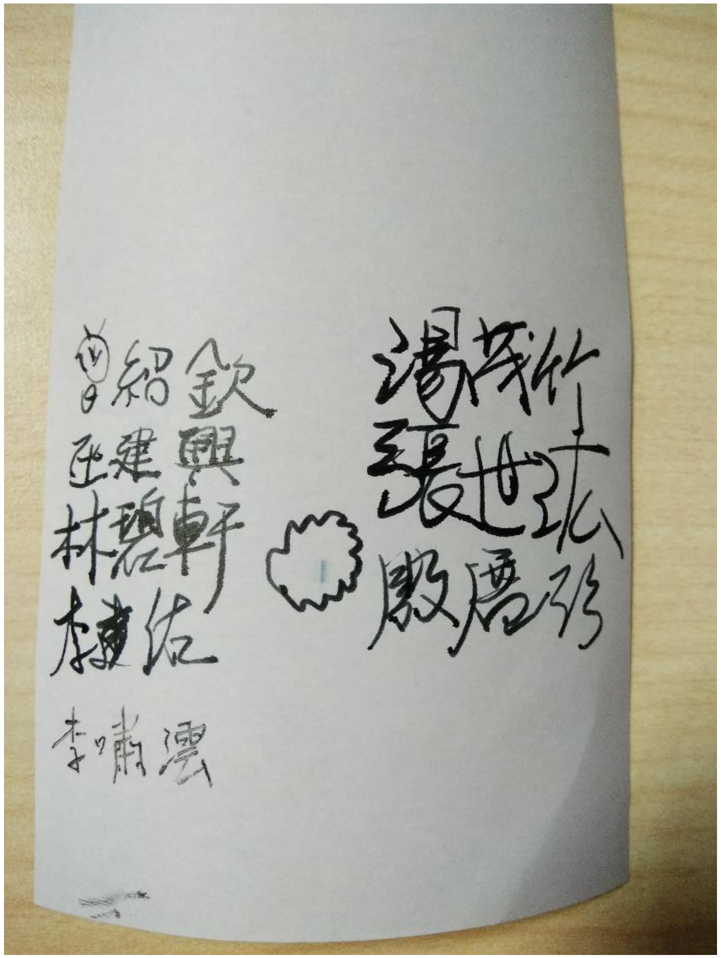

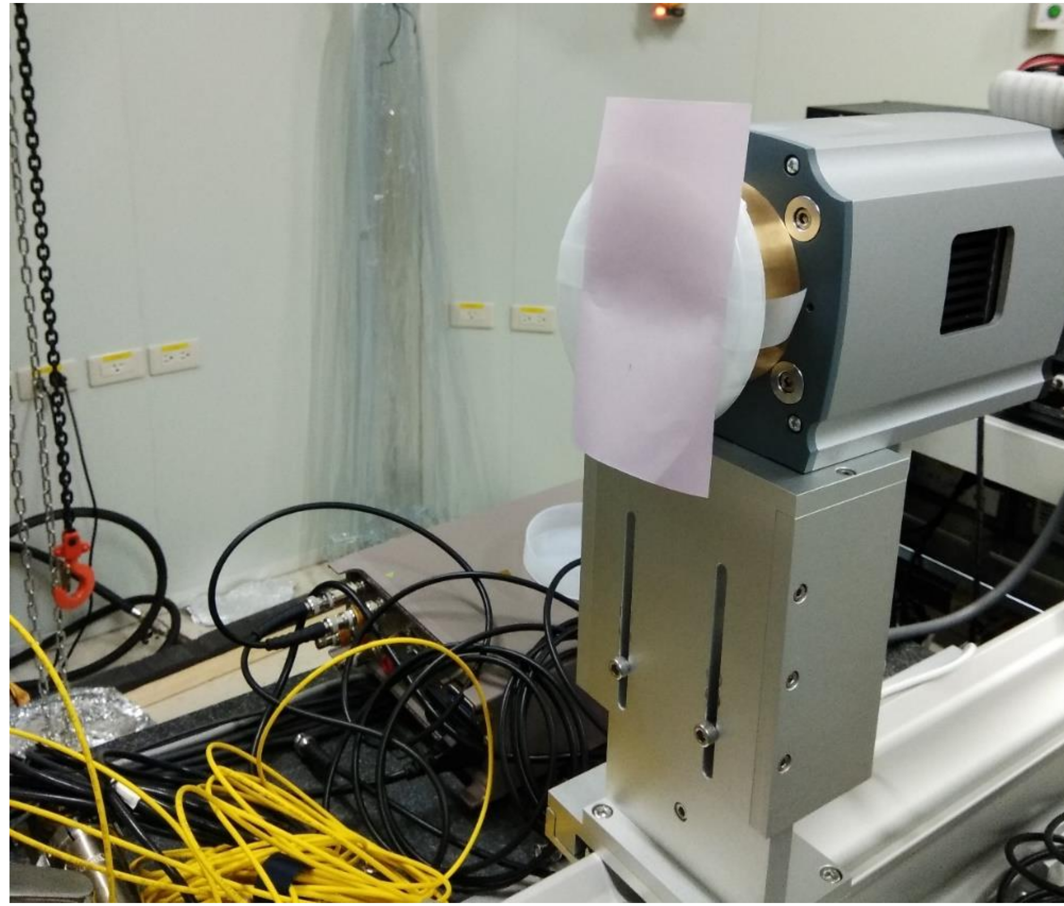

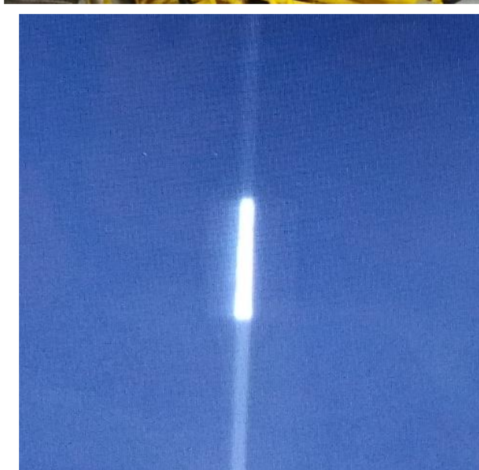

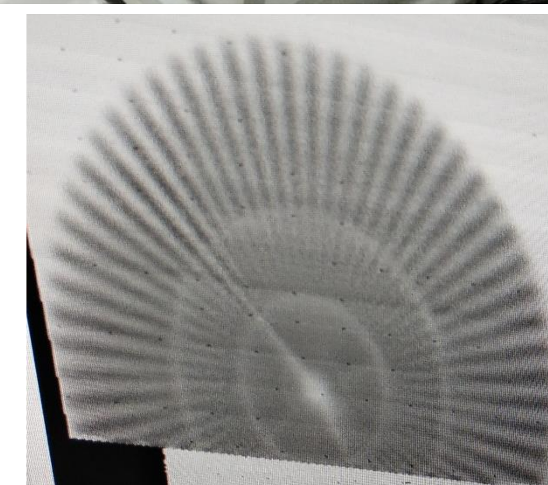

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X-ray Methods:

With tens-nm resolution (incoherent)

TAIWAN TPS 23A

- nano-XRF (X-ray fluorescence)
  - Element-specific nanoimaging
- nano-XRD (X-ray diffraction)
  - Nano-Crystalline
- nano-XAFS (X-ray absorption fine structures)
  - Local electronic structure
  - Local chemical environments
  - Element-specific, averaged over nano-size area
- nano-XEOL (X-ray excited optical luminescence)
  - X-ray-to-visible down-conversion efficiency in nano phosphor
- nano-PXM (projection X-ray microscopy)
  - Absorption and phase contrast x-ray images

Beyond sub-ten-nm resolution (coherent)

- nano-CXDI (coherent X-ray diffraction imaging)
- Bragg-ptychograpgy
  - strain dynamics in nano-devices

Beamline specification

- Energy range：4 - 15 keV
- Photon flux：$10^{10} \sim 10^{11}$ photons/sec
- Energy resolution：$< 2 \times 10^{-4}$ with Si(111) crystals
- Beam size：$\sim$ 50 nm at 10 keV
- High-order harmonic contamination：$\leqq 1 \times 10^{-4}$
- Energy scanning capabilities.

Other than X-rays

- SEM (SE, EDS, CL with high spatial resolution)
- Fly scanning
- In-Situ –electrical, gas, liquid

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nano-XRF (X-ray fluorescence)

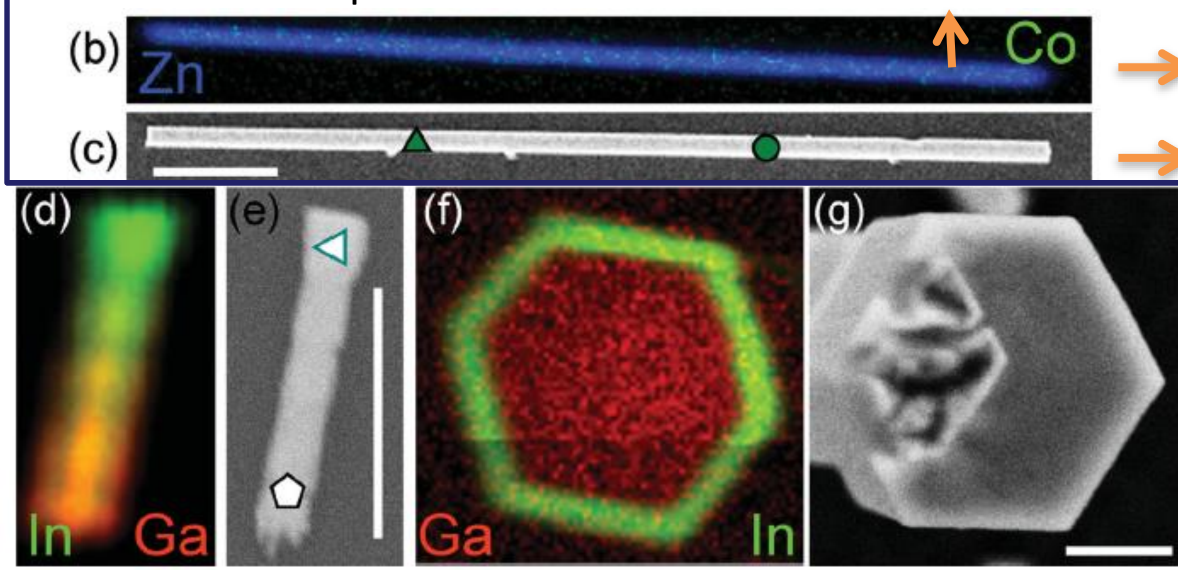
Element-specific nano-imaging

Doping of ZnO NWs by transition metal Co.
Application : Spintronic device
Want to know:

- Distribution
- Short structure order
- Elemental composition

- Pink beam mode at 12 KeV
- Pixel size : 25 x 25 nm^2
- Accumulation time : 0.5 sec/point
- beam size : 60 x 60 nm^2 (V x H)

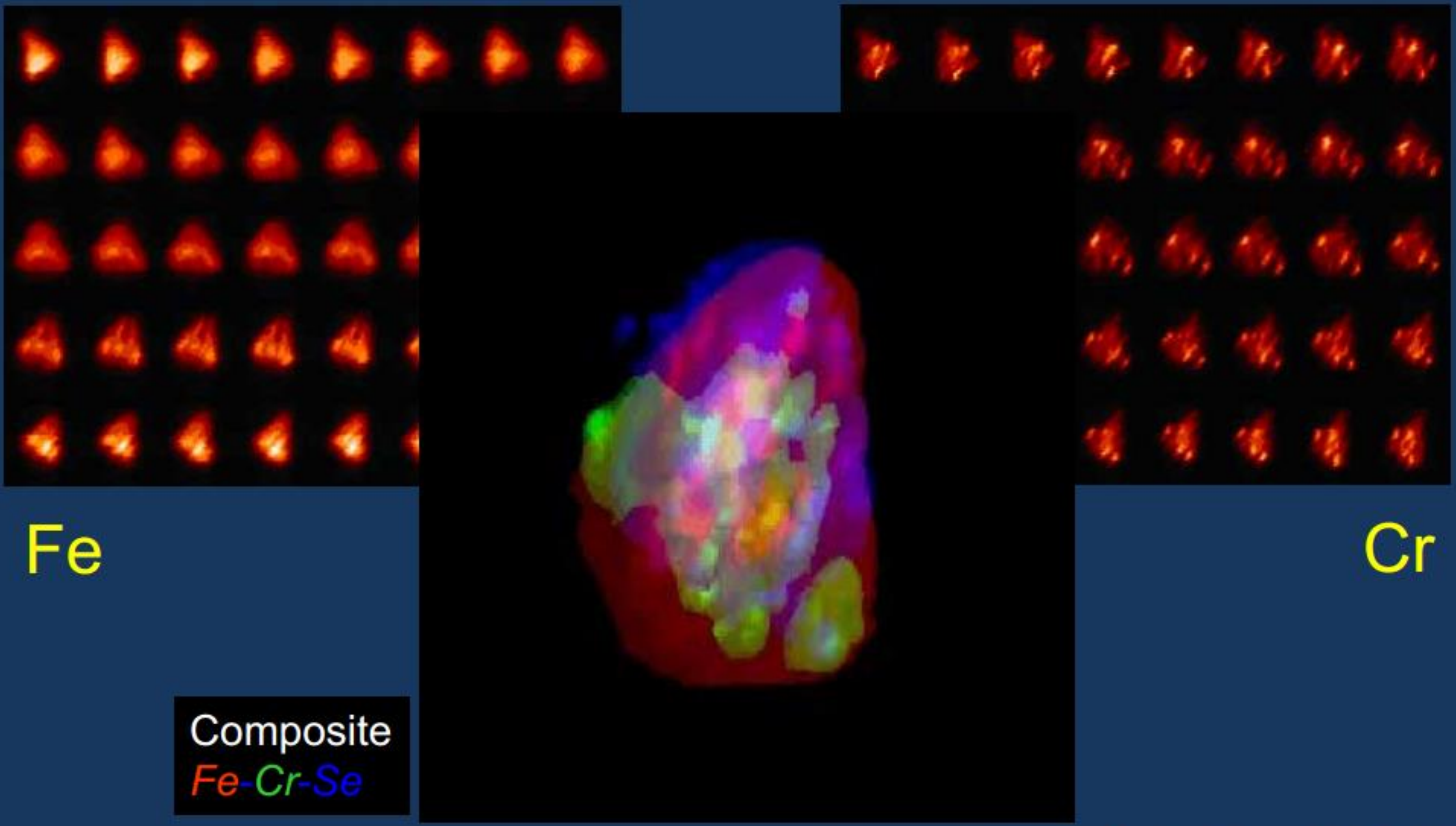
Doping method:
Ion implantation
and thermal annealing
Elemental map of XRF
SEM



Vapour-liguid-solid process
Nano Lett. 2011, 11, 5322–5326

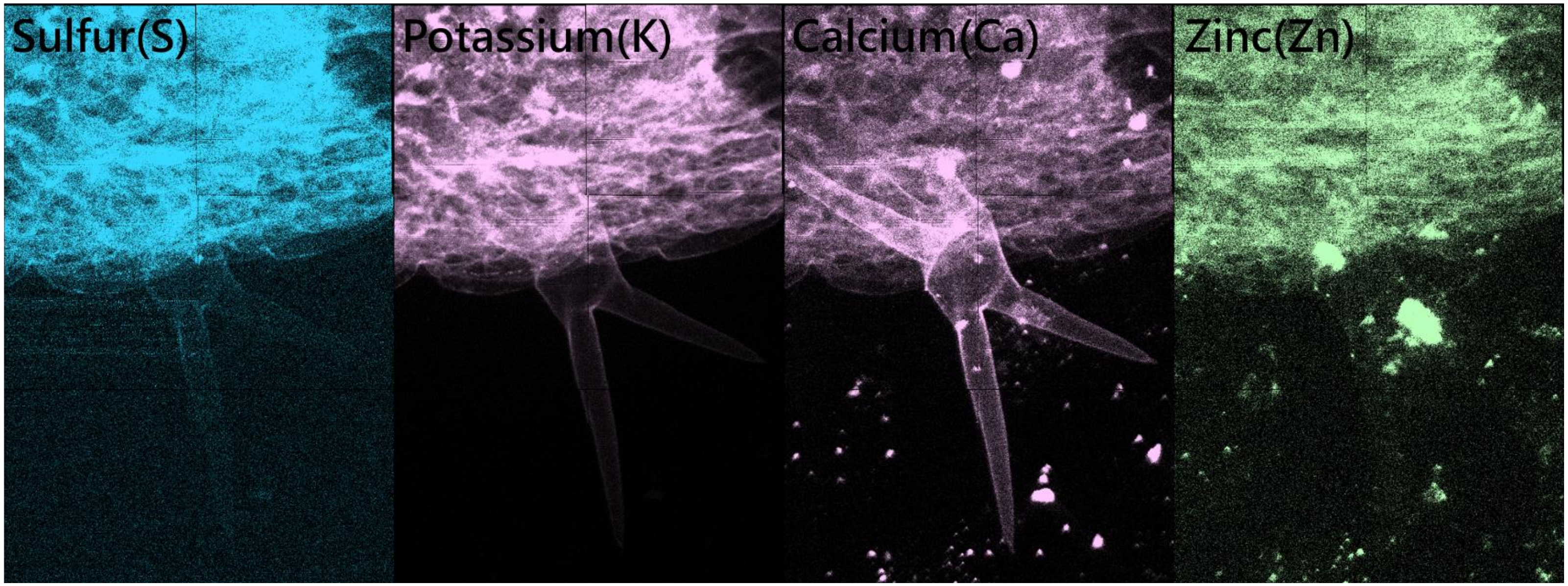
High resolution XRF tomography

Pixel size: 100 nm, sample rotation 0-180° (4.5° / image)

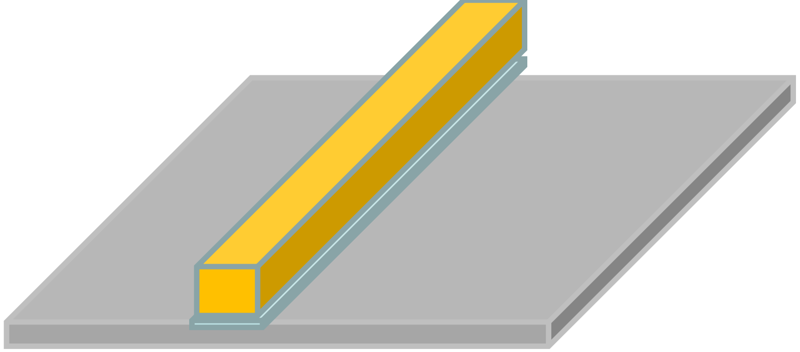


Silversmit *et al., Anal. Chem.* 81 (2009)

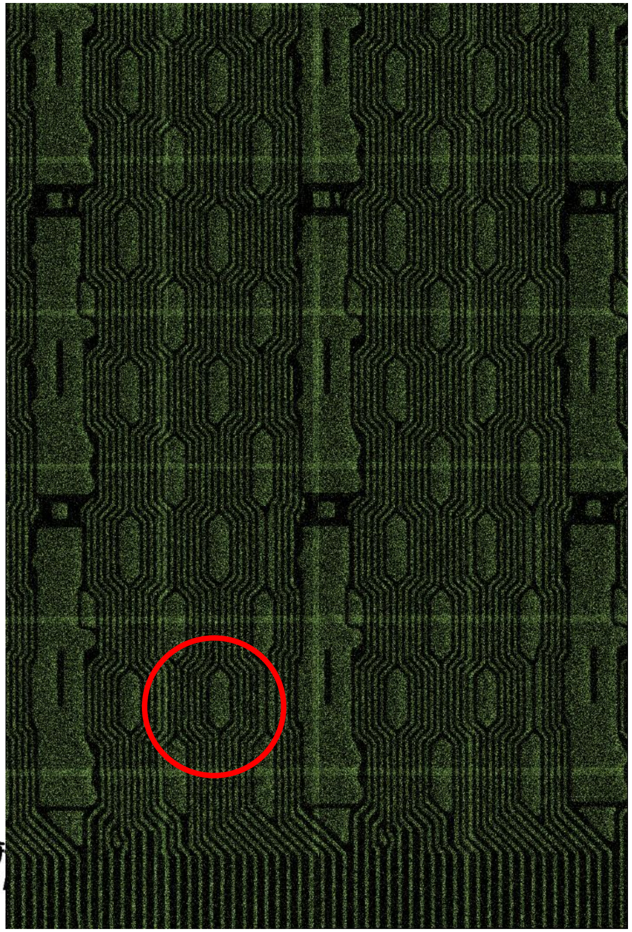
X-ray Nano Probe for Plant of heavy metal residue



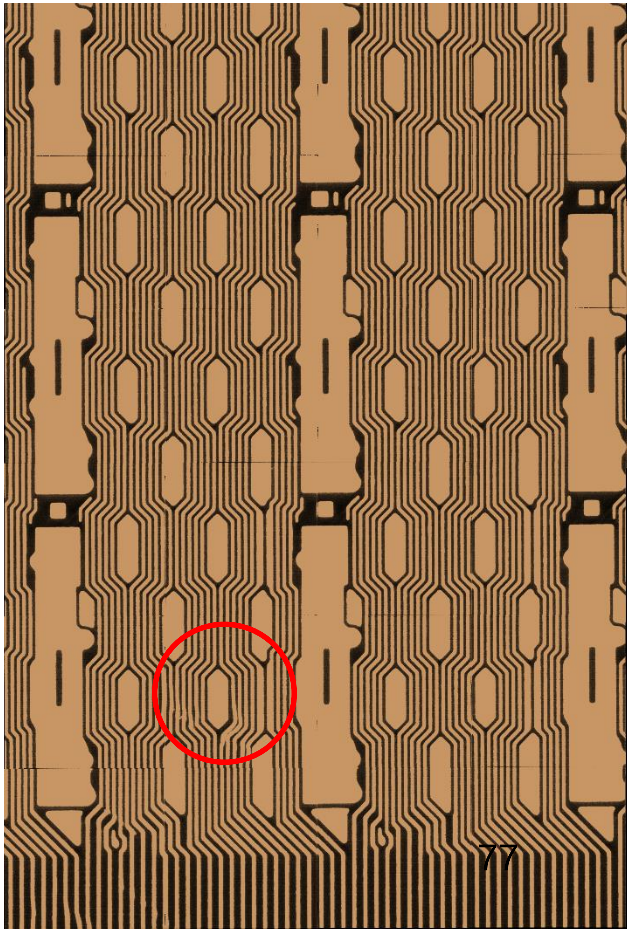
nano-XRF for Semiconductor industry



4510eV_Titanium (Ti)



8040eV_Copper (Cu)



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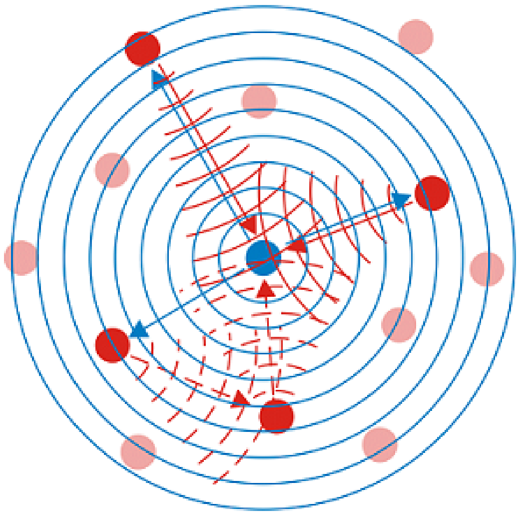
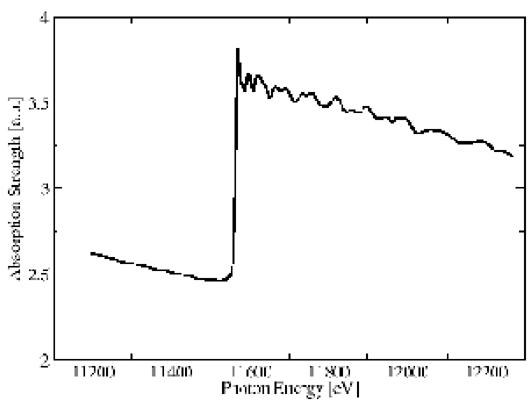
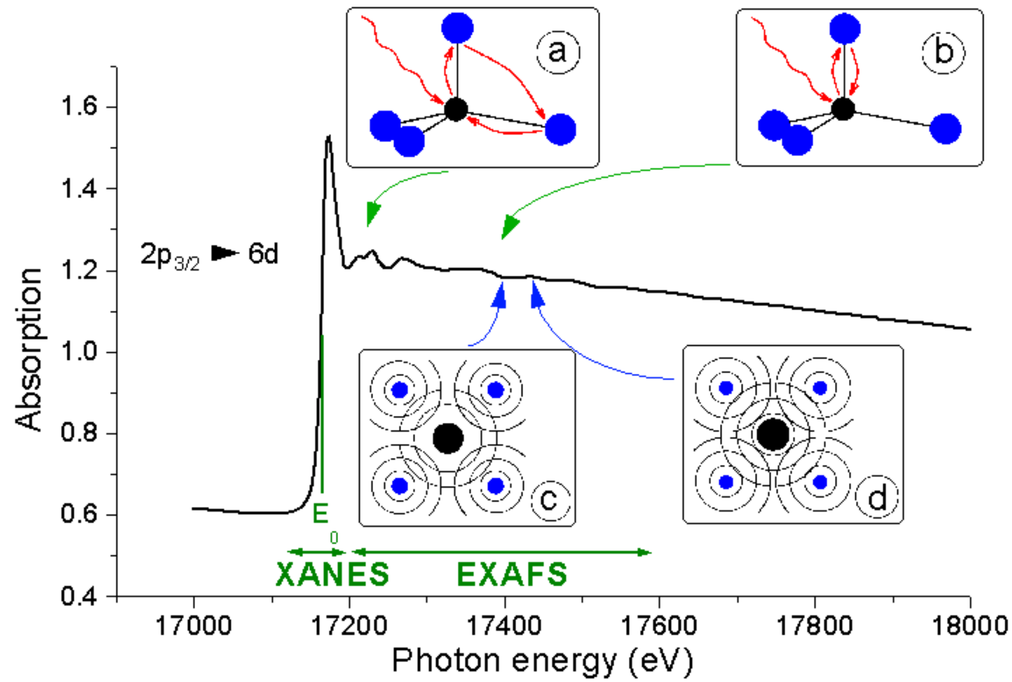
nano-XAFS (x-ray absorption fine structures)

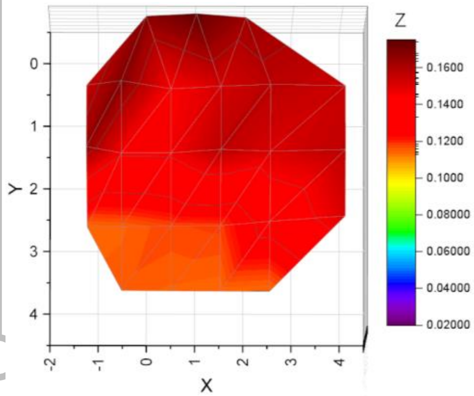
– Local electronic structure
– Local chemical environments
– Element-specific, averaged over nano-area



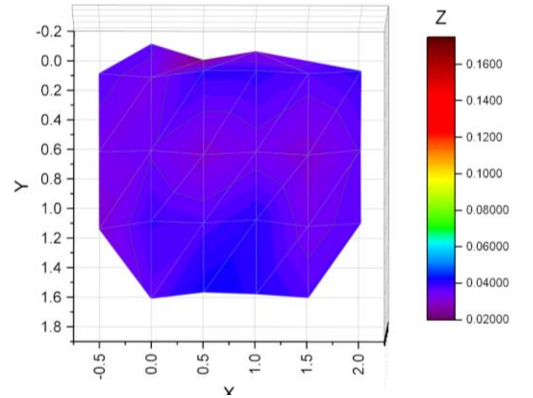




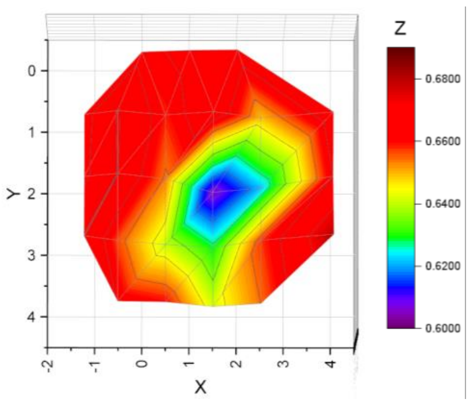
X-ray Nano Probe for Lithium Battery (NTU-CCMS)



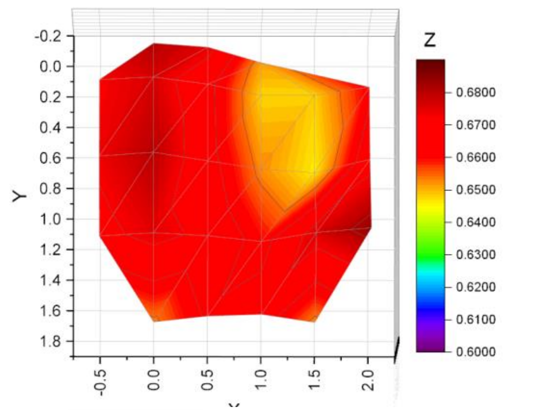
Mn-high Voltage



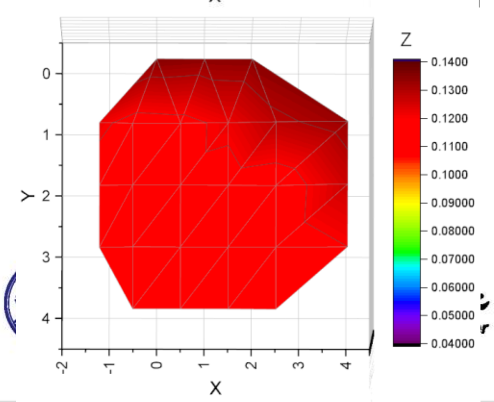
Mn-low Voltage



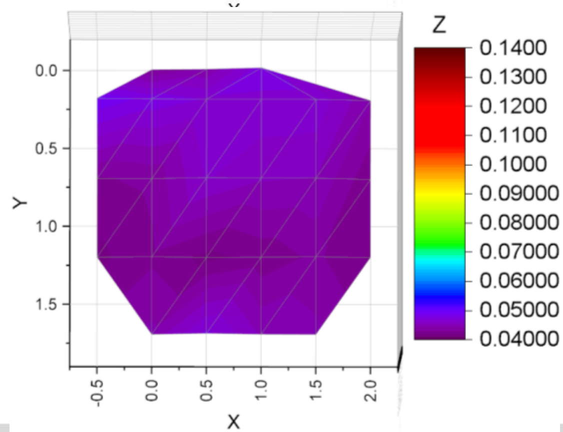
Co-high Voltage



Co-low Voltage

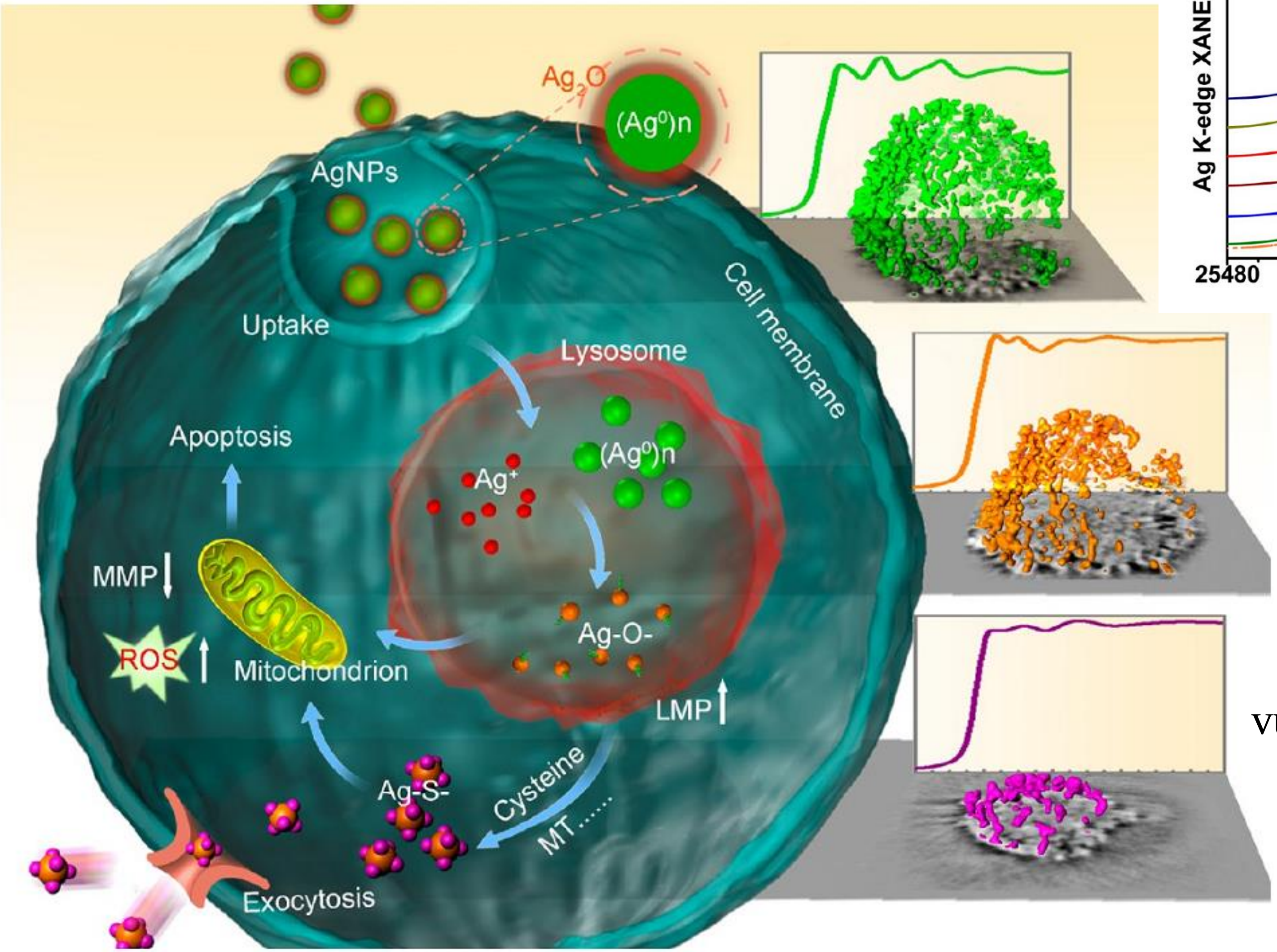


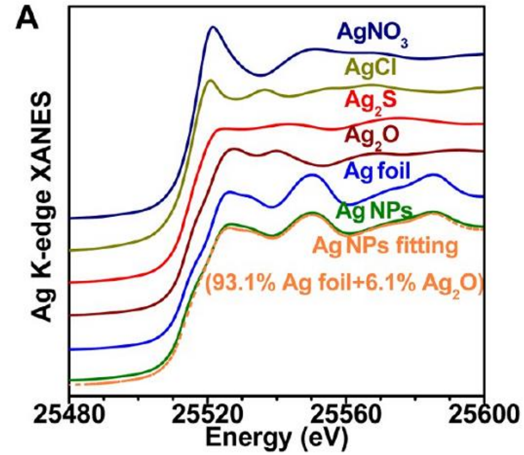
Ni-high Voltage



Ni-low Voltage

nano-XAFS





Oxidation

vulcanization

ACS NANO Vol 9, 6, 6532–6547 (2015)

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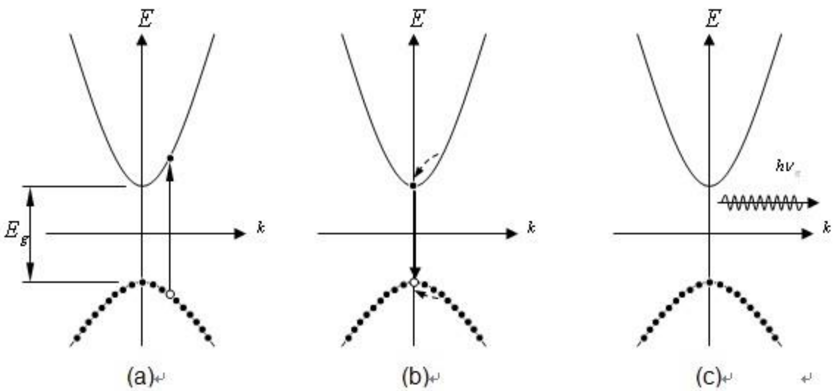
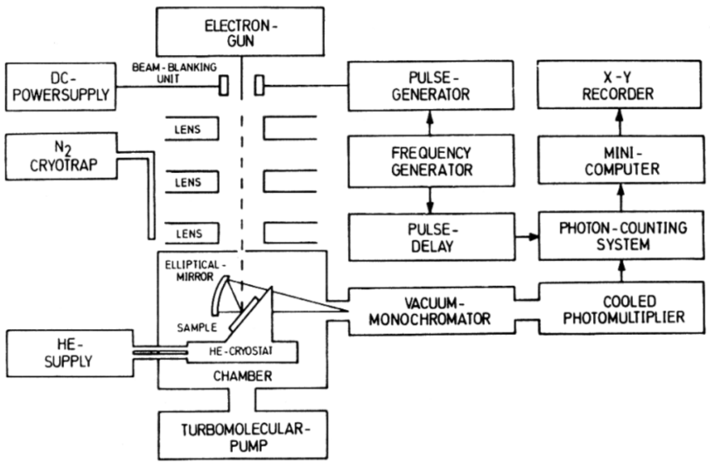
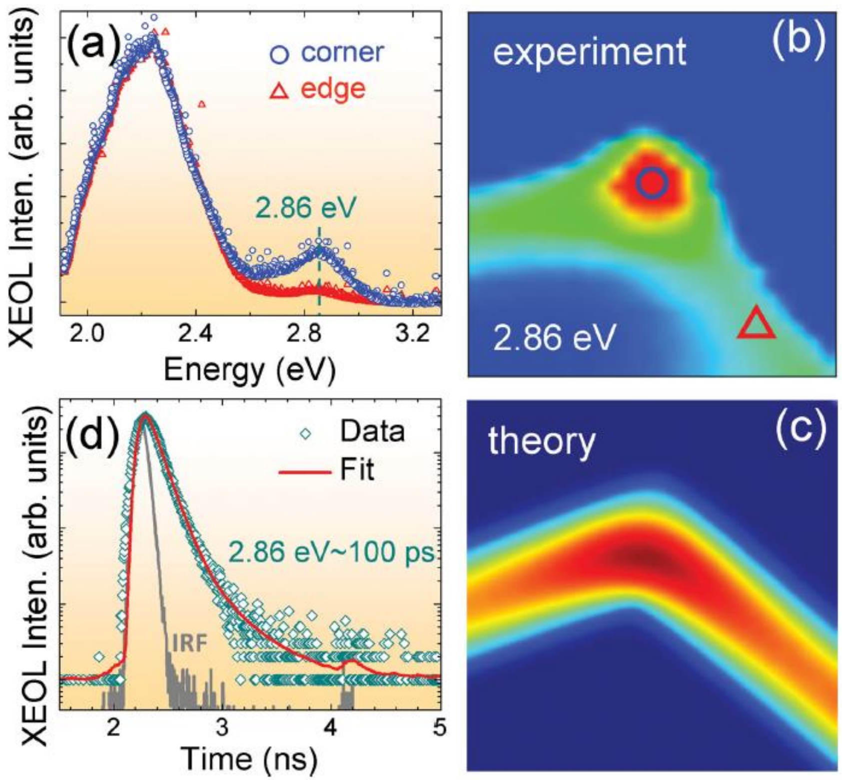
nano-XEOL (X-ray excited optical luminescence) & CL (cathodoluminescsnce)







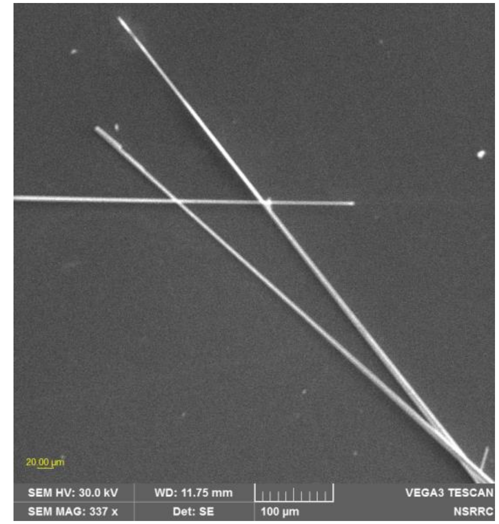
XEOL: 1.nano-area

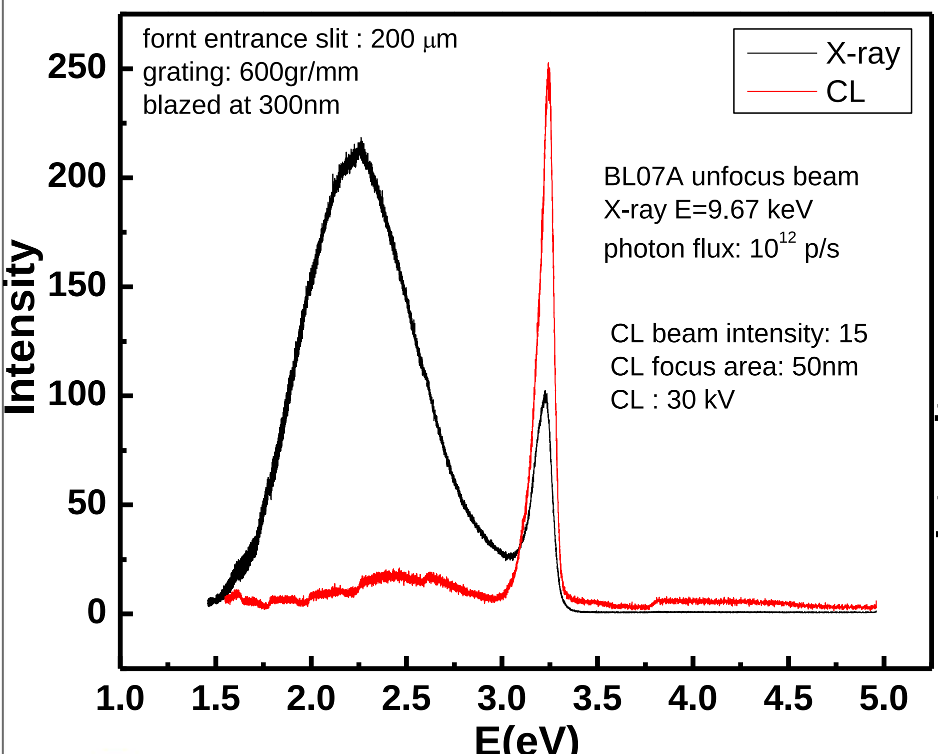
2.multi-layer, buried layer

Doping species, Band gap, Defect band, Charge transport

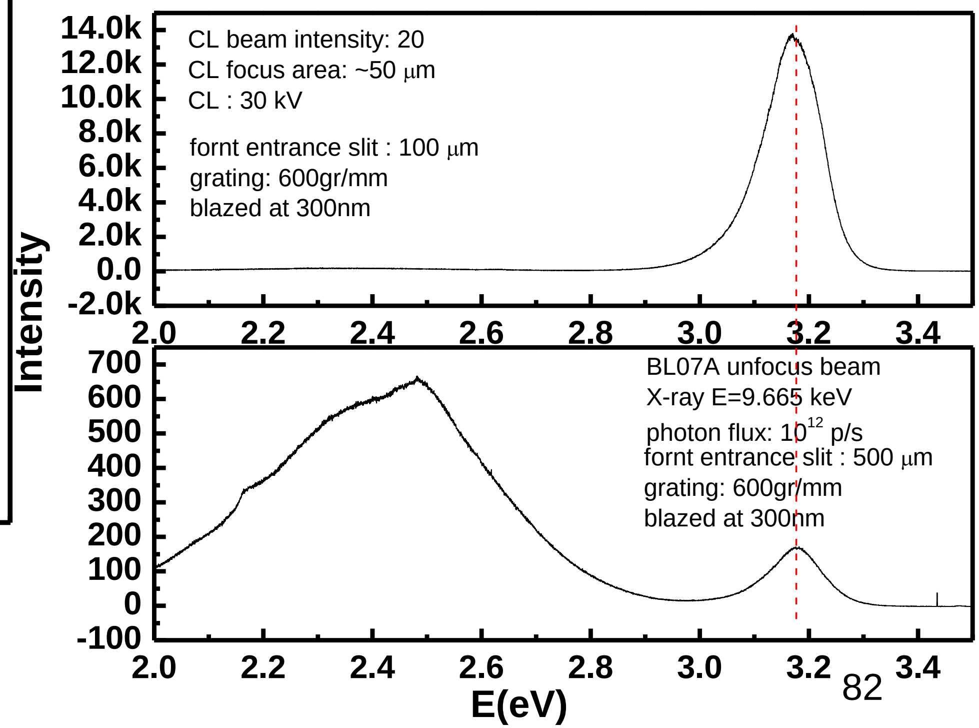
Adv. Mater. **2014**,
DOI: 10.1002/adma.201304345

O-polar ZnO wafer





ZnO single microwire



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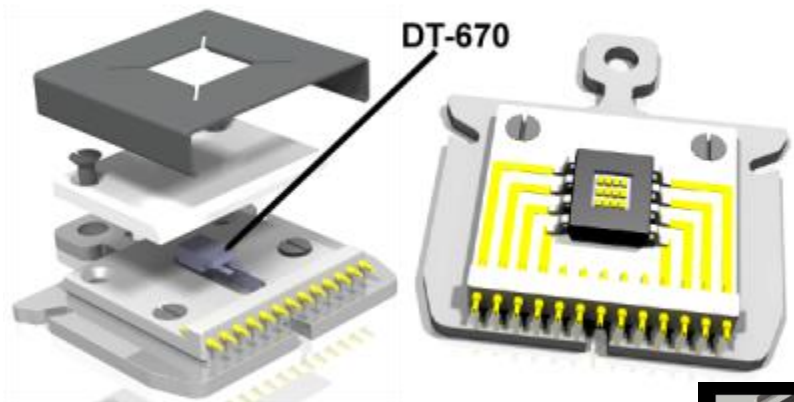
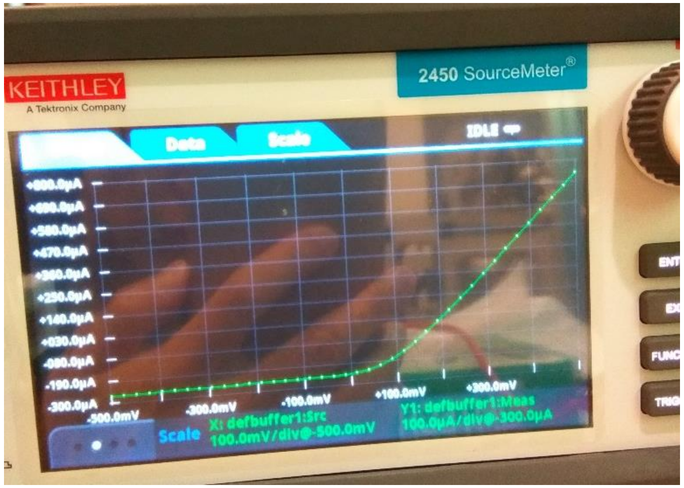
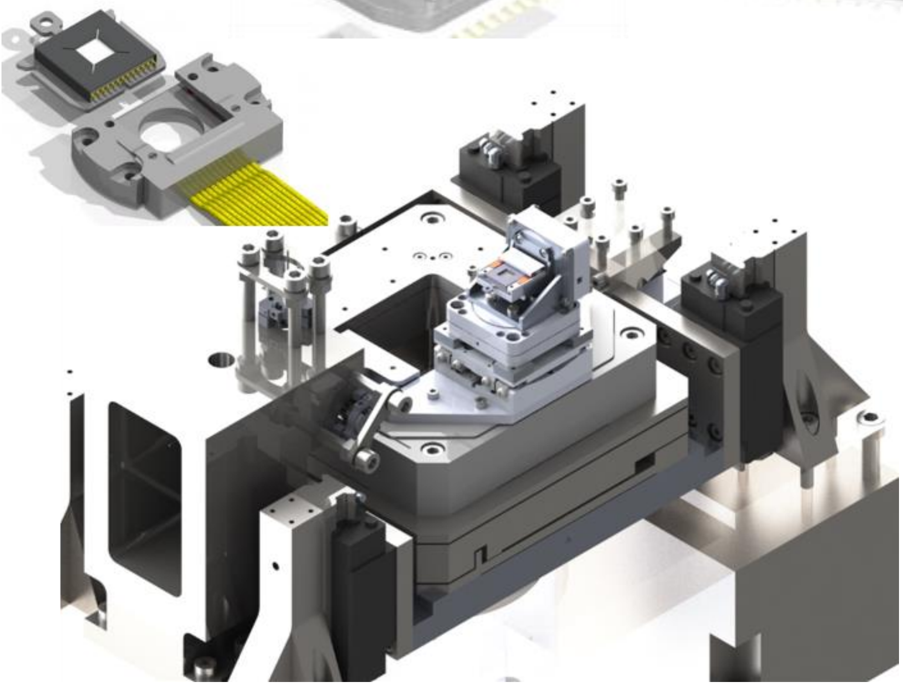
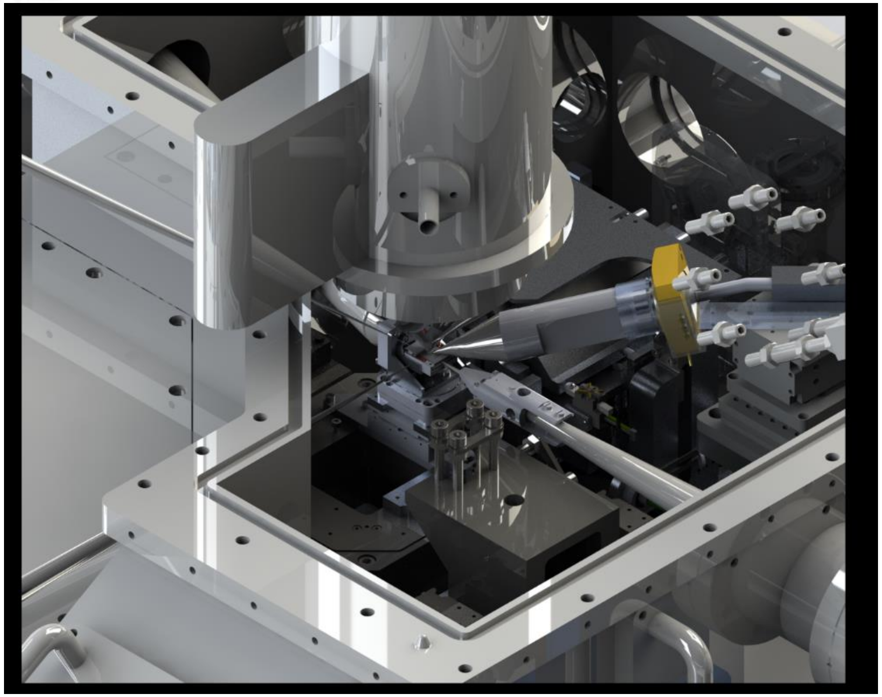
In-situ Electrical Sample Holder



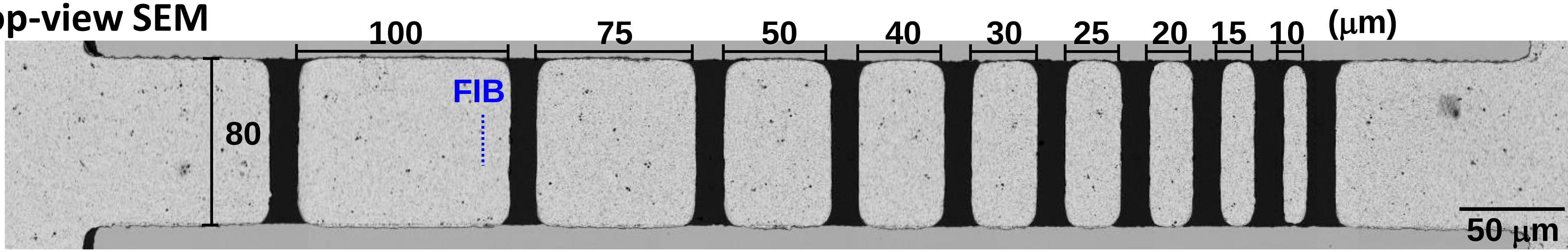




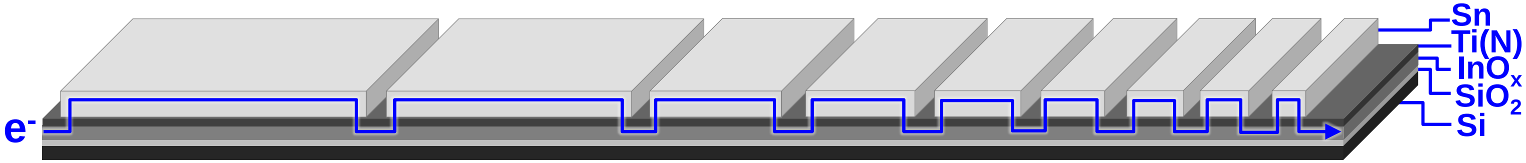


Sn Blech Structure

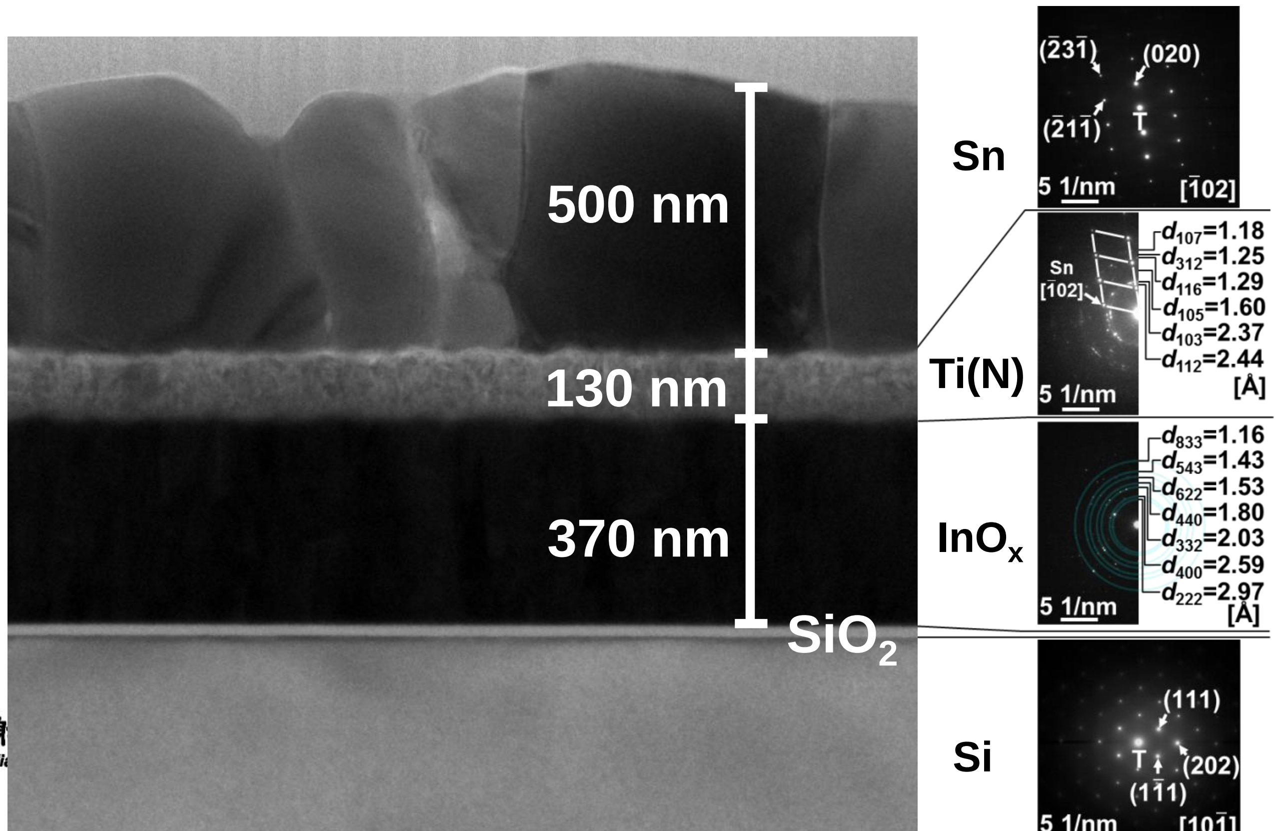
- Top-view SEM



- Tilted-view schematic



- Cross-sectional TEM



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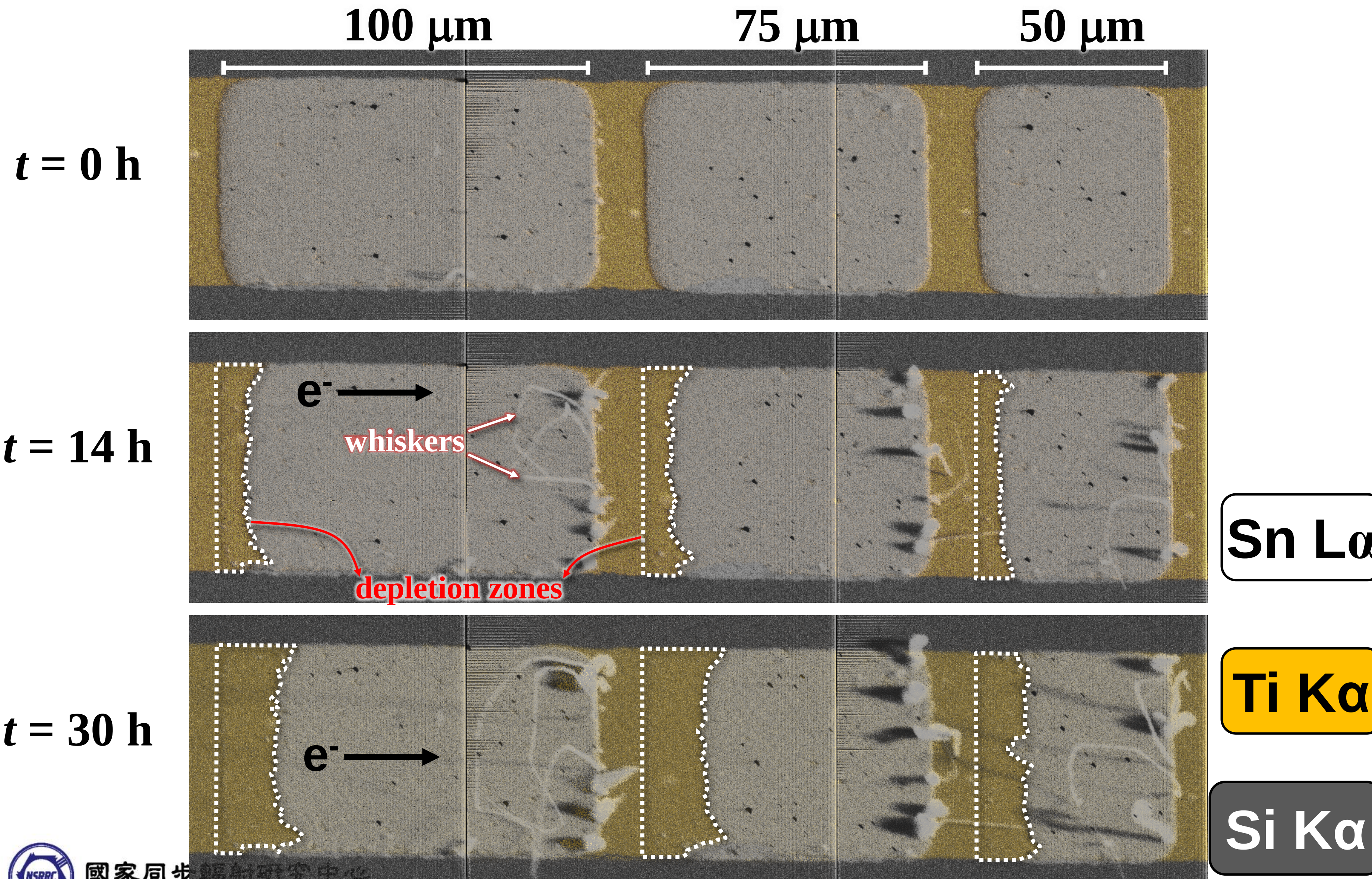
Real-time X-ray Nanoprobe Study of Sn Whisker Growth



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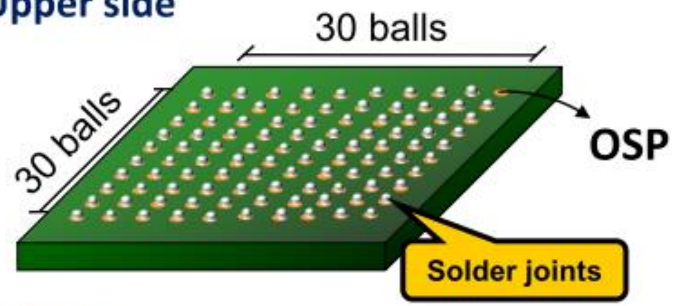
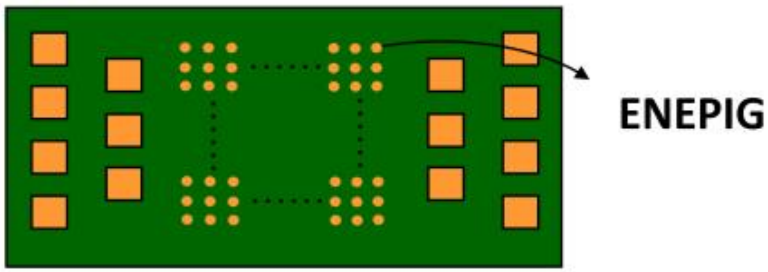
- $j = 1.7 \times 10^5$ A/cm² @ $T \approx 30$ °C

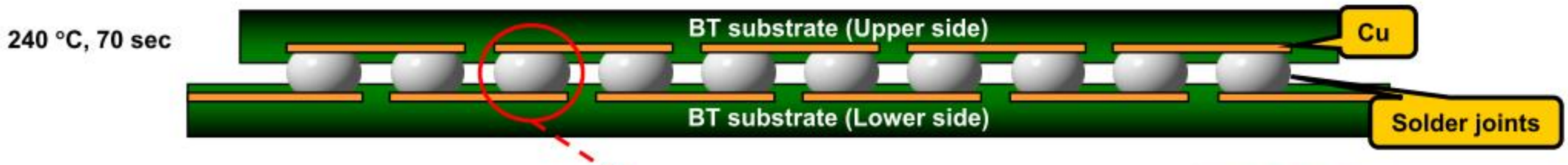
Upper side

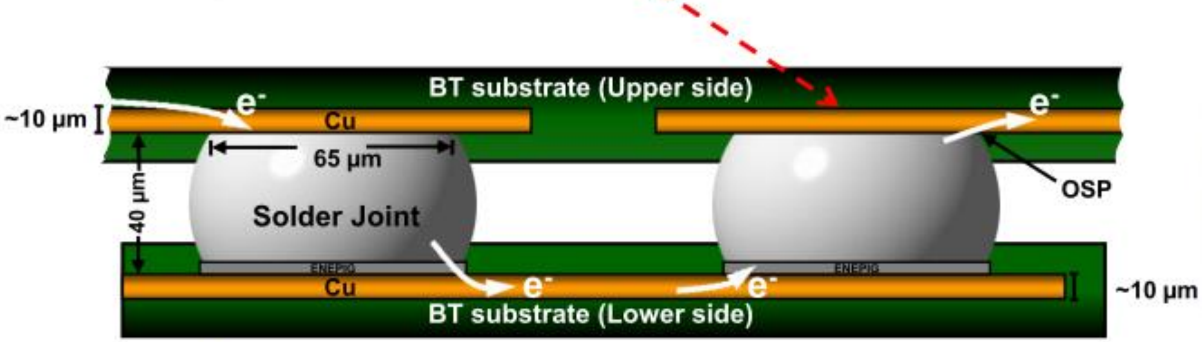


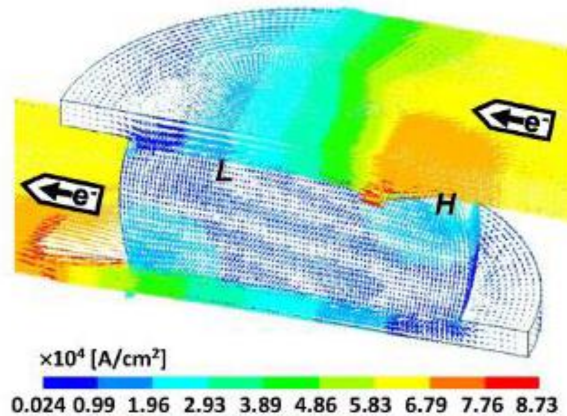
Lower Side



Daisy chain





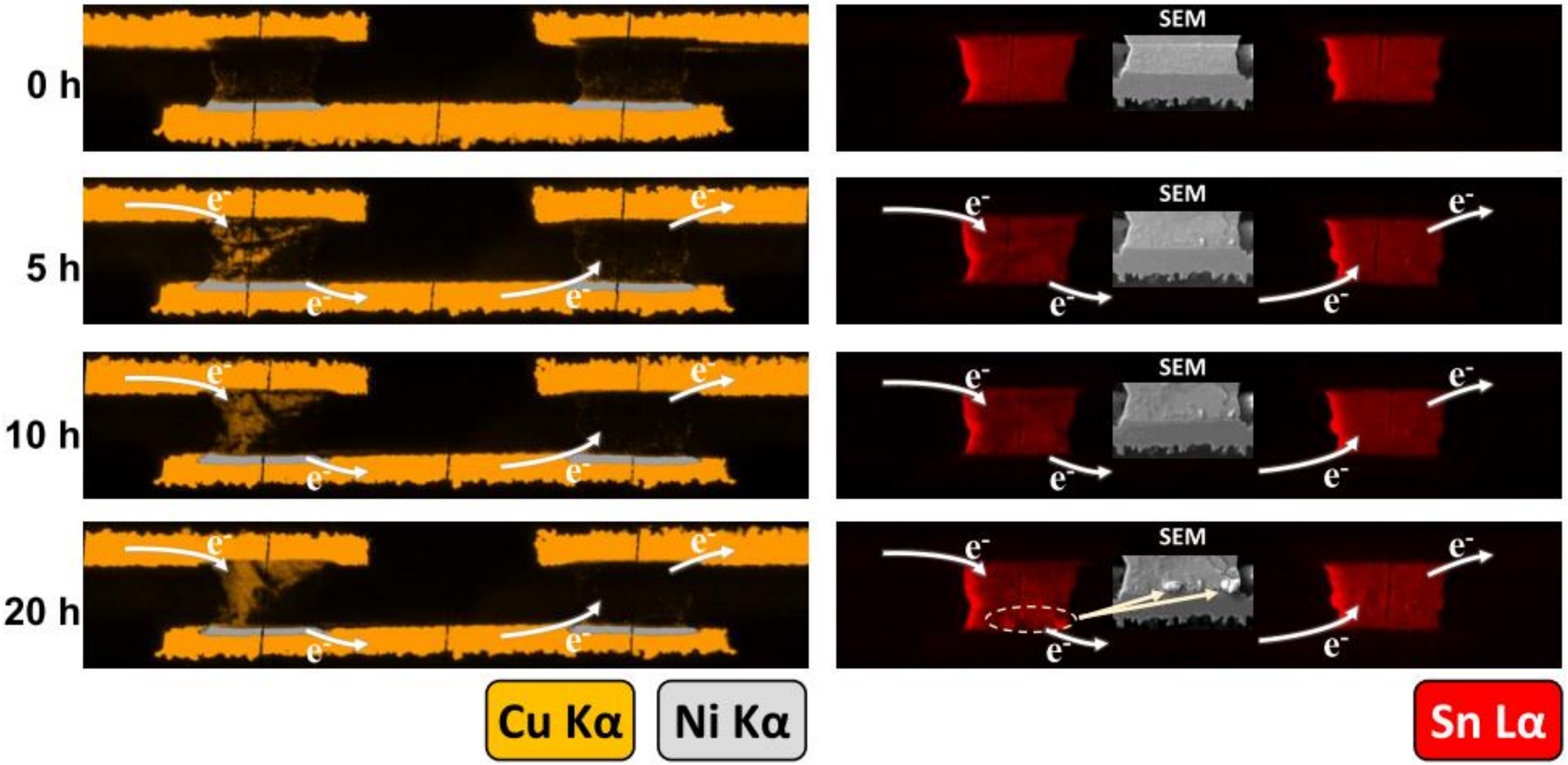


Ref: *Scripta Mater.*, vol. 114, p. 79, 2016.

Experimental parameters:

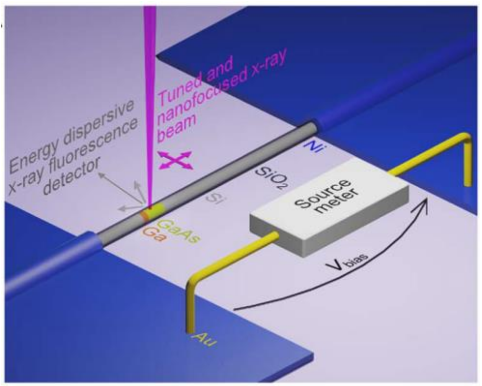
- Micro joint structure: Cu/OSP/Sn-0.7Cu/ENEPIG/Cu
- Direct current: 0.8 A @50 °C
- Current stressing time: 0–20 h

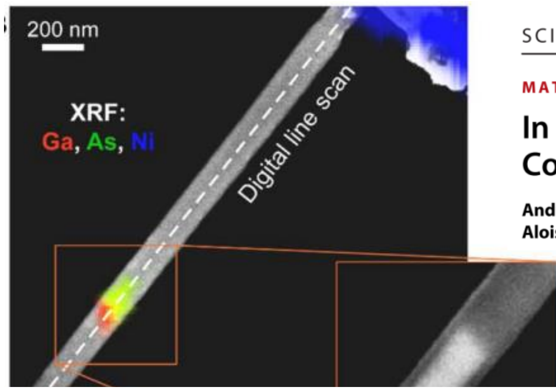
X-ray Fluorescence Mappings



- Low-temperature (50 °C) electromigration in micro joints was investigated (ex-situ) using nano-XRF microscopy (beamline 23A, TPS).
- Significant electromigration of Cu in the Sn matrix and formation of Sn extrusions at the anode were well characterized using nano-XRF microscopy.

X-ray beam–induced current (XBIC): A focused synchrotron x-ray nanobeam over a single semiconductor nanowire heterostructure and simultaneously measured the current through the device and the emitted characteristic x-rays as a function of the incoming hard x-ray energy. With these results, it is possible to identify the compositional and molecular structure as well as localize the electrical fields present under typical working conditions. This information allows us to draw an energy band diagram consistent with the elemental distribution and a high-resolution chemical speciation map.



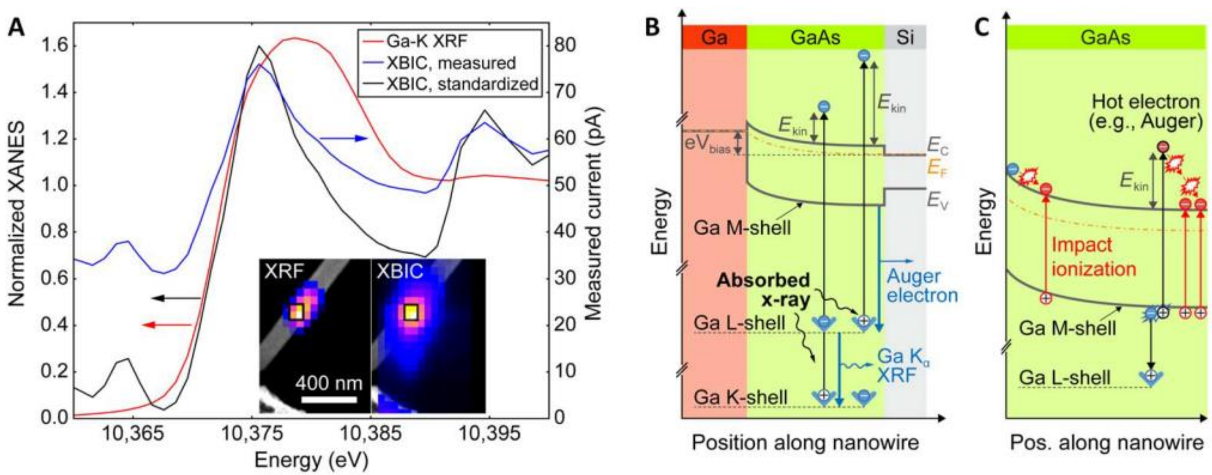


SCIENCE ADVANCES | RESEARCH ARTICLE

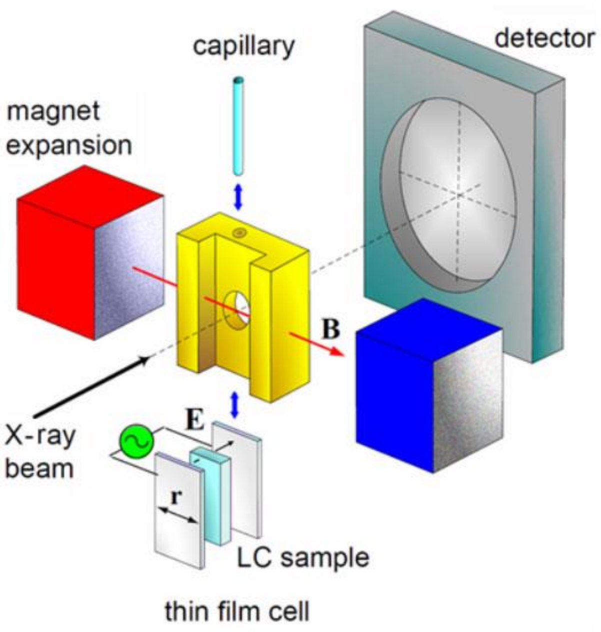
MATERIALS SCIENCE

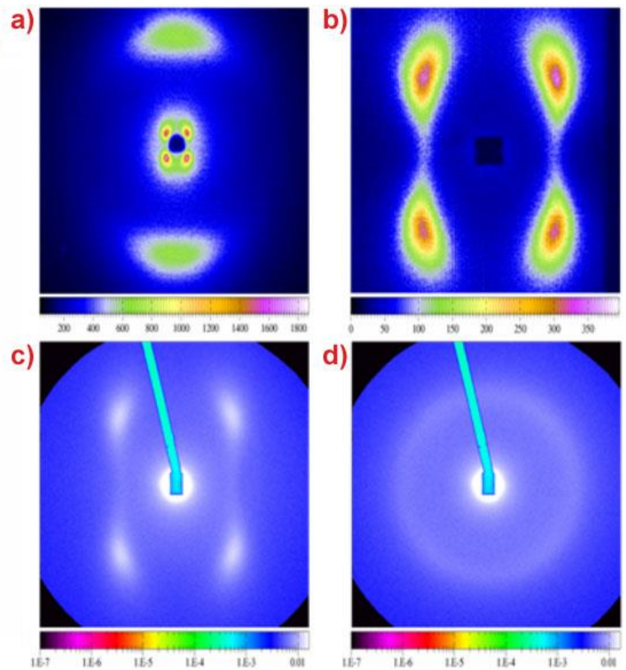
In operando x-ray imaging of nanoscale devices: Composition, valence, and internal electrical fields

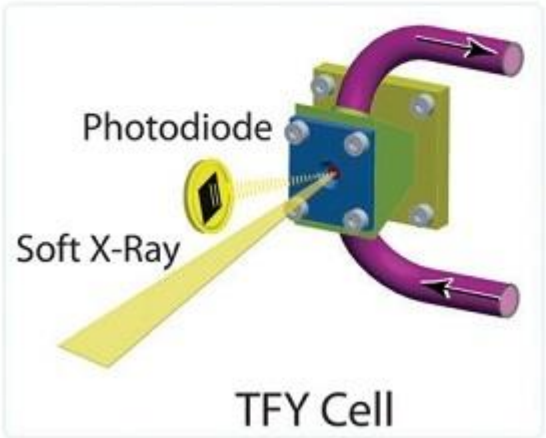
Andreas Johannes,[1*] Damien Salomon,[1] Gema Martinez-Criado,[1,2] Markus Glaser,[3] Alois Lugstein,[3] Carsten Ronning[4]

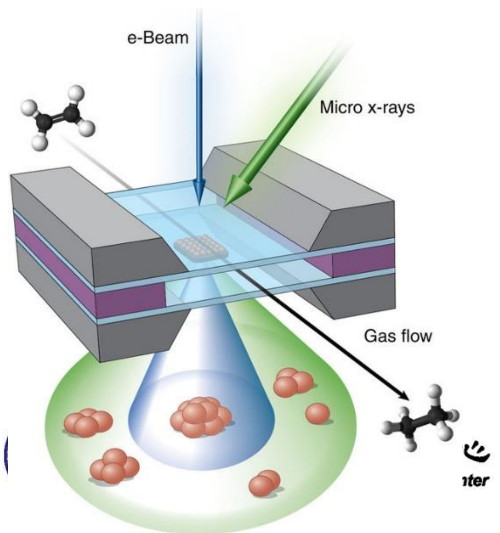


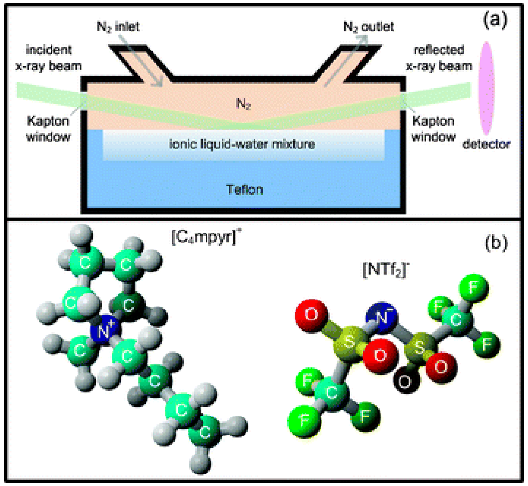
In-Situ Gas and Liquid Cell

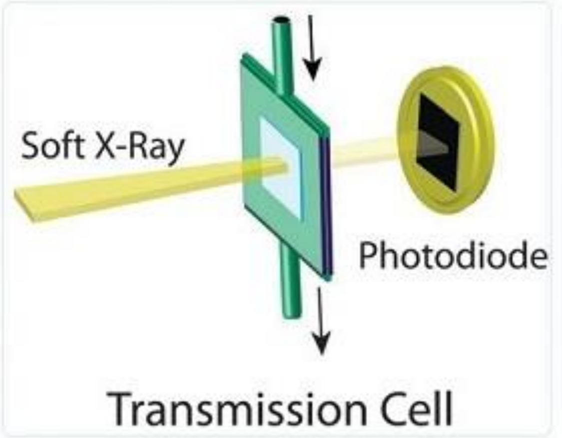






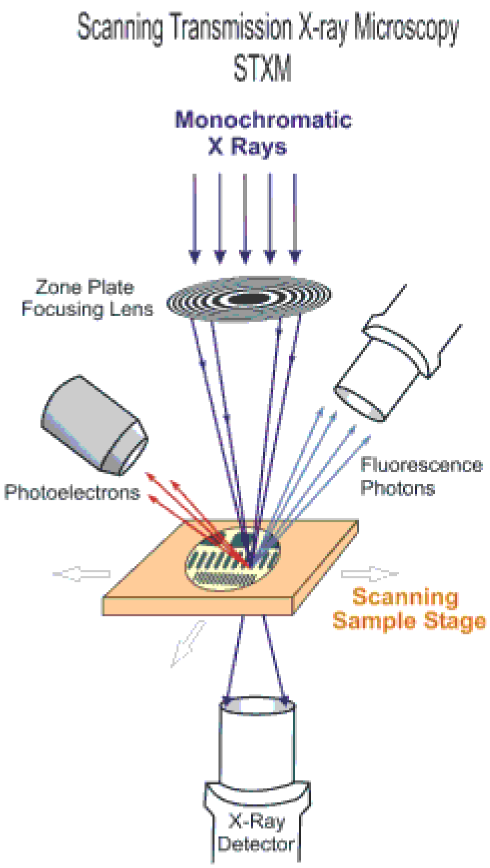


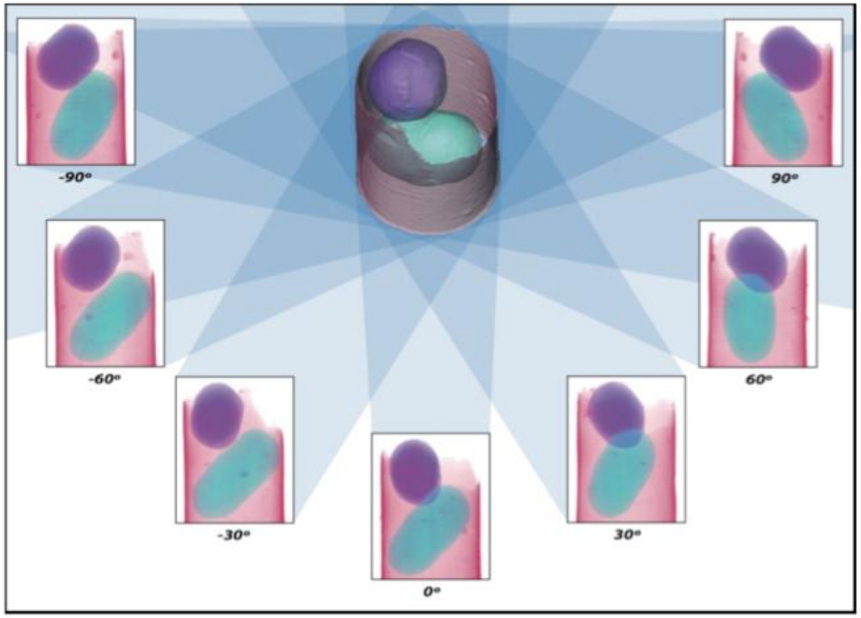




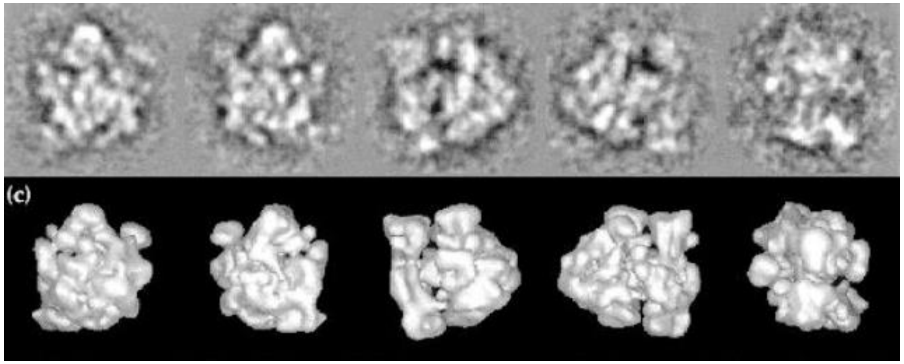
nano-PXM (projection x-ray microscopy)

– Absorption and phase contrast x-ray images





TRENDS in Cell Biology



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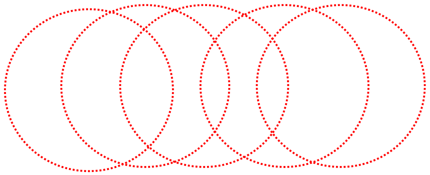
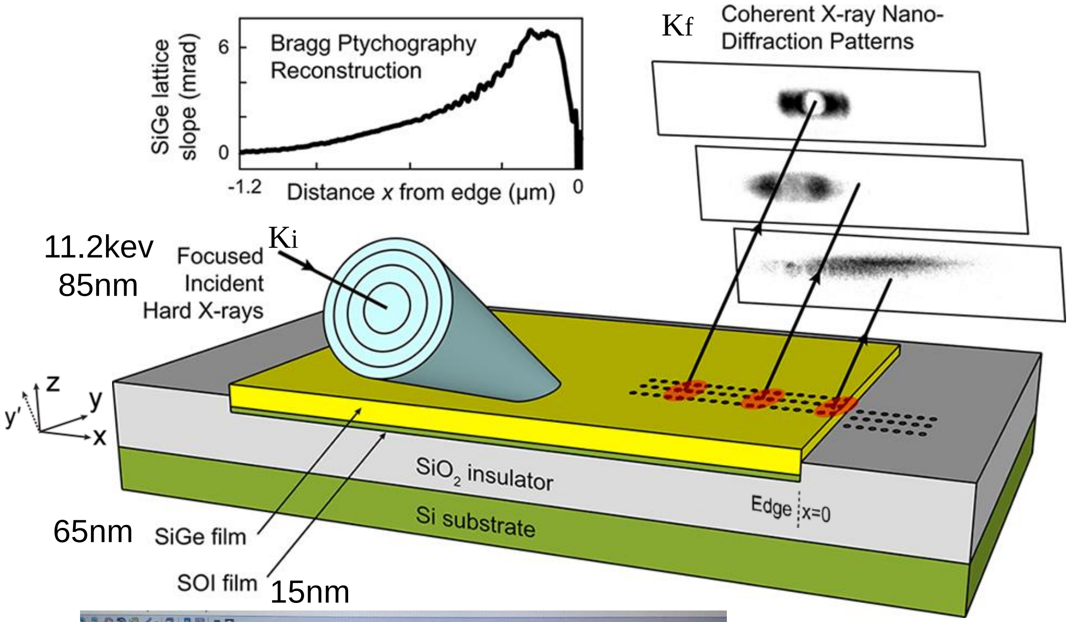
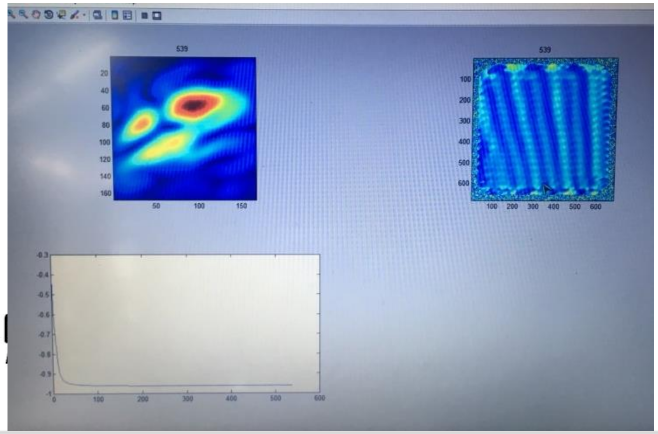
Adv. Mater. **2014**,
DOI: 10.1002/adma.201304345

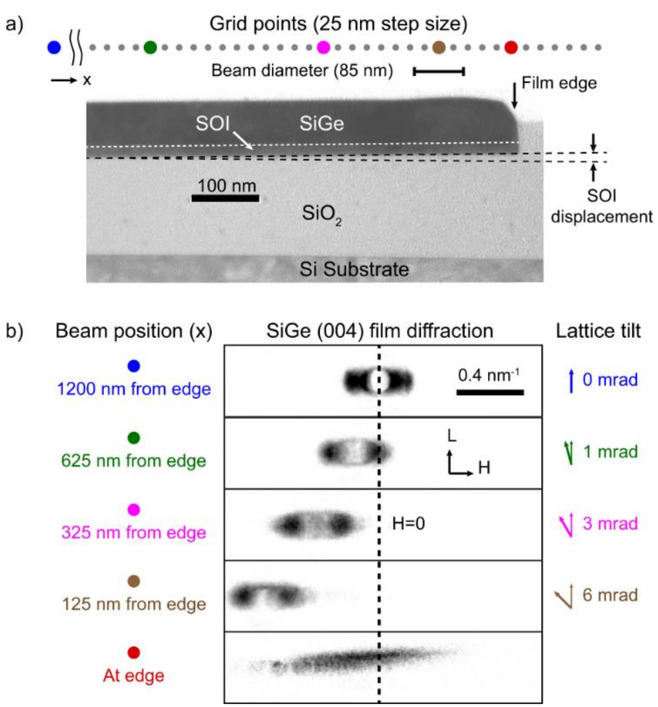
X-ray Bragg projection ptychography from thin film heterostructures



70% spatial overlap





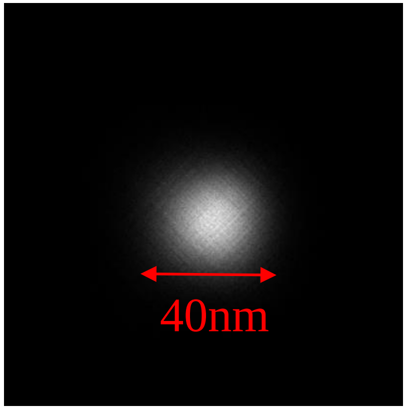


M. V. Holt *et al*, Phys. Rev. Lett. 112, 165502 (2014)

Summary

X-ray methods at 23A of TPS

- nano-XRF (x-ray fluorescence)
  - Element-specific nanoimaging
- nano-XRD (x-ray diffraction)
  - Nano-Crystalline
- nano-XAFS (x-ray absorption fine structures)
  - Local electronic structure
  - Local chemical environments
  - Element-specific, averaged over nano-size area
- nano-XEOL (x-ray excited optical luminescence)
  - X-ray-to-visible down-conversion efficiency in nano phosphor
- nano-PXM (projection x-ray microscopy)
  - Absorption and phase contrast x-ray images
- nano-CXDI (coherent x-ray diffraction imaging)
- Bragg-ptychograpgy
  - strain dynamics in nano-devices



房價

每間單人住宿價為NT$700/天，雙人住宿價為NT$1,000/天;四人房價為NT$1,500/天。

房型	實景	間數	房間坪數	收費	備 註
二張單人床		30	6	1,000元/晚	單人住宿一律 NT $700 元
四張單人床		1	12	1,500元/晚	
交誼廳		4	10		一至四樓
餐廳		2	7		三至四樓

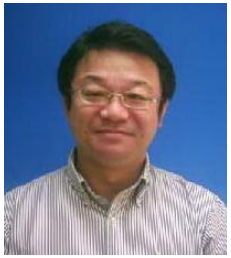
X-ray Nanoprobe Construction Team

Project Leader: Prof. J. Raynien Kwo (NTHU)

Construction Team

Leader

Mau-Tsu Tang



Beamline-

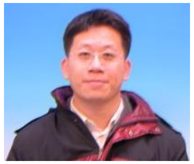
Shih-Hung Chang and Beamline Group

Endstation-

Gung-Chian Yin, optical design and overall system integration.

Bo-Yi Chen, Mechanical engineer.

Chien-Yu Lee, Electronic engineer.



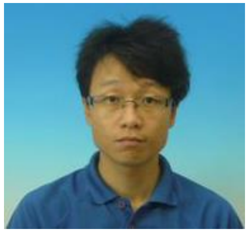
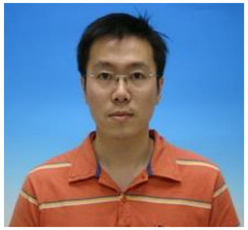

Huang-Yeh Chen, Mechanical design and experiment assistant.

Jian-Xing Wu, Software programmer, GUI and control panel design.

Beamline Scientist and Manager-

Shao-Chin Tseng, Sample preparation, experiment design

Bi-Hsuan Lin, Experiment design, XEOL, XRD.

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National Synchrotron Radiation Research Center


Thanks for your attentions